Relion® 650 series

Line distance protection REL650 ANSI
Commissioning manual
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This product includes cryptographic software written/developed by: Eric Young (eay@cryptsoft.com) and Tim Hudson (tjh@cryptsoft.com).

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Conformity

This product complies with the directive of the Council of the European Communities on the approximation of the laws of the Member States relating to electromagnetic compatibility (EMC Directive 2004/108/EC) and concerning electrical equipment for use within specified voltage limits (Low-voltage directive 2006/95/EC). This conformity is the result of tests conducted by ABB in accordance with the product standard EN 60255-26 for the EMC directive, and with the product standards EN 60255-1 and EN 60255-27 for the low voltage directive. The product is designed in accordance with the international standards of the IEC 60255 series and ANSI C37.90.
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Safety information

Dangerous voltages can occur on the connectors, even though the auxiliary voltage has been disconnected.

Non-observance can result in death, personal injury or substantial property damage.

Only a competent electrician is allowed to carry out the electrical installation.

National and local electrical safety regulations must always be followed.

The frame of the IED has to be carefully grounded.

Whenever changes are made in the IED, measures should be taken to avoid inadvertent tripping.

The IED contains components which are sensitive to electrostatic discharge. ESD precautions shall always be observed prior to touching components.
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Section 1  Introduction

1.1  This manual

The commissioning manual contains instructions on how to commission the IED. The manual can also be used by system engineers and maintenance personnel for assistance during the testing phase. The manual provides procedures for the checking of external circuitry and energizing the IED, parameter setting and configuration as well as verifying settings by secondary injection. The manual describes the process of testing an IED in a substation which is not in service. The chapters are organized in the chronological order in which the IED should be commissioned. The relevant procedures may be followed also during the service and maintenance activities.

1.2  Intended audience

This manual addresses the personnel responsible for commissioning, maintenance and taking the IED in and out of normal service.

The commissioning personnel must have a basic knowledge of handling electronic equipment. The commissioning and maintenance personnel must be well experienced in using protection equipment, test equipment, protection functions and the configured functional logics in the IED.
The engineering manual contains instructions on how to engineer the IEDs using the various tools available within the PCM600 software. The manual provides instructions on how to set up a PCM600 project and insert IEDs to the project structure. The manual also recommends a sequence for the engineering of protection and control functions, LHMI functions as well as communication engineering for IEC 60870-5-103, IEC 61850 and DNP 3.0.

The installation manual contains instructions on how to install the IED. The manual provides procedures for mechanical and electrical installation. The chapters are organized in the chronological order in which the IED should be installed.

The commissioning manual contains instructions on how to commission the IED. The manual can also be used by system engineers and maintenance personnel for assistance.
during the testing phase. The manual provides procedures for the checking of external
circuitry and energizing the IED, parameter setting and configuration as well as verifying
settings by secondary injection. The manual describes the process of testing an IED in a
substation which is not in service. The chapters are organized in the chronological order
in which the IED should be commissioned. The relevant procedures may be followed also
during the service and maintenance activities.

The operation manual contains instructions on how to operate the IED once it has been
commissioned. The manual provides instructions for the monitoring, controlling and
setting of the IED. The manual also describes how to identify disturbances and how to
view calculated and measured power grid data to determine the cause of a fault.

The application manual contains application descriptions and setting guidelines sorted per
function. The manual can be used to find out when and for what purpose a typical
protection function can be used. The manual can also provides assistance for calculating
settings.

The technical manual contains application and functionality descriptions and lists
function blocks, logic diagrams, input and output signals, setting parameters and technical
data, sorted per function. The manual can be used as a technical reference during the
engineering phase, installation and commissioning phase, and during normal service.

The communication protocol manual describes the communication protocols supported
by the IED. The manual concentrates on the vendor-specific implementations.

The point list manual describes the outlook and properties of the data points specific to the
IED. The manual should be used in conjunction with the corresponding communication
protocol manual.

### 1.3.2 Document revision history

<table>
<thead>
<tr>
<th>Document revision/date</th>
<th>History</th>
</tr>
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<tbody>
<tr>
<td>-/March 2013</td>
<td>First release</td>
</tr>
<tr>
<td>A/October 2016</td>
<td>Minor corrections made</td>
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### 1.3.3 Related documents

<table>
<thead>
<tr>
<th>Documents related to REL650</th>
<th>Identity number</th>
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<tbody>
<tr>
<td>Application manual</td>
<td>1MRK 506 334-UUS</td>
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<tr>
<td>Technical manual</td>
<td>1MRK 506 335-UUS</td>
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<tr>
<td>Commissioning manual</td>
<td>1MRK 506 336-UUS</td>
</tr>
<tr>
<td>Product Guide</td>
<td>1MRK 506 337-BUS</td>
</tr>
<tr>
<td>Type test certificate</td>
<td>1MRK 506 337-TUS</td>
</tr>
<tr>
<td>Application notes for Circuit Breaker Control</td>
<td>1MRG006806</td>
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### 1.4 Symbols and conventions

#### 1.4.1 Symbols

<table>
<thead>
<tr>
<th>Icon</th>
<th>Description</th>
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<tbody>
<tr>
<td><img src="image" alt="Electrical Warning Icon" /></td>
<td>The electrical warning icon indicates the presence of a hazard which could result in electrical shock.</td>
</tr>
<tr>
<td><img src="image" alt="Warning Icon" /></td>
<td>The warning icon indicates the presence of a hazard which could result in personal injury.</td>
</tr>
<tr>
<td><img src="image" alt="Caution Icon" /></td>
<td>The caution icon indicates important information or warning related to the concept discussed in the text. It might indicate the presence of a hazard which could result in corruption of software or damage to equipment or property.</td>
</tr>
<tr>
<td><img src="image" alt="Information Icon" /></td>
<td>The information icon alerts the reader of important facts and conditions.</td>
</tr>
</tbody>
</table>
The tip icon indicates advice on, for example, how to design your project or how to use a certain function.

Although warning hazards are related to personal injury, it is necessary to understand that under certain operational conditions, operation of damaged equipment may result in degraded process performance leading to personal injury or death. It is important that the user fully complies with all warning and cautionary notices.

1.4.2 Document conventions

- Abbreviations and acronyms in this manual are spelled out in the glossary. The glossary also contains definitions of important terms.
- Push button navigation in the LHMI menu structure is presented by using the push button icons.
  For example, to navigate between the options, use and .
- HMI menu paths are presented in bold.
  For example, select Main menu/Settings.
- LHMI messages are shown in Courier font.
  For example, to save the changes in non-volatile memory, select Yes and press .
- Parameter names are shown in italics.
  For example, the function can be enabled and disabled with the Operation setting.
- Each function block symbol shows the available input/output signal.
  - the character ^ in front of an input/output signal name indicates that the signal name may be customized using the PCM600 software.
  - the character * after an input/output signal name indicates that the signal must be connected to another function block in the application configuration to achieve a valid application configuration.
- Dimensions are provided both in inches and mm. If it is not specifically mentioned then the dimension is in mm.
### Section 2  Available functions

Note that not all functions included in the tables below have commissioning information available.

#### 2.1 Main protection functions

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<th>Line Distance</th>
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<td></td>
<td>REL650</td>
</tr>
<tr>
<td></td>
<td></td>
<td>REL650 (A01A) 3Ph/1CB</td>
</tr>
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<td>Impedance protection</td>
<td></td>
<td></td>
</tr>
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<td>Five zone distance protection, quadrilateral and mho characteristic</td>
<td>1 1 1 1</td>
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<tr>
<td>FDPSPDIS 21</td>
<td>Phase selection with load enchroachment, quadrilateral characteristic</td>
<td>1 1 1 1</td>
</tr>
<tr>
<td>FMPSPDIS 21</td>
<td>Faulty phase identification with load enchroachment for mho</td>
<td>1 1 1 1</td>
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<td>ZDARDIR  21</td>
<td>Additional distance protection directional function for earth faults</td>
<td>1 1 1 1</td>
</tr>
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<td>ZDNRDIR  21D</td>
<td>Directional impedance quadrilateral and mho</td>
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<td>Phase preference logic</td>
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## 2.2 Back-up protection functions

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### 2.3 Control and monitoring functions

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**Frequency protection**

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**Control**

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**Monitoring**

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### Available functions

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**2.4 Station communication**

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**Scheme communication**

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### 2.5 Basic IED functions

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<td>Denial of service, frame rate control for LAN1A and LAN1B ports</td>
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<td>DOSSCKT</td>
<td>Denial of service, socket flow control</td>
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3.1 Factory and site acceptance testing

Testing the proper IED operation is carried out at different occasions, for example:

- Acceptance testing
- Commissioning testing
- Maintenance testing

This manual describes the workflow and the steps to carry out the commissioning testing.

Factory acceptance testing (FAT) is typically done to verify that the IED and its corresponding configuration meet the requirements of the utility or industry. This test is the most complex and in depth, as it is done to familiarize the user with a new product or to verify a new configuration. The complexity of this testing depends on several factors, such as:

- New IED type
- New configuration
- Modified configuration

Site acceptance testing (SAT or commissioning testing) is typically done to verify that the installed IED is correctly set and connected to the power system. SAT requires that the acceptance testing has been performed and that the application configuration is verified.

Maintenance testing is a periodic verification that the IED is healthy and has correct settings, depending on changes in the power system. There are also other types of maintenance testing.

3.2 Commissioning checklist

Before starting up commissioning at site, check that the following items are available.

- Single line diagram
- Protection block diagram
- Circuit diagram
- Setting list and configuration
- RJ-45 Ethernet cable (CAT 5)
• Three-phase test kit or other test equipment depending on the complexity of the configuration and functions to be tested.
• PC with PCM600 installed along with the connectivity packages corresponding to the IEDs to be tested.
• Administration rights on the PC, to set up IP addresses
• Product documentation (engineering manual, installation manual, commissioning manual, operation manual, technical manual and communication protocol manual)

3.3 Checking the power supply

Check that the auxiliary supply voltage remains within the permissible input voltage range under all operating conditions. Check that the polarity is correct before powering the IED.

3.4 Energizing the IED

3.4.1 Checking the IED operation

Check all connections to external circuitry to ensure correct installation, before energizing the IED and carrying out the commissioning procedures.

Energize the power supply of the IED to pickup. This could be done in a number of ways, from energizing a whole cubicle to energizing a single IED. Set the IED time if no time synchronization source is configured. Check the self-supervision function in **Main menu/Diagnostics/Internal events** or **Main menu/Diagnostics/IED status/General** menu in local HMI to verify that the IED is functioning properly.

3.4.2 IED start-up sequence

The following sequence is expected when the IED is energized.

• The green Ready LED picks up flashing instantly and the ABB logo is shown on the LCD.
• After approximately 30 seconds, "Starting" is shown on the LCD.
• Within 90 seconds, the main menu is shown on the LCD and the green Ready LED shows a steady light, which indicates a successful pick up.

The pickup time depends on the size of the application configuration. Application configurations with less functionality have shorter pickup times.
If the green Ready LED continues to flash after pickup, the IED has detected an internal error. Navigate via Main menu/Diagnostics/IED status/General to investigate the error description.

### 3.5 Setting up communication between PCM600 and the IED

The communication between the IED and PCM600 is independent of the communication protocol used within the substation or to the NCC.

The communication media is always Ethernet and the used protocol is TCP/IP.

Each IED has an RJ-45 Ethernet interface connector on the front. The front Ethernet connector shall be used for communication with PCM600.

When an Ethernet-based station protocol is used, PCM600 communication can use the same Ethernet port and IP address.

To connect PCM600 to the IED, two basic variants must be considered.

- Direct point-to-point link between PCM600 and the IED front port.
- Indirect link via a station LAN or from remote via a network.

The physical connection and the IP address must be configured in both cases to enable communication.

The communication procedures are the same in both cases.

1. If needed, set the IP address for the IEDs.
2. Set up the PC or workstation for a direct link (point-to-point), or
3. Connect the PC or workstation to the LAN/WAN network.
4. Configure the IED IP addresses in the PCM600 project for each IED to match the IP addresses of the physical IEDs.

### Setting up IP addresses

The IP address and the corresponding mask must be set via the LHMI for each available Ethernet interface in the IED. Each Ethernet interface has a default factory IP address when the IED is delivered. This is not given when an additional Ethernet interface is installed or an interface is replaced.

- The default IP address for the IED front port is 10.1.150.3 and the corresponding subnetwork mask is 255.255.255.0, which can be set via the local HMI path Main menu/Configuration/Communication/TCP-IP configuration/ETHFRNT:1.
Setting up the PC or workstation for point-to-point access to IEDs front port

A special cable is needed to connect two physical Ethernet interfaces together without a hub, router, bridge or switch in between. The Tx and Rx signal wires must be crossed in the cable to connect Tx with Rx on the other side and vice versa. These cables are known as cross over cables. The maximum length is 2 m. The connector type is RJ-45.

![Diagram of point-to-point link between IED and PCM600 using a null-modem cable](IEC09000096-2-en.vsd)

*Figure 2: Point-to-point link between IED and PCM600 using a null-modem cable*

The following description is an example valid for standard PCs using Microsoft Windows operating system. The example is taken from a Laptop with one Ethernet interface.

Administrator rights are required to change the PC communication setup. Some PCs have the feature to automatically detect that Tx signals from the IED are received on the Tx pin on the PC. Thus, a straight (standard) Ethernet cable can be used.

When a PC is connected to the IED and the setting **DHCP Server** is set to **Enabled** via the local HMI path `Main menu/Configuration/Communication/TCP-IP configuration/ETHFRNT:1/DHCP Server`, the IEDs DHCP server for the front port assigns an IP address for the PC. The PC must be configured to obtain its IP address automatically as described in the following procedure.

1. Select **Search programs and files** in the **Start menu** in Windows.
Figure 3: Select: Search programs and files

2. Type **View network connections** and click on the **View network connections** icon.
3. Right-click and select **Properties**.

4. Select the TCP/IPv4 protocol from the list of configured components using this connection and click **Properties**.
Figure 6: Select the TCP/IPv4 protocol and open Properties

5. Select **Obtain an IP address automatically** if the parameter *DHCPServer* is set to *Enabled* in the IED.
Figure 7: Select: Obtain an IP address automatically

6. Select **Use the following IP address** and define **IP address** and **Subnet mask** if the front port is used and if the **IP address** is not set to be obtained automatically by the IED, see Figure 8. The IP address must be different from the IP address chosen for the IED.
7. Close all open windows and start PCM600.

### Setting up the PC to access the IED via a network

This task depends on the used LAN/WAN network.

The PC and IED must belong to the same subnetwork for this set-up to work.

### 3.6 Writing an application configuration to the IED

Ensure that the IED includes the correct application configuration according to project specifications.

The application configuration is created using PCM600 and then written to the IED. Establish a connection between PCM600 and the IED when an application configuration must be written to the IED.
After writing an application configuration to the IED, the IED makes an application restart or a complete IED restart, when necessary.

The IED does not restart after reconfiguring IEC61850 (regardless of whether the protocol is enabled or disabled).

Be sure to set the correct technical key in both the IED and PCM600 to prevent writing an application configuration to a wrong IED.

See the engineering manual for information on how to create or modify an application configuration and how to write to the IED.

3.7 Checking CT circuits

Check that the wiring is in strict accordance with the supplied connection diagram.

- Primary injection test to verify the current ratio of the CT, the correct wiring up to the protection IED and correct phase sequence connection (that is A, B, C.)
- CT secondary loop resistance measurement to confirm that the current transformer secondary loop DC resistance is within specification and that there are no high resistance joints in the CT winding or wiring.
- Grounding check of the individual CT secondary circuits to verify that each three-phase set of main CTs is properly connected to the station ground and only at one electrical point.
- Insulation resistance check.

CT and VT connectors are pre-coded, and the CT and VT connector markings are different. For more information, see the installation manual.

Both the primary and the secondary sides must be disconnected from the line and the IED when plotting the excitation characteristics.
3.8 Checking VT circuits

Check that the wiring is in strict accordance with the supplied connection diagram.

Correct possible errors before continuing to test the circuitry.

Test the circuitry.

- Polarity check
- VT circuit voltage measurement (primary injection test)
- Grounding check
- Phase relationship
- Insulation resistance check

The polarity check verifies the integrity of circuits and the phase relationships. The check must be performed as close to the IED as possible.

The primary injection test verifies the VT ratio and the wiring all the way from the primary system to the IED. Injection must be performed for each phase-to-neutral circuit and each phase-to-phase pair. In each case, voltages in all phases and neutral are measured.

3.9 Using the RTXP test switch

The RTXP test switch is designed to provide the means of safe testing of the IED. This is achieved by the electromechanical design of the test switch and test plug handle. When the test plug handle is inserted, it first blocks the trip and alarm circuits then it short circuits the CT secondary circuit and opens the VT secondary circuits making the IED available for secondary injection.

When pulled out, the test handle is mechanically stopped in half withdrawn position. In this position, the current and voltage enter the protection, but the alarm and trip circuits are still isolated. Before removing the test handle, check that no trip or alarms are present in the IED.

Not until the test handle is completely removed, the trip and alarm circuits are restored for operation.
Verify that the contact sockets have been crimped correctly and that they are fully inserted by tugging on the wires. Never do this with current circuits in service.

Current circuit

1. Verify that the contacts are of current circuit type.
2. Verify that the short circuit jumpers are located in the correct slots.

Voltage circuit

1. Verify that the contacts are of voltage circuit type.
2. Check that no short circuit jumpers are located in the slots dedicated for voltage.

Trip and alarm circuits

1. Check that the correct types of contacts are used.

### 3.10 Checking binary input and output circuits

#### 3.10.1 Binary input circuits

Preferably, disconnect the binary input connector from the binary input cards. Check all connected signals so that both input level and polarity are in accordance with the IED specifications.

#### 3.10.2 Binary output circuits

Preferably, disconnect the binary output connector from the binary output cards. Check all connected signals so that both load and polarity are in accordance with IED specifications.

### 3.11 Checking optical connections

Check that the Tx and Rx optical connections are correct.

An IED equipped with optical connections requires a minimum depth of 180 mm (7.2 inches) for plastic fiber cables and 275 mm (10.9 inches) for...
glass fiber cables. Check the allowed minimum bending radius from the optical cable manufacturer.
Section 4 Establishing connection and verifying the IEC 61850 station communication

4.1 Setting the station communication

To enable IEC 61850 station communication:

- The IEC 61850-8-1 station communication functionality must be on in the local HMI. Navigate to Main menu/Configuration/Communication/Station communication/IEC61850-8-1:1 and set the Operation parameter to Enabled.
- To enable GOOSE communication the Operation parameter for the corresponding GOOSE function blocks (GOOSEBINRCV and GOOSEINTLKRCV) must be set to Enabled in the application configuration.
- To enable GOOSE communication via the front port the parameter PortSelGOOSE in Main menu/Configuration/Communication/Station communication/IEC61850-8-1:1 must be set to Front. To enable GOOSE communication via rear port the parameter PortSelGOOSE must be set to LAN1.
- To enable MMS communication via the rear port the parameter PortSelMMS in Main menu/Configuration/Communication/Station communication/IEC61850-8-1:1 must be set to LAN1.

4.2 Verifying the station communication

Connect your PC to the substation network and ping the connected IED and the Substation Master PC, to verify that the communication is working (up to the transport layer).

The best way to verify the communication up to the application layer is to use protocol analyzer connected to the substation bus, and monitor the communication.
Section 5 Testing IED operation

5.1 Preparing the IED to verify settings

If a test switch is included, start preparation by making the necessary connections to the test switch. This means connecting the test equipment according to a specific and designated IED terminal diagram.

Put the IED into the test mode to facilitate the test of individual functions and prevent unwanted operation caused by other functions. The busbar differential protection is not included in the test mode and is not prevented to operate during the test operations. The test switch should then be connected to the IED.

Verify that analog input signals from the analog input module are measured and recorded correctly by injecting currents and voltages required by the specific IED.

To make testing even more effective, use PCM600. PCM600 includes the Signal monitoring tool, which is useful in reading the individual currents and voltages, their amplitudes and phase angles. In addition, PCM600 contains the Disturbance handling tool. The content of reports generated by the Disturbance handling tool can be configured which makes the work more efficient. For example, the tool may be configured to only show time tagged events and to exclude analog information and so on.

Check the disturbance report settings to ensure that the indications are correct.

For test functions and test and signal parameter names, see the technical manual. The correct initiation of the disturbance recorder is made on pickup and/or release or trip from a function. Also check that the wanted recordings of analog (real and calculated) and binary signals are achieved.

The IEDs in the 650 series can have between 1 and 4 individual parameter setting groups prepared with full sets of different parameters for all functions. The purpose of these groups is to be able to handle different power system load conditions to optimize the parameters settings of the different functions for these different power systems conditions (for example summer/winter and day/night).

Parameters can be entered into different setting groups. Make sure to test functions for the same parameter setting group. If needed, repeat the tests for all different setting groups used. The difference between testing the
first parameter setting group and the remaining is that there is no need for testing the connections.

During testing, observe that the right testing method, that corresponds to the actual parameters set in the activated parameter setting group, is used.

In the local HMI the sensitive directional earth fault protection SDEPSDE parameter group 4 is active indicated by the * next to #4 and the test of the SDEPSDE must be performed according to the instructions given for the setting OpModeSel and setting value 3I03V0Cosfi.

Set and configure the function(s) before testing. Most functions are highly flexible and permit a choice of functional and tripping modes. The various modes are checked at the factory as part of the design verification. In certain cases, only modes with a high probability of coming into operation need to be checked when commissioned to verify the configuration and settings.

Requirements for testing the function.

- Calculated settings
- Valid configuration diagram for the IED
- Valid terminal diagram for the IED
- Technical manual
- Three-phase test equipment

Content of the technical manual.

- Application and functionality summaries
- Function blocks
- Logic diagrams
- Input and output signals
- A list of setting parameters
- Technical data for the function

The test equipment should be able to provide a three-phase supply of currents and three-phase voltage. The magnitude and angle of currents (and voltages) should be possible to vary. Check that the IED is prepared for test before starting the test session. Consider the logic diagram of the function when performing the test.

The response from a test can be viewed in different ways.

- Binary output signals
- Service values in the local HMI (logical signal or phasors)
- Using the online mode in the PCM600 configuration software
Do not switch off the auxiliary power supply to the IED before changes, for example, setting parameter or local/remote control state changes are saved.

A mechanism for limiting the number of writings per time period is included in the IED to prevent the flash memory to be worn out due to too many writings. As a consequence it may take up to an hour to save changes. If the auxiliary power is interrupted before a change is saved, that change is lost.

5.2 Activating the test mode

Put the IED into the test mode before testing. The test mode blocks all protection functions and some of the control functions in the IED, and the individual functions to be tested can be unblocked to prevent unwanted operation caused by other functions. In this way, it is possible to test slower back-up measuring functions without the interference from faster measuring functions. The busbar differential protection is not included in the test mode and is not prevented to operate during the test operations. The test switch should then be connected to the IED. Test mode is indicated when the yellow PickupLED flashes.

1. Select Main menu/Tests/IED test mode/TESTMODE:1
2. Set parameter TestMode to Enabled.
3. Save the changes.
   As a consequence, the yellow pickupLED starts flashing as a reminder and remains flashing until the test mode is switched off.

5.3 Preparing the connection to the test equipment

The IED can be equipped with a test switch of type RTXP8, RTXP18 or RTXP24 or FT. The test switch and its associated test plug handles are a part of the COMBITEST or FT system of ABB, which provides secure and convenient testing of the IED.

When using the COMBITEST, preparations for testing are automatically carried out in the proper sequence, that is, for example, blocking of tripping circuits, short circuiting of CT’s, opening of voltage circuits, making IED terminals available for secondary injection. Terminals 1 and 8, 1 and 18 as well as 1 and 12 of the test switches RTXP8, RTXP18 and RTXP24 respectively are not disconnected as they supply DC power to the protection IED. When FT switch is used for testing, care shall be exercised to open the tripping circuit, ahead of manipulating the CT fingers.
The RTXH test-plug handle leads may be connected to any type of test equipment or instrument. When a number of protection IEDs of the same type are tested, the test-plug handle only needs to be moved from the test switch of one protection IED to the test switch of the other, without altering the previous connections.

Use COMBITEST test system to prevent unwanted tripping when the handle is withdrawn, since latches on the handle secure it in the half withdrawn position. In this position, all voltages and currents are restored and any re-energizing transients are given a chance to decay before the trip circuits are restored. When the latches are released, the handle can be completely withdrawn from the test switch, restoring the trip circuits to the protection IED.

If a test switch is not used, perform measurement according to the provided circuit diagrams.

Never disconnect the secondary connection of a current transformer circuit without first short-circuiting the transformer's secondary winding. Operating a current transformer with the secondary winding open will cause a massive potential build up that may damage the transformer and cause personal injury.

5.4 Connecting the test equipment to the IED

Connect the test equipment according to the IED specific connection diagram and the needed input and output signals for the function under test. An example of a connection is shown in figure 9.

Connect the current and voltage terminals. Pay attention to the current polarity. Make sure that the connection of input and output current terminals and the connection of the residual current conductor is correct. Check that the input and output logical signals in the logic diagram for the function under test are connected to the corresponding binary inputs and outputs of the IED under test.

To ensure correct results, make sure that the IED as well as the test equipment are properly grounded before testing.
5.5 Releasing the function to be tested

Release or unblock the function to be tested. This is done to ensure that only the function or the chain of functions to be tested are in operation and that other functions are prevented from operating. Release the tested function(s) by setting the corresponding Blocked parameter under Function test modes to No in the local HMI.

When testing a function in this blocking feature, remember that not only the actual function must be activated, but the whole sequence of interconnected functions (from measuring inputs to binary output contacts), including logic must be activated. Before starting a new test mode session, scroll through every function to ensure that only the function to be tested (and the interconnected ones) have the parameters Blocked and eventually EvDisable set to No and Yes respectively. Remember that a function is also blocked if the BLOCK input signal on the corresponding function block is active, which depends on the configuration. Ensure that the logical status of the BLOCK input signal is equal to 0 for the function to be tested. Event function blocks can also be individually blocked to ensure that no events are reported to a remote station during the test. This is done by setting the parameter EvDisable to Yes.
Any function is blocked if the corresponding setting in the local HMI under Main menu/Tests/Function test modes menu remains Enabled, that is, the parameter Blocked is set to Yes and the parameter TestMode under Main menu/Tests/IED test mode remains active. All functions that were blocked or released in a previous test mode session, that is, the parameter Test mode is set to Enabled, are reset when a new test mode session is started.

Procedure

1. Click the Function test modes menu. The Function test modes menu is located in the local HMI under Main menu/Tests/Function test modes.
2. Browse to the function instance that needs to be released.
3. Set parameter Blocked for the selected function to No.

5.6 Verifying analog primary and secondary measurement

Verify that the connections are correct and that measuring and scaling is done correctly. This is done by injecting current and voltage to the IED.

Apply input signals as needed according to the actual hardware and the application configuration.

1. Inject a symmetrical three-phase voltage and current at rated value.
2. Compare the injected value with the measured values.
   The voltage and current phasor menu in the local HMI is located under Main menu/Measurements/Analog primary values and Main menu/Measurements/Analog secondary values.
3. Compare the frequency reading with the set frequency and the direction of the power.
   The frequency and active power are located under Main menu/Tests/Function status/Monitoring/CVMMXN/CVMMXN:1/Outputs. Then navigate to the bottom of the list to find the frequency.

Check both analog primary and secondary values, because then the CT and VT ratios entered into the IED are also checked.
These checks shall be repeated for Analog primary values.

4. Inject an unsymmetrical three-phase voltage and current, to verify that phases are correctly connected.

If some setting deviates, check the analog input settings under

**Main menu/Configuration/Analog modules**

Measured values such as current and voltages as well as active, reactive and apparent power, power factor phase angles as well as positive and negative and zero sequence currents and voltages are available in the local HMI under **Main menu/Tests/Function status/Monitoring**.

Navigate to the measurement function that contains the quantity to be checked.

<table>
<thead>
<tr>
<th>Table 1: Measurement functions</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>Function</strong></td>
</tr>
<tr>
<td>CMXU</td>
</tr>
<tr>
<td>CMSQI</td>
</tr>
<tr>
<td>CVMMXN</td>
</tr>
<tr>
<td>VMMXU</td>
</tr>
<tr>
<td>VMSQI</td>
</tr>
<tr>
<td>VNMMXU</td>
</tr>
</tbody>
</table>

Also the Signal Monitoring tool in PCM600 can be used to read the measured values. In many cases it is more convenient to use PCM600 since, among many things, reports on measured values can be exported from the Signal Monitoring tool to other tools (for example, MS Excel) for further analysis.

### 5.7 Testing the protection functionality

Each protection function must be tested individually by secondary injection.

- Verify operating levels (trip) and timers.
- Verify alarm and blocking signals.
- Use the disturbance handling tool in PCM600 to evaluate that the protection function has received the correct data and responded correctly (signaling and timing).
- Use the event viewer tool in PCM600 to check that only expected events have occurred.
Section 6  Testing functionality

6.1  Testing disturbance report

6.1.1  Introduction

The following sub-functions are included in the disturbance report function:

• Disturbance recorder
• Event list
• Event recorder
• Fault locator
• Trip value recorder
• Indications

If the disturbance report is enabled, then its sub-functions are also set up and so it is not possible to only disable these sub-functions. The disturbance report function is disabled (parameter Operation = Disabled) in PCM600 or the local HMI under Main menu/Settings/IED Settings/Monitoring/Disturbance report/DRPRDRE:1.

6.1.2  Disturbance report settings

When the IED is in test mode, the disturbance report can be made active or inactive. If the disturbance recorder is turned on during test mode, recordings will be made. When test mode is switched off all recordings made during the test session are cleared.

Setting OpModeTest for the control of the disturbance recorder during test mode are located on the local HMI under Main menu/Settings/IED Settings/Monitoring/Disturbance report/DRPRDRE:1.

6.2  Identifying the function to test in the technical reference manual

Use the technical manual to identify function blocks, logic diagrams, input and output signals, setting parameters and technical data.
6.3 Testing impedance protection functions

6.3.1 Five zone distance protection, quadrilateral and mho characteristic ZQMPDIS (21)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ZQMPDIS (21) are available on the local HMI under Main menu/Tests/Function status/Impedance/ZQMPDIS(21,Z<)/ZQMPDIS:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.3.1.1 Quadrilateral characteristics

Consider releasing Zone 1, the Phase selection with load encroachment, quadrilateral characteristic FDPSPDIS (21) and the Tripping logic SMPPTRC (94).

Measure operating characteristics during constant current conditions. Keep the measured current as close as possible to its rated value or lower. But make sure it is higher than the set minimum operating current.

Ensure that the maximum continuous current to the IED does not exceed four times its rated value, if the measurement of the operating characteristics runs under constant voltage conditions.

The test procedure has to take into consideration that the shaped load encroachment characteristic is active. It is therefore necessary to check the setting. To verify the settings with the shaped load encroachment characteristic the test should be carried out according to figures 10 and 11 and tables 2 and 3.

To verify the settings the following fault types should be tested:

- One phase-to-phase fault
- One phase-to-ground fault

The shape of the operating characteristic depends on the values of the setting parameters.

Phase-to-phase faults

The angles a (angle on blinder in second quadrant for forward direction), b (load angle determining the load impedance area), c (angle to blinder in fourth quadrant for forward direction), d (line angle) and e (angle for ground compensation factor KN) in the figures below are adjusted with the parameters ArgNegRes, ArgLd, ArgDir, LineAng and KNAng respectively.
Figure 10: Distance protection characteristic with test points for phase-to-phase measurements

Table 2: Test points for phase-to-phase loops A-B (Ohm/phase)

<table>
<thead>
<tr>
<th>Test point</th>
<th>Reach</th>
<th>Set value</th>
<th>Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>X</td>
<td>Z · Sin (LineAng)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0</td>
<td></td>
</tr>
<tr>
<td>2</td>
<td>X</td>
<td>0</td>
<td></td>
</tr>
<tr>
<td></td>
<td>F</td>
<td>RLdFw</td>
<td>When RLdFw &lt; 0.5 * RFPP</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.5 * RFPP</td>
<td>When RLdFw &gt; 0.5 * RFPP</td>
</tr>
<tr>
<td>3</td>
<td>X</td>
<td>0.8 · Z · Sin (LineAng)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.8 · Z · Cos (LineAng) + RFPP/2</td>
<td></td>
</tr>
<tr>
<td>4</td>
<td>X</td>
<td>0.8 · Z · Sin (LineAng)</td>
<td>Can be limited by 0.5 * RFPP setting</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>-0.8 · Z · Sin (LineAng) · tan (ArgNegRes-90)</td>
<td></td>
</tr>
<tr>
<td>5</td>
<td>X</td>
<td>0.5 · RFPP · tan (ArgLd)</td>
<td>Only when RLdFw &lt; 0.5 * RFPP</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.5 · RFPP</td>
<td></td>
</tr>
<tr>
<td>6</td>
<td>X</td>
<td>-0.5 RLdFw · tan (ArgDir)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.5 · RLdFw</td>
<td></td>
</tr>
<tr>
<td>7</td>
<td>X</td>
<td>0.5 · Z · Sin (LineAng)</td>
<td>Time measurement</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0</td>
<td></td>
</tr>
</tbody>
</table>

Table 2 is used in conjunction with figure 10.
Table 3 is used in conjunction with figure 11.

Table 3: Test points for phase-to-ground C-E (Ohm/Loop)

<table>
<thead>
<tr>
<th>Test point</th>
<th>Reach</th>
<th>Value</th>
<th>Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>X</td>
<td>Z · Sin (LineAng) + KNMag · Z · Sin (LineAng + KNAng)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0</td>
<td></td>
</tr>
<tr>
<td>2</td>
<td>X</td>
<td>0</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>RLdFw</td>
<td>When RLdFw &lt; RFPE</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>RFPE</td>
<td>When RLdFw &gt; RFPE</td>
</tr>
<tr>
<td>3</td>
<td>X</td>
<td>0.8 (Z · Sin (LineAng) + KNMag · Z · Sin (LineAng + KNAng))</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.8(Z · Cos (LineAng) + KNMag · Z · Cos (LineAng + KNAng)) + RFPE</td>
<td></td>
</tr>
<tr>
<td>4</td>
<td>X</td>
<td>0.8 (Z · Sin (LineAng) + KNMag · Z · Sin (LineAng + KNAng))</td>
<td>Can be limited by RFPE</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>-(0.8 (Z · Sin (LineAng) + KNMag · Z · Sin (LineAng + KNAng)) · tan (ArgNegRes-90))</td>
<td></td>
</tr>
</tbody>
</table>

Table continues on next page
### 6.3.1.2 Mho characteristics

#### Phase-to-phase faults

<table>
<thead>
<tr>
<th>Test point</th>
<th>Reach</th>
<th>Value</th>
<th>Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>5</td>
<td>X</td>
<td>RFPE · tan (ArgLd)</td>
<td>Only when RLdFw &lt; RFPE</td>
</tr>
<tr>
<td>R</td>
<td>RFPE</td>
<td></td>
<td></td>
</tr>
<tr>
<td>6</td>
<td>X</td>
<td>-0.5 RLdFw · tan (ArgDir)</td>
<td></td>
</tr>
<tr>
<td>R</td>
<td>0.5 RLdFw</td>
<td></td>
<td></td>
</tr>
<tr>
<td>7</td>
<td>X</td>
<td>0.5 (Z · Sin (LineAng) + KNMag · Z · Sin (LineAng + KNAng))</td>
<td>Time measurement</td>
</tr>
<tr>
<td>R</td>
<td>0</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

**Figure 12:** Proposed test points for phase-to-phase fault

**Table 4:** Test points for phase-to-phase (ohms / phase)

<table>
<thead>
<tr>
<th>Test points</th>
<th>Reach</th>
<th>Value</th>
<th>Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>X</td>
<td>ZPP · sin(ZAngPP)</td>
<td></td>
</tr>
<tr>
<td>R</td>
<td>ZPP · sin(ZAngPP)</td>
<td></td>
<td></td>
</tr>
<tr>
<td>2</td>
<td>X</td>
<td>0.5 · (ZPP · sin(ZAngPP))</td>
<td></td>
</tr>
<tr>
<td>R</td>
<td>0.5·ZPP + ΔR = 0.5·ZPP·(1+cos(ZAngPP))</td>
<td></td>
<td></td>
</tr>
<tr>
<td>3</td>
<td>X</td>
<td>0.5·ZPP·sin(ZAngPP)</td>
<td></td>
</tr>
<tr>
<td>R</td>
<td>0.5·ZPP - ΔR = 0.5·ZPP·(1-cos(ZAngPP))</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>
Change the magnitude and angle of phase-to-phase voltage to achieve impedances at test points 1, 2 and 3. For each test point, observe that the output signals, PICKUP and TRx are activated where x refers to the actual phase to be tested. After the timer \( t_{PP} \) for the actual zone has elapsed, also the signals TRIP and TRx shall be activated.

**Phase-to-ground faults**

For simplicity, the same test points as for phase-to-phase faults are proposed, but considering new impedance values.

![Diagram of impedance values](IEC07000010-4-en.vsd)

**Figure 13:**

**Table 5:** *Test points for phase-to-phase loops A-B (Ohm/Loop)*

<table>
<thead>
<tr>
<th>Test points</th>
<th>Reach</th>
<th>Value</th>
<th>Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>X</td>
<td>ZPE \cdot \sin(ZAngPE)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>ZPE \cdot \cos(ZAngPE)</td>
<td></td>
</tr>
<tr>
<td>2</td>
<td>X</td>
<td>0,5 \cdot ZPE \cdot \sin(ZAngPE)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0,5 \cdot ZPE + \Delta R = 0,5 \cdot ZPE \cdot (1 - \cos(ZAngPE))</td>
<td></td>
</tr>
<tr>
<td>3</td>
<td>X</td>
<td>0,5 \cdot ZPE \cdot \sin(ZangPE)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0,5 \cdot ZPE - \Delta R = 0,5 \cdot ZPE \cdot (1 - \cos(ZAngPE))</td>
<td></td>
</tr>
</tbody>
</table>

Check also in the same way as for phase-to-ground fault for each test point that the output signals TRIP and TRx are activated where x refers to the actual phase to be tested. After the timer \( t_{PE} \) for the zone has elapsed, also the signals TRIP and TRx shall be activated.
6.3.1.3 Measuring the operating limit of set values with shaped load encroachment characteristics

1. Subject the IED to healthy normal load conditions for at least two seconds.
2. Apply the fault condition and slowly decrease the measured impedance to find the operating value of the phase-to-phase fault A-B for zone 1 according to test point 1 in figure 10 and table 2. Compare the result of the measurement with the set value.
3. Repeat steps 1 to 2 to find the operating value for the remaining test points.
   Observe that the zones that are not tested have to be blocked and the zone that is tested has to be released.
4. Repeat steps 1 to 3 to find the operating value for the phase-to-ground fault C-E according to figure 11 and table 3.

Test point 6 is intended to test the directional line of impedance protection. Since directionality is a common function for all 5 measuring zones, it is only necessary to test point 6 once, in the forward direction. Directional functionality testing (trip inside, no-trip outside) should always be carried for all impedance zones set with directionality (forward or reverse).

6.3.1.4 Measuring the operate time of distance protection zones

1. Subject the IED to healthy normal load conditions for at least two seconds.
2. Apply the fault condition to find the operating time for the phase-to-phase fault according to test point 7 in figure 10 and table 2 for zone 1. Compare the result of the measurement with the setting $t_{1PP}$.
3. Repeat steps 1 to 2 to find the operating time for the phase-to-ground fault according to test point 7 in figure 11 and table 3. Compare the result of the measurement with the setting $t_{1PE}$.
4. Repeat steps 1 to 2 to find the operating time for all other used measuring zones. Observe that the zones that are not tested have to be blocked and the zone that is tested has to be released.

6.3.1.5 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Impedance/ZQMPDIS(21,Z<)/ZQMPDIS:1.
individual function in a chain, to be tested next. Remember to set the parameter *Blocked* to *Yes*, for each individual function that has been tested.

### 6.3.2 Phase selection with load encroachment, quadrilateral characteristic FDPSPDIS (21)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for FDPSPDIS are available on the local HMI under *Main menu/Tests/Function status/Impedance/FDPSPDIS/FDPSPDIS:1*. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The phase selectors operate on the same measuring principles as the impedance measuring zones. So it is necessary to follow the same principles as for distance protection, when performing the secondary injection tests.

Measure operating characteristics during constant current conditions. Keep the measured current as close as possible to the rated value of its associated input transformer, or lower. But ensure that it is higher than the set minimum operating current.

Ensure that the maximum continuous current to the IED does not exceed four times its rated value, if the measurement of the operating characteristics runs under constant voltage conditions.

To verify the settings the operating points according to figures 14 and 15 should be tested. See also tables 6 and 7 for information.
Figure 14: Operating characteristic for phase selection function, forward direction single-phase faults

Table 6: Test points for phase-ground loop CG (Ohm/loop)

<table>
<thead>
<tr>
<th>Test point</th>
<th>Reach</th>
<th>Value</th>
<th>Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>X</td>
<td>[X1+XN]</td>
<td>XN=(X0-X1)/3</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0</td>
<td></td>
</tr>
<tr>
<td>2</td>
<td>X</td>
<td>0</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>RLdFwd</td>
<td>When RLdFwd &lt; RFltFwPG</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>RFltFwPG</td>
<td>When RLdFwdPG &gt; RFltFwPG</td>
</tr>
<tr>
<td>3</td>
<td>X</td>
<td>0.85·[X1+XN]</td>
<td>R≈0.491·(X1+XN)+RFltFwPGPG</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td></td>
<td></td>
</tr>
<tr>
<td>4</td>
<td>X</td>
<td>0.85·[X1+XN]</td>
<td>Can be limited by RFltFwPG</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>-0.85·[X1+XN]·tan (AngNegRes-90°)</td>
<td></td>
</tr>
<tr>
<td>5</td>
<td>X</td>
<td>RFltFwPG·tan (LdAngle)</td>
<td>Only when RLdFwd &lt; RFltFwPGPG</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>RFltFwPG</td>
<td></td>
</tr>
<tr>
<td>6</td>
<td>X</td>
<td>-0.5·RLdFwd·tan (ArgDir)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.5·RLdFwd</td>
<td></td>
</tr>
</tbody>
</table>

Table 6 is used together with figure 14.
Table 7:  Test points for phase-to-phase loops A-B (Ohm/phase)

<table>
<thead>
<tr>
<th>Test point</th>
<th>Reach</th>
<th>Value</th>
<th>Comments</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>X</td>
<td>X1</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0</td>
<td></td>
</tr>
<tr>
<td>2</td>
<td>X</td>
<td>0</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>RLdFwd</td>
<td>When RLdFwd &lt; 0.5·RFltFwdPP</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.5·RFltFwdPP</td>
<td>When RLdFwd &gt; 0.5·RFltFwdPP</td>
</tr>
<tr>
<td>3</td>
<td>X</td>
<td>0.85·X1</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.85·X1·1/tan(60°)+0.5 RFltFwdPP</td>
<td>R=0.491·X1+0.5 RFltFwdPP</td>
</tr>
<tr>
<td>4</td>
<td>X</td>
<td>0.85·X1</td>
<td>Can be limited by RFltFwdPP</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>-0.85·X1·tan (AngRes-90°)</td>
<td></td>
</tr>
<tr>
<td>5</td>
<td>X</td>
<td>0.5·RFltFwdPP·tan (ArgLd)</td>
<td>Only when RLdFwd &lt; RFltFwdPP</td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.5·RFltFwdPP</td>
<td></td>
</tr>
<tr>
<td>6</td>
<td>X</td>
<td>-0.5·RLdFwd·tan (ArgDir)</td>
<td></td>
</tr>
<tr>
<td></td>
<td>R</td>
<td>0.5·RLdFwd</td>
<td></td>
</tr>
</tbody>
</table>

*Figure 15:  Operating characteristic for phase selection function, forward direction phase-to-phase faults*
6.3.2.1 Measuring the operate limit of set values

1. Supply the IED with healthy conditions for at least two seconds.
2. Apply the fault condition and slowly decrease the measured impedance to find the operate value for of the phase-to-ground loop ECG, test point 1, according to figure 14. Compare the result of the measurement with the expected value according to table 6.
   The corresponding binary signals that inform about the operation of the phase selection measuring elements are available in the local HMI under Main menu/Tests/Function status/Impedance/FDPSPDIS.
3. Repeat steps 1 to 2 to find the operate values for the remaining test points according to figure 14 and table 6.

4. Repeat steps 1 to 3 to find the operate value for the phase-to-phase fault in A - C according to figure 15 and table 7.

6.3.2.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Impedance/FDPSPDIS/FDPSPDIS:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.3.3 Faulty phase identification with load encroachment FMPSPDIS (21)

There is no specific test routine for this function. The function is tested in conjunction with other impedance (mho) functions.

6.3.4 Phase preference logic PPLPHIZ

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".
Values of the logical signals for PPLHPIZ are available on the local HMI under Main menu/Tests/Function status/Impedance/PPLHPIZ/PPLHPIZ:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The Phase preference logic function PPLPHIZ is tested with a three-phase testing equipment for distance protections. PPLPHIZ is tested in co-operation with the Five zone distance protection, quadrilateral and mho characteristic function ZQMPDIS (21). The distance protection and the phase preference logic shall be set to values according to the real set values to be used. The test is made by means of injection of voltage and current where the amplitude of both current and voltage and the phase angle between the voltage and current can be controlled.

During the test the following binary signals (outputs) shall be monitored:

- Trip signal from distance protection
- Trip signal from phase preference logic

1. Connect the test set for injection of voltage and current.
2. Inject voltages and currents corresponding to a phase-to-phase to ground fault within zone 1 of the distance protection function. In the test one of the current inputs (one of the faulted phases) is disconnected. The remaining current is the fault current out on the protected line. All combinations of two phase-to-ground faults with one phase current are tested. The result shall be according to table 8. It should be checked that the fault will give phase-to-phase voltage, phase-to-ground voltage, zero-sequence voltage and phase current so that the conditions set for the logic are fulfilled.

### Table 8: Operation at different combinations of faults and operation mode

<table>
<thead>
<tr>
<th>OperMode</th>
<th>Fault type/Faulted phase current to the IED</th>
</tr>
</thead>
<tbody>
<tr>
<td></td>
<td>A_BG/IA</td>
</tr>
<tr>
<td>No Filter</td>
<td>Trip</td>
</tr>
<tr>
<td>No Pref</td>
<td>Trip</td>
</tr>
<tr>
<td>1231c</td>
<td>Trip</td>
</tr>
<tr>
<td>1321c</td>
<td>No Trip</td>
</tr>
<tr>
<td>123a</td>
<td>Trip</td>
</tr>
<tr>
<td>132a</td>
<td>Trip</td>
</tr>
<tr>
<td>213a</td>
<td>No Trip</td>
</tr>
<tr>
<td>231a</td>
<td>No Trip</td>
</tr>
<tr>
<td>312a</td>
<td>Trip</td>
</tr>
<tr>
<td>321a</td>
<td>No Trip</td>
</tr>
</tbody>
</table>
6.3.4.1 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Off under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No, under Main menu/Tests/Function test modes/<Function group>/<Function>/<Function:1> for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.3.5 Power swing detection ZMRPSB (68)

The aim is to verify that the settings of the Power swing detection function ZMRPSB (68) is according to the setting table and to verify that ZMRPSB (68) operates as expected.

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ZMRPSB (68) are available on the local HMI under Main menu/Tests/Function status/Impedance/ZMRPSB(68)/ZMRPSB:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

Before starting this process, all impedance measuring zones shall be set and in operation. Test the outer resistive boarder in forward and reverse direction, RLdOutFw and RLdOutRv and the inner reactive boarder in forward and reverse direction X1InFw and X1InRv. See figure 16.

The corresponding resistive boarder for the inner resistive boundary and outer resistive boundary is calculated automatically from the setting of kLdRFw and kLdRRv.

The inner zone of ZMRPSB (68) must cover all zones by at least 10% margin.

The test is mainly divided into two parts, one which aim is to verify that the settings are in accordance to the selective plane and a second part to verify the operation of ZMRPSB (68). The proposed test points for validation of the settings are numbered according to figure 16.

Test of the interactions or combinations that are not configured are not considered in this instruction.
Where:

\[ RLdInFw = RLdOutFw \cdot kLdRFw \]
\[ RLdInRv = RLdOutRv \cdot kLdRRv \]
\[ X1OutFw = X1InFw + (RLdOutFw - RLdInFw) \]
\[ X1OutRv = X1InRv + (RLdOutFw - RLdInFw) \]

6.3.5.1 Verifying the settings

Preconditions

The following output signal shall be configured to binary output available: ZOUT, measured impedance within outer impedance boundary.
1. Keep the measured current as close as possible to its rated value or lower. Keep it constant during the test, but ensure that it is higher than the set minimum operating current.

2. Ensure that the maximum continuous current to the IED does not exceed four times its rated value, if the measurement of the operating characteristics runs under constant voltage conditions.

3. Make the necessary connections and settings of the test equipment for test of point 1 according to figure 16.

4. Decrease the measured three-phase impedance slowly and observe the operation value for the signal ZOUT.

5. Compare the operation value with the set value.

6. Do the necessary change of the setting of the test equipment and repeat step 4 and step 5 for point 2, 3 and 4 according to figure 16.

6.3.5.2 Testing the power swing detection function ZMRPSB (68)

Preconditions

The following output signals shall be configured to binary outputs: ZOUT, measured impedance within outer impedance boundary, ZIN, measured impedance within inner impedance boundary and PICKUP, power swing detection.

1. Slowly decrease the measured impedance in all three phases until the PICKUP signal gets activated.

2. Increase the measured voltages to their rated values.

3. Decrease instantaneously voltages in all three phases to the values, which are approximately 20% lower than the voltage that gives the set value $RILIn$ at the predefined test current.

4. The PICKUP signal must not appear.

5. Increase the measured voltages to their rated values.

6.3.5.3 Testing the $tR1$ timer

Preconditions

- The input I0CHECK, residual current ($3I_0$) detection used to inhibit the pickup output must be configured to the output signal STPE on the FDPSPDIS (21) function.
- The input BLK_SS, block inhibit of the pickup output for subsequent residual current detection is connected to FALSE.
1. Program the test equipment for a single-phase to ground fault and energize FDPSPDIS (21) and check that the input BLOCK on the power swing detection function ZMRPSB (68) is activated.

2. Make a test sequence so that a single-phase to ground fault occurs after that the trajectory of the impedance has passed the outer and inner boundary of ZMRPSB (68) during power swing. Use the result from test of ZMRPSB (68) above to determine when the fault shall be applied. The ground-fault must be activated before tR1 has elapsed.

3. Start the sequence and observe that the PICKUP signal will not be activated.

6.3.5.4 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Impedance/ZMRPSB(68)/ZMRPSB:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.3.6 Automatic switch onto fault logic, voltage and current based ZCVPSOF

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ZCVPSOF are available on the local HMI under Main menu/Tests/Function status/Impedance/ZCVPSOF/ZCVPSOF:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

Automatic switch onto fault logic, voltage and current based function ZCVPSOF is checked using secondary injection tests together with the Scheme communication logic for distance or overcurrent protection function ZCPSCH (85) and with the dead line detection function (DLD), which is embedded in ZCVPSOF. ZCVPSOF is activated either by the external input BC, or by the internal DLD. SDDRFUF is done with a pre-fault condition where the phase voltages and currents are at zero. A reverse three-phase fault with zero impedance and a three-phase fault with an impedance corresponding to the whole line is applied. This fault shall cause an instantaneous trip and result in a TRIP indication.

6.3.6.1 External activation of ZCVPSOF

1. Activate the switch onto fault BC input.
During normal operating conditions, the BC input is de-energized.

2. Apply a three-phase fault condition corresponding to a fault at approximately 45% of the line or with an impedance at 50% of used zone setting and current greater than 30% of \( I_n \).

3. Check that the correct trip outputs, external signals and indication are obtained.

6.3.6.2 Automatic initiation of ZCVPSOF

1. Deactivate the switch onto fault BC input.
2. Set current and voltage inputs to 0 for at least 1 second.
3. Apply a three-phase fault condition corresponding to a fault at approximately 45% of the line or with an impedance at 50% of used zone setting and current greater than 30% of \( I_n \).
4. Check that the correct trip outputs, external signals and indication are obtained.

6.3.6.3 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Impedance/ZCVPSOF/ZCVPSOF:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.4 Testing current protection functions

6.4.1 Instantaneous phase overcurrent protection 3-phase output PHPIOC (50)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for PHPIOC (50) are available on the local HMI under Main menu/Tests/Function status/Current/PHPIOC(50,1)>>)/PHPIOC:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

To verify the settings the following fault type should be tested:

- Phase-to-ground fault
Ensure that the maximum continuous current, supplied from the current source used for the test of the IED, does not exceed four times the rated current value of the IED.

### 6.4.1.1 Measuring the operate limit of set values

1. Inject a phase current into the IED with an initial value below that of the setting.
2. Increase the injected current until the TRIP signal appears.
3. Switch the fault current off.

Observe: Do not exceed the maximum permitted overloading of the current circuits in the IED.

4. Compare the measured operating current with the set value.

### 6.4.1.2 Completing the test

Continue to test another function or end the testing by setting the parameter *TestMode* to *Disabled* under *Main menu/Tests/IED test mode/TESTMODE:*1. If another function is tested, then set the parameter *Blocked* to *No* under *Main menu/Tests/Function test modes/Current/PHPIOC(50,I>>)/PHPIOC:*1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter *Blocked* to *Yes*, for each individual function that has been tested.

### 6.4.2 Instantaneous phase overcurrent protection phase segregated output SPTPIOC (50)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for SPTPIOC (50) are available on the local HMI under *Main menu/Tests/Function status/Current/SPTPIOC(50,I>>)/SPTPIOC:*1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

To verify the settings the following fault type should be tested:

- Phase-to-ground fault

Ensure that the maximum continuous current, supplied from the current source used for the test of the IED, does not exceed four times the rated current value of the IED.

1. Inject a phase current into the IED with an initial value below that of the setting.
2. Increase the injected current in the Ln phase until the TR_A (TR_B or TR_C) signal appears.
3. Switch the fault current off. Observe to not exceed the maximum permitted overloading of the current circuits in the IED.
4. Compare the measured operating current with the set value.

6.4.2.1 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/SPTPIOC(50,I>>)/SPTPIOC:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.4.3 Four step phase overcurrent protection 3-phase output OC4PTOC (51_67)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for OC4PTOC (51_67) are available on the local HMI under Main menu/Tests/Function status/Current/OC4PTOC(51_67,4I>/OC4PTOC:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.4.3.1 Verifying the settings

1. Connect the test set for current injection to the appropriate IED phases.
   If there is any configuration logic that is used to enable or block any of the four available overcurrent steps, make sure that the step under test is enabled (for example, end fault protection).
   Connect the symmetrical three-phase injection current into phases A, B and C.
2. Connect the test set for the appropriate three-phase voltage injection to the IED phases A, B and C. The protection shall be fed with a symmetrical three-phase voltage.
3. Set the injected polarizing voltage slightly larger than the set minimum polarizing voltage (default is 5% of VBase) and set the injection current to lag the appropriate voltage by an angle of 55° if forward directional function is selected.
   If 1 out of 3 currents for operation is chosen: The voltage angle of phase A is the reference.
   If reverse directional function is selected, set the injection current to lag the polarizing voltage by an angle equal to 235° (equal to 55° + 180°).
4. Increase the injected current and note the operate value of the tested step of the function.
5. Decrease the current slowly and note the reset value.
6. If the test has been performed by injection of current in phase A, repeat the test, injecting current into phases B and C with polarizing voltage connected to phases B, respectively C (1 out of 3 currents for operation).
7. If the test has been performed by injection of current in phases AB, repeat the test, injecting current into phases BC and CA with the appropriate phase angle of injected currents.
8. Block higher set stages when testing lower set stages by following the procedure described below.
9. Connect a trip output contact to a timer.
10. Set the injected current to 200% of the operate level of the tested stage, switch on the current and check the time delay. For inverse time curves, check the operate time at a current equal to 110% of the operate current for $t_xMin$.
11. Check that all trip and pickup contacts operate according to the configuration (signal matrixes).
12. Reverse the direction of the injected current and check that the protection does not operate.
13. Repeat the above described tests for the higher set stages.
14. Finally check that pickup and trip information is stored in the event menu.

Verification of the non-directional phase overcurrent function is done as instructed above, without applying any polarizing voltage.

6.4.3.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/OC4PTOC(51_67,4I>)/OC4PTOC:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.4.4 Four step phase overcurrent protection phase segregated output OC4SPTOC (51_67)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".
Values of the logical signals for OC4SPTOC (51_67) are available on the local HMI under Main menu/Tests/Function status/Current/OC4SPTOC(51_67,4I>)/OC4SPTOC:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.4.4.1 Verifying the settings

1. Connect the test set for appropriate current injection to the appropriate IED phases. If there is any configuration logic that is used to enable/block any of the four available overcurrent steps, make sure that the step under test is enabled, for example end fault protection. Connect the symmetrical three-phase injection current into phases A, B and C.

2. Connect the test set for the appropriate three-phase voltage injection to the IED phases A, B and C. Make sure that the protection is fed with a symmetrical three-phase voltage.

3. Set the injected polarizing voltage slightly larger than the set minimum polarizing voltage (default is 5% of $V_{Base}$) and set the injection current to lag the appropriate voltage by an angle of about 55° if forward directional function is selected. If reverse directional function is selected, set the injection current to lag the polarizing voltage by an angle equal to 235° (equal to 55° + 180°).

4. Increase the injected current and note the operated value of the tested step of the function.

5. Decrease the current slowly and note the reset value.

6. If the test has been performed by injection of current in phase A, repeat the test when injecting current into phases B and C with polarizing voltage connected to phases B respectively C (1 of 3 currents for operation).

7. If the test has been performed by injection of current in phases AB, repeat the test when injecting current into phases BC and CA with appropriate phase angle of injected currents.

8. Block higher set stages when testing lower set stages according to below.

9. Connect a trip output contact to a timer.

10. Set the injected current to 200% of the operate level of the tested stage, switch on the current and check the time delay. For inverse time curves, check the operate time at a current equal to 110% of the operate current for $t_{\text{Min}}$.

11. Check that all trip and pickup contacts operate according to the configuration (signal matrixes).

12. Reverse the direction of the injected current and check that the protection does not operate.

13. Repeat the above-described tests for the higher set stages.

14. Finally check that pickup and trip information is stored in the event menu.
Check of the non-directional phase over-current function. This is done in principle as instructed above, without applying any polarizing voltage.

6.4.4.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/OC4SPTOC(51_67,4I>)/OC4SPTOC:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.4.5 Instantaneous residual overcurrent protection EFPIOC (50N)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for EFPIOC (50N) are available on the local HMI under Main menu/Tests/Function status/Current/EFPIOC(50N,IN>>)/EFPIOC:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

To verify the settings the following fault type should be tested:

• Phase-to-ground fault

Ensure that the maximum continuous current, supplied from the current source used for the test of the IED, does not exceed four times the rated current value of the IED.

6.4.5.1 Measuring the operate limit of set values

1. Inject a phase current into the IED with an initial value below that of the setting.
2. Increase the injected current in the Ln or in the neutral (summated current input) phase until the TRIP signal appears.
3. Disable the fault current
   Observe to not exceed the maximum permitted overloading of the current circuits in the IED
4. Compare the measured operating current with the set value.
6.4.5.2 Completing the test

Continue to test another function or end the testing by setting the parameter *TestMode* to *Disabled* under **Main menu/Tests/IED test mode/TESTMODE:1*. If another function is tested, then set the parameter *Blocked* to *No* under **Main menu/Tests/Function test modes/Current/EFPIOC(50N,IN>>)/EFPIOC:1* for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter *Blocked* to *Yes*, for each individual function that has been tested.

6.4.6 Four step residual overcurrent protection, zero or negative sequence direction EF4PTOC (51N/67N)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for EF4PTOC (51N67N) are available on the local HMI under **Main menu/Tests/Function status/Current/EF4PTOC(51N67N,4IN>)/EF4PTOC:X*. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.4.6.1 Four step directional residual overcurrent protection

1. Connect the test set for single current injection to the appropriate IED terminals. Connect the injection current and voltage to terminals A and neutral.
2. Set the injected polarizing voltage slightly larger than the set minimum polarizing voltage (default 1% of Vn) and set the injection current to lag the voltage by an angle equal to the set reference characteristic angle (*AngleRCA*), if the forward directional function is selected.
   
   If reverse directional function is selected, set the injection current to lag the polarizing voltage by an angle equal to RCA+ 180°.
3. Increase the injected current and note the value at which the studied step of the function operates.
4. Decrease the current slowly and note the reset value.
5. If the test has been performed by injection of current in phase A, repeat the test, injecting current into terminals B and C with a polarizing voltage connected to terminals B, respectively C.
6. Block lower set steps when testing higher set steps according to the instructions that follow.
7. Connect a trip output contact to a timer.
8. Set the injected current to 200% of the operate level of the tested step, switch on the current and check the time delay.
For inverse time curves, check the operate time at a current equal to 110% of the 
operate current for \( tx_{Min} \).

9. Check that all trip and trip contacts operate according to the configuration (signal 
matrixes)

10. Reverse the direction of the injected current and check that the step does not operate.

11. Check that the protection does not operate when the polarizing voltage is zero.

12. Repeat the above described tests for the higher set steps.

13. Finally, check that pickup and trip information is stored in the event menu.

6.4.6.2 Four step non-directional residual overcurrent protection

1. Do as described in "Four step directional residual overcurrent protection", but 
without applying any polarizing voltage.

6.4.6.3 Completing the test

Continue to test another function or end the testing by setting the parameter \( TestMode \) to 
\( Disabled \) under Main menu/Tests/IED test mode/TESTMODE:1. If another function is 
tested, then set the parameter \( Blocked \) to \( No \) under Main menu/Tests/Function test 
modes/Current/EF4PTOC(51N67N,4IN>/)/EF4PTOC:X for the function, or for each 
individual function in a chain, to be tested next. Remember to set the parameter \( Blocked \) to 
\( Yes \), for each individual function that has been tested.

6.4.7 Sensitive directional residual overcurrent and power protection 
SDEPSDE (67N)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify 
settings".

Values of the logical signals for SDEPSDE (67N) are available on the local HMI under 
Main menu/Tests/Function status/Current/SDEPSDE(67N,IN<->)/SDEPSDE:1. 
The Signal Monitoring in PCM600 shows the same signals that are available on the local 
HMI.

6.4.7.1 Measuring the operate and time limit for set values

Operation mode \( 3I_0 \cdot \cos\phi \)

Procedure

1. Set the polarizing voltage to \( 1.2 \cdot VN_{Re}l_{PU} \) and the phase angle between voltage and 
current to the set characteristic angle (\( RCADir \)), the current lagging the voltage.
Take setting $RCAComp$ into consideration if not equal to 0.

2. Measure that the operate current of the set directional element is equal to the $INcosPhiPU$ setting.
   The I Dir ($I_0 \cos(\text{Angle})$) function activates the BFI_3P and STDIRIN output.

3. Measure with angles $\varphi = RCADir \pm 45^\circ$ that the measuring element operates when $I_0 \cos (RCADir - \varphi) = I_0 \cos(+/-45) = INcosPhiPU$.

4. Compare the result with the set value.
   Take the set characteristic into consideration, see figure 17 and figure 18.

5. Measure the operate time of the timer by injecting a current two times the set $INcosPhiPU$ value and the polarizing voltage $1.2 \cdot VNRelPU$.

\[ T_{inv} = kSN \cdot Sref / 3I_{true} \cdot \cos(\varphi) \]  

(Equation 1)

6. Compare the result with the expected value.
   The expected value depends on whether definite or inverse time was selected.

7. Set the polarizing voltage to zero and increase until the boolean output signal VNREL is activated, which is visible in the Application Configuration in PCM600 when the IED is in online mode. Compare the voltage with the set value $VNRelPU$.

8. Continue to test another function or complete the test by setting the test mode to Disabled.
Figure 17: Characteristic with ROAdir restriction
Operation mode $3I_0 \cdot 3V_0 \cdot \cos \varphi$

1. Set the polarizing voltage to $1.2 \cdot VN_{RelPU}$ and the phase angle between voltage and current to the set characteristic angle ($RCADir$), the current lagging the voltage.
2. Measure that the operate power is equal to the $SN_{PU}$ setting for the set directional element.
   Note that for pick-up, both the injected current and voltage must be greater than the set values $IN_{RelPU}$ and $VN_{RelPU}$ respectively.
   The function activates the $BFI_{3P}$ and $STDIRIN$ outputs.
3. Measure with angles $\varphi = RCADir \pm 45^\circ$ that the measuring element operates when $3I_0 \cdot 3V_0 \cdot \cos (RCADir \cdot \varphi) = 3I_0 \cdot 3V_0 \cdot \cos(\pm 45) = SN_{PU}$.
4. Compare the result with the set value. Take the set characteristic into consideration, see figure 17 and figure 18.
5. Measure the operate time of the timer by injecting $1.2 \cdot VN_{RelPU}$ and a current to get two times the set $SN\_PU$ operate value.

$$T_{inv} = kSN \cdot Sref \div 3I_{\text{user}} \cdot 3V_{\text{user}} \cdot \cos(\varphi)$$

(Equation 2)

6. Compare the result with the expected value.
The expected value depends on whether definite or inverse time was selected.

7. Continue to test another function or complete the test by setting the test mode to Disabled.

**Operation mode 3I$_0$ and $\varphi$**

1. Set the polarizing voltage to $1.2 \cdot VN_{RelPU}$ and the phase angle between voltage and current to the set characteristic angle ($RCADir$), the current lagging the voltage.
2. Measure that the operate power is equal to the $IN_{RelPU}$ setting for the set directional element.

Note that for pickup, both the injected current and voltage must be greater than the set values $IN_{RelPU}$ and $VN_{RelPU}$ respectively.

The function activates the BFI_3P and STDIRIN output.

3. Measure with angles $\varphi$ around $RCADir \pm ROAdir$.
4. Compare the result with the set values, refer to figure 19 for example characteristic.
5. Measure the operate time of the timer by injecting a current to get two times the set $SN\_PU$ operate value.

$$T_{inv} = kSN \cdot Sref \div 3I_{\text{user}} \cdot 3V_{\text{user}} \cdot \cos(\varphi)$$

(Equation 3)

6. Compare the result with the expected value.
The expected value depends on whether definite or inverse time was selected.

7. Continue to test another function or complete the test by setting the test mode to Disabled.
Non-directional ground fault current protection

Procedure

1. Measure that the operate current is equal to the \( I_{\text{INNonDirPU}} \) setting. The function activates the BFI_3P and STDIRIN output.
2. Measure the operate time of the timer by injecting a current of 200% of the operate value.
3. Compare the result with the expected value. The expected value depends on whether definite time \( t_{\text{INNonDir}} \) or inverse time was selected.
4. Continue to test another function or complete the test by setting the test mode to Disabled.

Residual overvoltage release and protection

Procedure

1. Measure that the operate voltage is equal to the \( V_{\text{N_PU}} \) setting. The function activates the BFI_3P and STUN signals.
2. Measure the operate time by injecting a voltage 1.2 timers set \( V_{\text{N_PU}} \) operate value.
3. Compare the result with the set \( t_{\text{VN}} \) operate value.
4. Inject a voltage $0.8 \cdot V_{NRelPU}$ and a current high enough to operate the directional function at the chosen angle.
5. Increase the voltage until the directional function is released.
6. Compare the measured value with the set $V_{NRelPU}$ operate value.

6.4.7.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/SDEPSDE(67N,IN<->)/SDEPSDE:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.4.8 Thermal overload protection, one time constant, Fahrenheit/ Celsius LFPTTR/LCPTTR (26)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for LFPTTR/LCPTTR (26) are available on the local HMI under , Main menu/Tests/Function status/Current/LFPTTR(26,T>)/LFPTTR:1, Main menu/Tests/Function status/Current/LCPTTR(26,T>)/LCPTTR:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

Check that the input logical signal BLOCK is logical zero and that on the local HMI, the logical signal TRIP, PICKUP and ALARM are equal to logical zero.

6.4.8.1 Testing the protection without external temperature compensation (NonComp)

1. Quickly set the measured current (fault current) in one phase to about 300% of $I_{Ref}$ (to minimise the trip time), and switch the current off.
2. Reset the thermal memory on the local HMI under Main menu/Clear/Clear temperature constant/LFPTTR(26,8>)/LFPTTR:1, Main menu/Clear/Clear temperature constant/LCPTTR(26,8>)/LCPTTR:1
3. Switch the fault current on and take note of the temperature, available on the local HMI under Main menu/Tests/Function status/Current/LFPTTR(26,8>)/LFPTTR:1/Outputs/TEMP, Main menu/Tests/Function status/Current/LCPTTR(26,8>)/LCPTTR:1/Outputs/TEMP
4. Check the time until the alarm limit has reached the AlarmTemp level during injection.
Monitor the signal ALARM until it appears on the corresponding binary output or on the local HMI.
5. Compare the measured temperature with the setting.
6. Measure the LFPTTR/LCPTTR (26) protection trip time.
   Use the TRIP signal from the configured binary output to stop the timer.
7. Take the TEMP readings.
   Compare with the setting of TripTemp.
8. Activate the BLOCK binary input.
   The signals ALARM, RI and TRIP should disappear.
9. Reset the BLOCK binary input.
10. Check the reset limit (TdReset).
    Monitor the signal PICKUP until it disappears on the corresponding binary output or on the local HMI, take the TEMP readings and compare with the setting of RecTemp.
11. Compare the measured trip time with the setting according to the formula.
12. Reset the thermal memory.
13. Continue to test another function or end the test by changing the test mode setting to Disabled.

6.4.8.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/LFPTTR(26,T>)/LFPTTR:1, Main menu/Tests/Function test modes/Current/LCPTTR(26,T>)/LCPTTR:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.4.9 Breaker failure protection, phase segregated activation and output CCRBRF (50BF)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for CCRBRF (50BF) are available on the local HMI under Main menu/Tests/Function status/Current/CCRBRF(50BF)/CCRBRF:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The Breaker failure protection, 3-phase activation and output function CCRBRF (50BF) should normally be tested in conjunction with some other function that provides an initiate signal. An external INITIATE signal can also be used.
To verify the settings in the most common back-up trip mode 1 out of 3, it is sufficient to test phase-to-ground faults.

At mode 2 out of 4 the phase current setting, Pickup_PH can be checked by single-phase injection where the return current is connected to the summated current input. The value of residual (ground fault) current IN set lower than Pickup_PH is easiest checked in back-up trip mode 1 out of 4.

6.4.9.1 Checking the phase current operate value, Pickup_PH

Check the current level IP> where setting FunctionMode=Current and setting BuTripMode=1 out of 3 or 2 out of 4 as set under Main menu/Settings/IED Settings/Current/CCRBRF(50BF)/CCRBRF:1.

1. Apply the fault condition, including INITIATION of CCRBRF (50BF), with a current below set Pickup_PH.
2. Repeat the fault condition and increase the current in steps until a trip occurs.
3. Compare the result with the set Pickup_PH.
4. Disconnect AC and INITIATE input signals.

Note! If NoIPickupcheck or Retrip off is set, only back-up trip can be used to check set Pickup_PH.

6.4.9.2 Checking the residual (ground fault) current operate value Pickup_N set below Pickup_PH

Check the low set Pickup_N current where setting FunctionMode = Current and setting BuTripMode = 1 out of 4 as set under Main menu/Settings/IED Settings/Current/CCRBRF(50BF)/CCRBRF:1.

1. Apply the fault condition, including INITIATION of CCRBRF (50BF), with a current just below set IN>Pickup_N.
2. Repeat the fault condition and increase the current in steps until trip appears.
3. Compare the result with the set Pickup_N.
4. Disconnect AC and INITIATE input signals.

6.4.9.3 Checking the re-trip and back-up times

The check of the set times can be made in connection with the check of operate values above.
Choose the applicable function and trip mode, such as FunctionMode = Current and setting RetripMode = No CBPos. Check as set under Main menu/Settings/IED Settings/Current/CCRBRF(50BF)/CCRBRF:1.

1. Apply the fault condition, including initiation of CCRBRF (50BF), well above the set current value. Measure time from INITIATION of CCRBRF (50BF).
2. Check the re-trip $t_l$ and back-up trip times $t_2$.
3. Disconnect AC and INITIATE input signals.

### 6.4.9.4 Verifying the re-trip mode

Choose the mode below, which corresponds to the actual case.

In the cases below it is assumed that FunctionMode = Current as set under Main menu/Settings/IED Settings/Current/CCRBRF(50BF)/CCRBRF:1.

#### Checking the case without re-trip, RetripMode = Retrip Off

1. Set RetripMode = Retrip Off.
2. Apply the fault condition, including initiation of CCRBRF (50BF), well above the set current value.
3. Verify that no re-trip, but back-up trip is achieved after set time.
4. Disconnect AC and INITIATE input signals.

#### Checking the re-trip with current check, RetripMode = CB Pos Check

1. Set RetripMode = CB Pos Check.
2. Apply the fault condition, including initiation of CCRBRF (50BF), well above the set current value.
3. Verify that re-trip is achieved after set time $t_l$ and back-up trip after time $t_2$
4. Apply the fault condition, including initiation of CCRBRF (50BF), with current below set current value.
5. Verify that no re-trip, and no back-up trip is obtained.
6. Disconnect AC and INITIATE input signals.

#### Checking re-trip without current check, RetripMode = No CBPos Check

1. Set RetripMode = No CBPos Check.
2. Apply the fault condition, including initiation of CCRBRF (50BF), without any current.
3. Verify that re-trip is achieved after set time $t_l$, and back-up trip after time $t_2$. 
4. Apply the fault condition, including initiation of CCRBRF (50BF), with current below set current value.
5. Verify that re-trip is achieved after set time \( t_1 \), but no back-up trip is obtained.
6. Disconnect AC and INITIATE input signals.

6.4.9.5 Verifying the back-up trip mode

In the cases below it is assumed that \( FunctionMode = Current \) is selected.

Checking that back-up tripping is not achieved at normal CB tripping

Use the actual tripping modes. The case below applies to re-trip with current check.

1. Apply the fault condition, including initiation of CCRBRF (50BF), with phase current well above set value \( IP \).
2. Interrupt the current, with a margin before back-up trip time, \( t_2 \). It may be made at issue of re-trip command.
3. Check that re-trip is achieved, if selected, but no back-up trip is obtained.
4. Disconnect AC and INITIATE input signals.

The normal mode \( BuTripMode = 1 \ out \ of \ 3 \) should have been verified in the tests above. In applicable cases the modes \( 1 \ out \ of \ 4 \) and \( 2 \ out \ of \ 4 \) can be checked. Choose the mode below, which corresponds to the actual case.

Checking the case \( BuTripMode = 1 \ out \ of \ 4 \)

It is assumed that the ground-fault current setting \( Pickup_N \) is below phase current setting \( Pickup_PH \).

1. Set \( BuTripMode = 1 \ out \ of \ 4 \).
2. Apply the fault condition, including initiation of CCRBRF (50BF), with one-phase current below set \( Pickup_PH \) but above \( Pickup_N \). The residual ground-fault should then be above set \( Pickup_N \).
3. Verify that back-up trip is achieved after set time. If selected, re-trip should also appear.
4. Disconnect AC and INITIATE input signals.

Checking the case \( BuTripMode = 2 \ out \ of \ 4 \)

The ground-fault current setting \( Pickup_N \) may be equal to or below phase-current setting \( Pickup_PH \).
1. Set \textit{BuTripMode} = 2 out of 4.
2. Apply the fault condition, including initiation of CCRBRF (50BF), with one-phase current above set \textit{Pickup\_PH} and residual (ground fault) above set \textit{Pickup\_N}.
3. Verify that back-up trip is achieved after set time. If selected, re-trip should also appear.
4. Apply the fault condition, including initiation of CCRBRF (50BF), with at least one-phase current below set \textit{Pickup\_PH} and residual (ground fault) above set \textit{Pickup\_N}. The current may be arranged by feeding three- (or two-) phase currents with equal phase angle (I0-component) below \textit{Pickup\_PH}, but of such value that the residual (ground fault) current \((3I_0)\) will be above set value \textit{Pickup\_N}.
5. Verify that back-up trip is not achieved.
6. Disconnect AC and INITIATE input signals.

6.4.9.6 Verifying the case \textit{RetripMode} = \textit{Contact}

It is assumed that re-trip without current check is selected, \textit{RetripMode} = \textit{Contact}.

1. Set \textit{FunctionMode} = \textit{Contact}
2. Apply input signal for CB closed to input 52a\_A (B or C).
3. Apply input signal, for initiation of CCRBRF (50BF).
4. Verify that phase selection re-trip and back-up trip are achieved after set times.
5. Disconnect the trip signal. Keep the CB closed signal.
6. Apply input signal, for initiation of CCRBRF (50BF).
7. Arrange disconnection of CB closed signal well before set back-up trip time \(t2\).
8. Verify that back-up trip is not achieved.
9. Disconnect injected AC and INITIATE input signals.

6.4.9.7 Verifying the function mode \textit{Current\&Contact}

To be made only when \textit{FunctionMode} = \textit{Current\&Contact} is selected.

Checking the case with fault current above set value \textit{Pickup\_PH}

The operation shall be as in \textit{FunctionMode} = \textit{Current}.

1. Set \textit{FunctionMode} = \textit{Current\&Contact}.
2. Leave the inputs for CB close inactivated. These signals should not influence.
3. Apply the fault condition, including initiation of CCRBRF (50BF), with current above the set \textit{Pickup\_PH} value.
4. Check that the re-trip, if selected, and back-up trip commands are achieved.
5. Disconnect injected AC and INITIATE input signals.
Checking the case with fault current below set value *Pickup_BlkCont*

The case shall simulate a case where the fault current is very low and operation will depend on CB position signal from CB auxiliary contact. It is suggested that re-trip without current check is used, setting *RetripMode = No CBPos Check*.

1. Set *FunctionMode = Current&Contact*.
2. Apply input signal for CB closed to relevant input or inputs 52a_A (B or C)
3. Apply the fault condition with input signal(s) for initiation of CCRBRF (50BF). The value of current should be below the set value *Pickup_BlkCont*
4. Verify that phase selection re-trip (if selected) and back-up trip are achieved after set times. Failure to trip is simulated by keeping the signal(s) CB closed activated.
5. Disconnect the AC and the INITIATE signal(s). Keep the CB closed signal(s).
6. Apply the fault and the initiation again. The value of current should be below the set value *Pickup_BlkCont*.
7. Arrange disconnection of BC closed signal(s) well before set back-up trip time t2. It simulates a correct CB tripping.
8. Verify that back-up trip is not achieved. Re-trip can appear for example, due to selection “Re-trip without current check”.
9. Disconnect injected AC and INITIATE input signals.

### 6.4.9.8 Completing the test

Continue to test another function or end the testing by setting the parameter *TestMode* to *Disabled* under *Main menu/Tests/IED test mode/TESTMODE:1*. If another function is tested, then set the parameter *Blocked* to *No* under *Main menu/Tests/Function test modes/Current/CCRBRF(50BF)/CCRBRF:X* for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter *Blocked* to *Yes*, for each individual function that has been tested.

### 6.4.10 Breaker failure protection, phase segregated activation and output CSPRBRF (50BF)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for CSPRBRF (50BF) are available on the local HMI under *Main menu/Tests/Function status/Current/CSPRBRF(50BF)/CSPRBRF:1*. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

Breaker failure protection, phase segregated activation and output CSPRBRF (50BF) should normally be tested in conjunction with some other function that provides an initiate signal. An external INITATE signal can also be used.
To verify the settings in the most common back-up trip mode 1 out of 3 it is sufficient to test phase-to-ground-faults.

At mode 2 out of 4 the Phase current setting, Pickup_{PH} can be checked by single phase injection where the return current is connected to the summed current input. The value of residual (EF) current IN set lower than Pickup_{PH} is most easily checked in backup trip mode 1 out of 4.

6.4.10.1 Checking the phase current operate value, Pickup_{PH}

Check the current level \( IP \) where setting FunctionMode = Current and setting BuTripMode = 1 out of 3 or 2 out of 4 as set under Main menu/Settings/IED Settings/Current/CSPRBRF(50BF)/CSPRBRF:1.

1. Apply the fault condition, including INITIATION of CSPRBRF (50BF), with a current below set Pickup_{PH}.
2. Repeat the fault condition and increase the current in steps until a trip occurs.
3. Compare the result with the set Pickup_{PH}.
4. Disconnect AC and INITIATE input signals.

If “No IPickup check” or “Retrip off” is set, only back-up trip can be used to check set Pickup_{PH}.

6.4.10.2 Checking the residual (GF) current operate value \( IN > \) set below \( IP > \)

Check the low set \( IN > \) current where setting FunctionMode = Current and setting BuTripMode = 1 out of 4 as set under Main menu/Settings/IED Settings/Current/CSPRBRF(50BF)/CSPRBRF:1.

1. Apply the fault condition, including initiation of CSPRBRF 50BF, with a current just below set Pickup_{N}.
2. Repeat the fault condition and increase the current in steps until trip appears.
3. Compare the result with the set Pickup_{N}.
4. Disconnect AC and initiation input signals.

6.4.10.3 Checking the re-trip and back-up times

The check of the set times can be made in connection with the check of operate values above. Choose the applicable function and trip mode, such as FunctionMode = Current and setting RetripMode = No CBPos Check as set under Main menu/Settings/IED Settings/CSPRBRF(50BF)/Current/CSPRBRF:1.
1. Apply the fault condition, including initiation of CSPRBRF (50BF), well above the set current value. Measure time from initiation of CSPRBRF (50BF).
2. Check the re-trip $t_1$ and back-up trip times $t_2$.
3. Disconnect AC and initiate input signals.

### 6.4.10.4 Verifying the **RetripMode**

1. Choose the mode below, which corresponds to the actual case. In the cases below it is assumed that $FunctionMode = \text{Current}$ as set under **Main menu/Settings/IED Settings/Current/CSPRBRF(50BF)/CSPRBRF:1**
2. Continue with the cases shown below.

#### Checking the re-trip with current check, **RetripMode = CB Pos Check**

1. Set $RetripMode = CB \text{ Pos Check}$ check.
2. Apply the fault condition, including initiation of CSPRBRF (50BF), well above the set current value.
3. Verify that retrip is achieved after set time $t_1$ and back-up trip after time $t_2$
4. Apply the fault condition, including initiation of CSPRBRF (50BF), with current below set current value.
5. Verify that no re-trip, and no back-up trip is obtained.
6. Disconnect AC and initiate input signals.

#### Checking the case without re-trip, **RetripMode = Retrip Off**

1. Set $RetripMode = \text{Retrip Off}$.
2. Apply the fault condition, including initiation of CSPRBRF (50BF), well above the set current value.
3. Verify that no re-trip, but back-up trip is achieved after set time.
4. Disconnect AC and initiate input signals.

#### Checking re-trip without current check, **RetripMode = No CBPos Check**

1. Set $RetripMode = \text{No CBPos Check}$.
2. Apply the fault condition, including initiation of CSPRBRF (50BF), well above the set current value.
3. Verify that re-trip is achieved after set time $t_1$, and back-up trip after time $t_2$.
4. Apply the fault condition, including initiation of CSPRBRF (50BF), with current below set current value.
5. Verify that re-trip is achieved after set time $t_1$, but no back-up trip is obtained.
6. Disconnect AC and initiate input signals.
6.4.10.5 Verifying the case \textit{RetripMode} = \textit{No CB Pos Check}

It is assumed that re-trip without current check is selected, \textit{RetripMode} = \textit{No CB Pos Check}.

1. Set \textit{FunctionMode} = \textit{Contact}.
2. Apply input signal for CB closed to input CBCLD.
3. Apply input signal, for initiation of CSPRBRF (50BF).
4. Verify that re-trip and back-up trip are achieved after set times.
5. Disconnect the initiate signal. Keep the CB closed signal.
6. Apply input signal, for initiating of CSPRBRF (50BF).
7. Arrange disconnection of CB closed signal well before set back-up trip time \( t_2 \).
8. Verify that back-up trip is not achieved.
9. Disconnect injected AC and initiate input signals.

6.4.10.6 Verifying the function mode \textit{Current} & \textit{Contact}

- To be made only when \textit{FunctionMode} = \textit{Current} & \textit{Contact} is selected.
- Checking the case with fault current above set value \textit{Pickup PH}.
- The operation shall be as in \textit{FunctionMode} = \textit{Current} & \textit{Contact}.

1. Set \textit{FunctionMode} = \textit{Current} & \textit{Contact}.
2. Leave the inputs for CB close inactivated. These signals should not influence.
3. Apply the fault condition, including initiation of CSPRBRF (50BF), with current above the set \textit{Pickup PH} value.
4. Check that the re-trip, if selected, and back-up trip commands are achieved.
5. Disconnect injected AC and initiate input signals.

6.4.10.7 Checking the case with fault current below set value \textit{Pickup BlkCont}

The case shall simulate a case where the fault current is very low and operation will depend on CB position signal from CB auxiliary contact. It is suggested that retrip without current check is used; setting \textit{RetripMode} = \textit{No CBPos Check}.

1. Set \textit{FunctionMode} = \textit{Current} & \textit{Contact} check.
2. Apply input signal for CB closed to relevant input or inputs BFI_A, BFI_B, or BFI_C
3. Apply the fault condition with input signal(s) for initiation of CSPRBRF (50BF). The value of current should be below the set value \textit{Pickup BlkCont}.
4. Verify that phase selection re-trip (if selected) and back-up trip are achieved after set times. Failure to trip is simulated by keeping the signal(s) CB closed activated.
5. Disconnect the AC and the initiation signal(s). Keep the CB closed signal(s).
6. Apply the fault and the initiate again. The value of current should be below the set value \textit{Pickup\_BlkCont}.
7. Arrange disconnection of BC closed signal(s) well before set back-up trip time \(t_2\). It simulates a correct CB tripping.
8. Verify that back-up trip is not achieved. Re-trip can appear for example, due to selection "Re-trip without current check".
9. Disconnect injected AC and initiation of input signals.

### 6.4.10.8 Checking the phase current operate value, \textit{Pickup\_PH}

Check the low set \textit{Pickup\_PH} current where setting \textit{FunctionMode} = \textit{Current} and setting \textit{BuTripMode} = 1 out of 3 or 2 out of 4 as set under \textit{Main menu/Settings/IED Settings/Current/CSPRBRF(50BF)/CSPRBRF:1}.

1. Apply the fault condition, including pickup of CSPRBRP (50BF), with a current just below set \textit{Pickup\_PH}.
2. Repeat the fault condition and increase the current in steps until trip appears.
3. Compare the result with the set \textit{Pickup\_PH}.
4. Disconnect AC and pickup input signals.

\begin{itemize}
  \item If \textit{NoPickupcheck} or \textit{Retrip off} is set, only back-up trip can be used to check set \textit{Pickup\_PH}.
\end{itemize}

### 6.4.10.9 Completing the test

Continue to test another function or end the testing by setting the parameter \textit{TestMode} to \textit{Disabled} under \textit{Main menu/Tests/IED test mode/TESTMODE:1}. If another function is tested, then set the parameter \textit{Blocked} to \textit{No} under \textit{Main menu/Tests/Function test modes/Current/CSPRBRF(50BF)/CSPRBRF:1} for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter \textit{Blocked} to \textit{Yes}, for each individual function that has been tested.

### 6.4.11 Stub protection STBPTOC (50STB)

Prepare the IED for verification of settings as outlined in \textit{5.1 "Preparing the IED to verify settings"}.

Logical signals for STBPTOC (50STB) protection are available on the local HMI under \textit{Main menu/Tests/Function status/Current/STBPTOC(50STB)/STBPTOC:1/Inputs or Outputs}.
Values of the logical signals for STBPTOC (50STB) are available on the local HMI under Main menu/Tests/Function status/Current/STBPTOC(50STB,I>)/STBPTOC:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.4.11.1 Measuring the operate limit of set values

1. Check that the input logical signals BLOCK and ENABLE and the output logical signal TRIP are all logical zero.
2. Activate the input ENABLE on the STBPTOC (50STB) function block
3. For a short while inject a current (fault current) in one phase to about 110% of the set operating current, and switch the current off. Observe to not exceed the maximum permitted overloading of the current circuits in the IED.
4. Switch the fault current on and measure the operating time of STBPTOC (50STB). Use the TRIP signal from the configured binary output to stop the timer. The operation should be instantaneously.
5. Activate the input BLOCK on the STBPTOC (50STB) function block.
6. Switch on the fault current (110% of the setting). No TRIP signal should appear.
7. Switch off the fault current.
8. For a short while inject a current (fault current) in same phase to about 90% of the set operating current, and switch the current off.
9. Switch the fault current on. No TRIP signal should appear.
10. Switch off the fault current.
11. Reset the ENABLE binary input.
12. Switch the fault current on. No TRIP signal should appear.
13. Disable the fault current.

6.4.11.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/STBPTOC(50STB,I>)/STBPTOC:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.
6.4.12 Pole discrepancy protection CCRPLD (52PD)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for CCRPLD (52PD) are available on the local HMI under Main menu/Tests/Function status/Current/CCRPLD(52PD)/CCRPLD:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.4.12.1 Verifying the settings

1. When CCRPLD (52PD) is set for external, set setting ContSel to Enable under Main menu/Settings/IED Settings/Current/CCRPLD/CCRPLD:1 to activate the logic that detects pole discordance when external pole discordance signaling is used (input EXTPDIND) in the application configuration.
2. Activate the input EXTPDIND on CCRPLD (52PD) function block, and measure the operating time of CCRPLD (52PD).
3. Compare the measured time with the set value tTrip.
4. Reset the EXTPDIND input.
5. When CCRPLD (52PD) is set for unsymmetrical current detection with CB monitoring, set setting CurrSel under Main menu/Settings/IED Settings/Current/CCRPLD/CCRPLD:1 to Enable. Use the TRIP signal from the configured binary output to stop the timer.
6. Repeat point 4 and 5 using OPENCMD instead of CLOSECMD. Set all three currents to 110% of CurrRelLevel. Activate CLOSECMD. NO TRIP signal should appear due to symmetrical condition.

6.4.12.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/CCRPLD(52PD)/CCRPLD:X for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.4.13 Broken conductor check BRCPTOC (46)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".
Values of the logical signals for BRCPTOC (46) are available on the local HMI under Main menu/Tests/Function status/Current/BRCPTOC(46,lub)/BRCPTOC:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

### 6.4.13.1 Measuring the operate and time limit of set values

1. Check that the input logical signal BLOCK to the BRCPTOC (46) function block is logical zero and note on the local HMI that the output signal TRIP from the BRCPTOC (46) function block is equal to the logical 0.
2. Set the measured current (fault current) in one phase to about 110% of the set operating current $IP_>$.
   Observe to not exceed the maximum permitted overloading of the current circuits in the terminal.
3. Switch on the fault current and measure the operating time of BRCPTOC (46). TRIP is controlled by Gate 13 in the configuration.
   Use the TRIP signal from the configured binary output to stop the timer.
4. Compare the measured time with the set value $t_{Oper}$.
5. Activate the BLOCK binary input.
6. Switch on the fault current (110% of the setting) and wait longer than the set value $t_{Oper}$.
   No TRIP signal should appear.
7. Switch off the fault current.
8. Set the measured current (fault current) in same phase to about 90% of the set operating current $IP_>$. Switch off the current.
9. Switch on the fault current and wait longer than the set value $t_{Oper}$.
   No TRIP signal should appear.
10. Switch off the fault current.

### 6.4.13.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/BRCPTOC(46,lub)/BRCPTOC:X for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

### 6.4.14 Directional underpower protection GUPPDUP (37)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".
Values of the logical signals for GUPPDUP (37) are available on the local HMI under **Main menu/Tests/Function status/Current/GUPPDUP(37,P<)/GUPPDUP:1**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

### 6.4.14.1 Verifying the settings

The underpower protection shall be set to values according to the real set values to be used.

The test is made by means of injection of voltage and current where the amplitude of both current and voltage and the phase angle between the voltage and current can be controlled. During the test, the analog outputs of active and reactive power shall be monitored.

1. Connect the test set for injection of voltage and current corresponding to the mode to be used in the application. If a three-phase test set is available this could be used for all the modes. If a single-phase current/voltage test set is available the test set should be connected to a selected input for one-phase current and voltage. Use the formulas stated in Table 9 for the different calculation modes used. The set mode **Mode** can be found on the local HMI under **Main menu/Settings/IED Settings/Current/GUPPDUP(37,P<)/GUPPDUP:1/General**.

<table>
<thead>
<tr>
<th>Set value: Mode</th>
<th>Formula used for complex power calculation</th>
</tr>
</thead>
<tbody>
<tr>
<td>A, B, C</td>
<td>[ \overline{S} = \overline{V_A} \cdot I_A^\ast + \overline{V_B} \cdot I_B^\ast + \overline{V_C} \cdot I_C^\ast ] (Equation 4)</td>
</tr>
<tr>
<td>Arone</td>
<td>[ \overline{S} = \overline{V_{AB}} \cdot I_A^\ast - \overline{V_{BC}} \cdot I_C^\ast ] (Equation 5)</td>
</tr>
<tr>
<td>PosSeq</td>
<td>[ \overline{S} = 3 \cdot \overline{V_{PosSeq}} \cdot I_{PosSeq}^\ast ] (Equation 6)</td>
</tr>
<tr>
<td>AB</td>
<td>[ \overline{S} = \overline{V_{AB}} \cdot (I_A^\ast - I_B^\ast) ] (Equation 7)</td>
</tr>
<tr>
<td>BC</td>
<td>[ \overline{S} = \overline{V_{BC}} \cdot (I_B^\ast - I_C^\ast) ] (Equation 8)</td>
</tr>
</tbody>
</table>

Table continues on next page
### Set value: Mode

<table>
<thead>
<tr>
<th>Formula used for complex power calculation</th>
</tr>
</thead>
<tbody>
<tr>
<td>( S = V_{CA} \cdot (I_{C}^* - I_{A}^*) )</td>
</tr>
<tr>
<td>(Equation 9)</td>
</tr>
<tr>
<td>( S = 3 \cdot V_{A} \cdot I_{A}^* )</td>
</tr>
<tr>
<td>(Equation 10)</td>
</tr>
<tr>
<td>( S = 3 \cdot V_{B} \cdot I_{B}^* )</td>
</tr>
<tr>
<td>(Equation 11)</td>
</tr>
<tr>
<td>( S = 3 \cdot V_{C} \cdot I_{C}^* )</td>
</tr>
<tr>
<td>(Equation 12)</td>
</tr>
</tbody>
</table>

2. Adjust the injected current and voltage to the set values in % of \( I_{Base} \) and \( V_{Base} \) (converted to secondary current and voltage). The angle between the injected current and voltage shall be set equal to the set direction \( \text{Angle1} \), angle for stage 1 (equal to 0° for low forward power protection and equal to 180° for reverse power protection). Check that the monitored active power is equal to 100% of rated power and that the reactive power is equal to 0% of rated power.

3. Change the angle between the injected current and voltage to \( \text{Angle1} + 90° \). Check that the monitored active power is equal to 0% of rated power and that the reactive power is equal to 100% of rated power.

4. Change the angle between the injected current and voltage back to 0°. Decrease the current slowly until the PICKUP1 signal, pickup of stage 1, is activated.

5. Increase the current to 100% of \( I_{Base} \).

6. Switch the current off and measure the time for activation of TRIP1, trip of stage 1.

7. If a second stage is used, repeat steps 2 to 6 for the second stage.

### 6.4.14.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Current/GUPPDUP(37,P<)/GUPPDUP:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.
6.4.15 Directional overpower protection GOPPDOP (32)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for GOPPDOP (32) are available on the local HMI under Main menu/Tests/Function status/Current/GOPPDOP(32,P>/GOPPDOP:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.4.15.1 Verifying the settings

The overpower protection shall be set to values according to the real set values to be used. The test is made by means of injection of voltage and current where the amplitude of both current and voltage and the phase angle between the voltage and current can be controlled. During the test the analog outputs of active and reactive power shall be monitored.

1. Connect the test set for injection of voltage and current corresponding to the mode to be used in the application. If a three phase test set is available this could be used for all the modes. If a single phase current/voltage test set is available the test set should be connected to a selected input for one phase current and voltage. Use the formulas stated in Table 9 for the different calculation modes used. The set mode Mode can be found under Main menu/Settings/IED Settings/Current/GOPPDOP(32,P>/GOPPDOP:1/General.

2. Adjust the injected current and voltage to the set rated values in % of IBase and VBase (converted to secondary current and voltage). The angle between the injected current and voltage shall be set equal to the set direction Angle1, angle for stage 1 (equal to 0° for low forward power protection and equal to 180° for reverse power protection). Check that the monitored active power is equal to 100% of rated power and that the reactive power is equal to 0% of rated power.

3. Change the angle between the injected current and voltage to Angle1 + 90°. Check that the monitored active power is equal to 0% of rated power and that the reactive power is equal to 100% of rated power.

4. Change the angle between the injected current and voltage back to Angle1 value. Increase the current slowly from 0 until the PICKUP1 signal, pickup of stage 1, is activated. Check the injected power and compare it to the set value Power1, power setting for stage 1 in % of Sbase.

5. Increase the current to 100% of IBase and switch the current off.

6. Switch the current on and measure the time for activation of TRIP1, trip of stage 1.

7. If a second stage is used, repeat steps 2 to 6 for the second stage.

6.4.15.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is
tested, then set the parameter **Blocked** to **No** under **Main menu/Tests/Function test modes/Current/GOPPDOP(32,P>)/GOPPDOP:X** for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter **Blocked** to **Yes**, for each individual function that has been tested.

## 6.5 Testing voltage protection functions

### 6.5.1 Two step undervoltage protection UV2PTUV (27)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for UV2PTUV (27) are available on the local HMI under **Main menu/Tests/Function status/Voltage/UV2PTUV(27,2U<)/UV2PTUV:1**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

### 6.5.1.1 Verifying the setting

**Verification of PICKUP value and time delay to operate for Step 1**

1. Check that the IED settings are appropriate, especially the PICKUP value, the definite time delay and the **1 out of 3** operation mode.
2. Supply the IED with three-phase voltages at their rated values.
3. Slowly decrease the voltage in one of the phases, until the PICKUP signal appears.
4. Note the operate value and compare it with the set value.

The operate value in secondary volts is calculated according to the following equations:

For phase-to-ground measurement:

\[
V_{\text{pickup}} < \frac{V_{\text{Base}} \times VT_{\text{sec}}}{100 \times \sqrt{3} \times VT_{\text{prim}}}
\]

(Equation 13)

For phase-to-phase measurement:

\[
V_{\text{pickup}} < \frac{V_{\text{Base}} \times VT_{\text{sec}}}{100 \times VT_{\text{prim}}}
\]

(Equation 14)

5. Increase the measured voltage to rated load conditions.
6. Check that the PICKUP signal resets.
7. Instantaneously decrease the voltage in one phase to a value about 20% lower than the measured operate value.
8. Measure the time delay for the TRIP signal, and compare it with the set value.
9. Check the inverse time delay by injecting a voltage corresponding to $0.8 \times V_{\text{pickup}}$.

For example, if the inverse time curve A is selected, the trip signals TRST1 and TRIP operate after a time corresponding to the equation:

$$t(s) = \frac{TD1}{\frac{V}{1 - \frac{V}{V_{\text{pickup}}}}}$$

(Equation 15)

where:
- $t(s)$: Operate time in seconds
- TD1: Settable time multiplier of the function for step 1
- $V$: Measured voltage
- $V_{\text{pickup}}$: Set pickup voltage for step 1

For example, if the measured voltage jumps from the rated value to 0.8 times the set pickup voltage level and time multiplier TD1 is set to 0.05 s (default value), then the TRST1 and TRIP signals operate at a time equal to 0.250 s ± tolerance.

10. The test above can be repeated to check the inverse time characteristic at different voltage levels.
11. Repeat the above-described steps for step 2.

**Extended testing**

1. The tests above can be repeated for 2 out of 3 and for 3 out of 3 operation mode.

**6.5.1.2 Completing the test**

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Voltage/UV2PTUV(27,2U<)/UV2PTUV:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.
6.5.2 Two step overvoltage protection OV2PTOV (59)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for OV2PTOV (59) are available on the local HMI under Main menu/Tests/Function status/Voltage/OV2PTOV(59,2U>/OV2PTOV:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.5.2.1 Verification of single-phase voltage and time delay to operate for Step 1

1. Apply single-phase voltage below the set value $\text{Pickup1}$.
2. Slowly increase the voltage until the PU_ST1 signal appears.
3. Note the operate value and compare it with the set value.
   
   ![](image)
   
   The operate value in secondary volts is calculated according to the following equations:

For phase-to-ground measurement:

$$\frac{V_{\text{pickup}}}{100} > \frac{V_{\text{Base}} \times VT_{\text{sec}}}{\sqrt{3} \times VT_{\text{prim}}}$$

(Equation 16)

For phase-to-phase measurement:

$$\frac{V_{\text{pickup}}}{100} > \frac{V_{\text{Base}} \times VT_{\text{sec}}}{VT_{\text{prim}}}$$

(Equation 17)

4. Decrease the voltage slowly and note the reset value.
5. Set and apply about 20% higher voltage than the measured operate value for one phase.
6. Measure the time delay for the TRST1 signal and compare it with the set value.
7. Check the inverse time delay by injecting a voltage corresponding to $1.2 \times V_{\text{pickup}}$.
   
   ![](image)
   
   For example, if the inverse time curve A is selected, the trip signals TRST1 and TRIP operate after a time corresponding to the equation:

$$t(s) = \left(\frac{TD1}{V_{\text{pickup}}} - 1\right)$$

(Equation 18)
where:

<table>
<thead>
<tr>
<th>Symbol</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>t(s)</td>
<td>Operate time in seconds</td>
</tr>
<tr>
<td>TD1</td>
<td>Settable time multiplier of the function for step 1</td>
</tr>
<tr>
<td>V</td>
<td>Measured voltage</td>
</tr>
<tr>
<td>Vpickup&gt;</td>
<td>Set pickup voltage for step 1</td>
</tr>
</tbody>
</table>

For example, if the measured voltage jumps from 0 to 1.2 times the set start voltage level and time multiplier TD1 is set to 0.05 s (default value), then the TRST1 and TRIP signals operate at a time equal to 0.250 s ± tolerance.

8. The test above can be repeated to check the inverse time characteristic at different voltage levels.

9. Repeat the above-described steps for step 2.

### 6.5.2.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Voltage/OV2PTOV(59,2U>)/OV2PTOV:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

### 6.5.3 Two step residual overvoltage protection ROV2PTOV (59N)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ROV2PTOV (59N) are available on the local HMI under Main menu/Tests/Function status/Voltage/ROV2PTOV(59N,2UN>)/ROV2PTOV:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

### 6.5.3.1 Verifying the settings

1. Apply the single-phase voltage either to a single-phase voltage input or to a residual voltage input with the pickup value below the set value Pickup1.
2. Slowly increase the value until PU_ST1 appears.
3. Note the operate value and compare it with the set value.
4. Decrease the voltage slowly and note the reset value.
5. Set and apply about 20% higher voltage than the measured operate value for one phase.
6. Measure the time delay for the TRST1 signal and compare it with the set value.
7. Check the inverse time delay by injecting a voltage corresponding to $1.2 \times V_{\text{pickup}}$.

For example, if the inverse time curve A is selected, the trip signals TRST1 and TRIP operate after a time corresponding to the equation:

$$t(s) = \frac{TD1 \times V}{V_{\text{pickup}}} - 1 \text{ seconds}$$

(Equation 19)

where:
- $t(s)$: Operate time in seconds
- $TD1$: Settable time multiplier of the function for step 1
- $V$: Measured voltage
- $V_{\text{pickup}}$: Set pickup voltage for step 1

For example, if the measured voltage jumps from 0 to 1.2 times the set pickup voltage level and time multiplier $TD1$ is set to 0.05 s (default value), then the TRST1 and TRIP signals operate at a time equal to 0.250 s ± tolerance.

8. Repeat the test for step 2.

### 6.5.3.2 Completing the test

Continue to test another function or end the testing by setting the parameter `TestMode` to `Disabled` under `Main menu/Tests/IED test mode/TESTMODE:1`. If another function is tested, then set the parameter `Blocked` to `No` under `Main menu/Tests/Function test modes/Voltage/ROV2PTOV(59N,2UN>/ROV2PTOV:1` for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter `Blocked` to `Yes`, for each individual function that has been tested.

### 6.5.4 Loss of voltage check LOVPTUV (27)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".
Values of the logical signals for LOVPTUV (27) are available on the local HMI under Main menu/Tests/Function status/Voltage/LOVPTUV(27,U<)/LOVPTUV:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.5.4.1 Measuring the operate limit of set values

1. Check that the input logical signals BLOCK, CBOPEN and BLKU are logical zero.
2. Supply a three-phase rated voltage in all three phases and note on the local HMI that the TRIP logical signal is equal to the logical 0.
3. Switch off the voltage in all three phases.
   After set \( t_{\text{Trip}} \) time a TRIP signal appears on the corresponding binary output or on the local HMI.
   Note that TRIP at this time is a pulse signal, duration should be according to set \( t_{\text{Pulse}} \).
4. Inject the measured voltages at rated values for at least set \( t_{\text{Restore}} \) time.
5. Activate the CBOPEN binary input.
6. Simultaneously disconnect all the three-phase voltages from the IED.
   No TRIP signal should appear.
7. Inject the measured voltages at rated values for at least set \( t_{\text{Restore}} \) time.
8. Activate the BLKU binary input.
9. Simultaneously disconnect all the three-phase voltages from the IED.
   No TRIP signal should appear.
10. Reset the BLKU binary input.
11. Inject the measured voltages at rated values for at least set \( t_{\text{Restore}} \) time.
12. Activate the BLOCK binary input.
13. Simultaneously disconnect all the three-phase voltages from the IED.
   No TRIP signal should appear.
14. Reset the BLOCK binary input.

6.5.4.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Voltage/LOVPTUV(27,U<)/LOVPTUV:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.
6.6 Testig frequency protection functions

6.6.1 Underfrequency protection SAPTUF (81)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for SAPTUF (81) are available on the local HMI under Main menu/Tests/Function status/Frequency/SAPTUF(81,f<)/SAPTUF:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.6.1.1 Verifying the settings

Verification of PICKUP value and time delay to operate

1. Check that the IED settings are appropriate, for example the pickup value and the time delay.
2. Supply the IED with three-phase voltages at their rated values and initial frequency. The initial frequency is calculated using Equation 20.

\[
\text{StartFrequency} + 0.02 + \text{floor}\left[\frac{f_r - \text{StartFrequency}}{0.04}\right] \times 0.04
\]

(Equation 20)

3. Slowly decrease the voltage frequency by steps of 40 mHz until the PICKUP signal appears; during each step apply the voltage signal for a time that is either at least 10% longer than \((t_{Delay}+100 \text{ ms})\) or a suitable time to monitor the function.
4. Note the frequency value at which the PICKUP signal appears and compare it with the set value \(\text{StartFrequency}\).
5. Increase the frequency until its rated value is reached.
6. Check that the PICKUP signal resets.
7. Supply the IED with three-phase voltages at their rated values and frequency 20 mHz over the set value \(\text{StartFrequency}\).
8. Decrease the frequency with a 40 mHz step, applying it for a time that is at least 10% longer than \((t_{Delay}+100 \text{ ms})\).
9. Measure the time delay of the \(TRIP\) signal, and compare it with the set value \(t_{Delay}\). Note that the measured time consists of the set value of the time delay plus the minimum trip time of the function (80 - 90 ms).

Extended testing

[1] \(\text{floor}[x]\) is the largest integer less than or equal to \(x\)
1. Check that the IED settings are appropriate, for example the pickup value and the time delay.
2. Supply the IED with three-phase voltages at their rated values and frequency 20 mHz under the set value \(\text{StartFrequency}\), applying it for a time that is at least 10% longer than \((t\text{Delay}+100 \text{ ms})\).
3. Verify that the TRIP signal is active.
4. Increase the frequency with a 40 mHz step, applying it until the TRIP signal resets.
5. Measure the reset time of the \(\text{TRIP}\) signal, and compare it with the technical data of the function.

**Verification of the low voltage magnitude blocking**

1. Check that the IED settings are appropriate, especially the \(\text{PUFrequency}\) and the \(t\text{Delay}\) in SAPTUF, and the \(\text{GlobalBaseSel}\) and the \(\text{MinValFreqMeas}\) in the SMAI preprocessing function.
2. Supply the IED with three-phase voltages at rated values.
3. Slowly decrease the magnitude of the applied voltage until the \(\text{BLKDMAGN}\) signal appears.
4. Note the voltage magnitude value and compare it with the value \(\text{MinValFreqMeas} \times \text{UBase} / 100\).
   Where:
   - \(\text{MinValFreqMeas}\) is a set value of the SMAI.
   - \(\text{UBase}\) is the value in the GBASVAL group identified by the setting \(\text{GlobalBaseSel}\).
5. Slowly decrease the frequency of the applied voltage, to a value below \(\text{PUFrequency}\) as explained in Section "Verification of PICKUP value and time delay to operate".
6. Check that the PICKUP signal does not appear.
7. Wait for a time corresponding to \((t\text{Delay}+100 \text{ ms})\), and check that the TRIP signal does not appear.
8. Slowly increase the magnitude of the applied voltages until the \(\text{BLKDMAGN}\) signal resets.
9. Verify that the signal \(\text{PICKUP}\) appears and wait for a time at least equal to \((t\text{Delay}+100 \text{ ms})\) to verify that also the signal TRIP becomes active.

**6.6.1.2 Completing the test**

Continue to test another function or end the testing by setting the parameter \(\text{TestMode}\) to \(\text{Disabled}\) under \text{Main menu/Tests/IED test mode/TESTMODE:1}. If another function is tested, then set the parameter \(\text{Blocked}\) to \(\text{No}\) under \text{Main menu/Tests/Function test modes/Frequency/SAPTUF(81,f<)/SAPTUF:X} for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter \(\text{Blocked}\) to \(\text{Yes}\), for each individual function that has been tested.
6.6.2 Overfrequency protection SAPTOF (81)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for SAPTOF (81) are available on the local HMI under Main menu/Tests/Function status/Frequency/SAPTOF(81,f>)/SAPTOF:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.6.2.1 Verifying the settings

Verification of PICKUP value and time delay to operate

1. Check that the IED settings are appropriate, for example the pickup value and the time delay.
2. Supply the IED with three-phase voltages at their rated values and initial frequency. The initial frequency is calculated using Equation 21.

\[
\text{StartFrequency} - 0.02 - \text{floor}\left[f, - \text{StartFrequency}\right]/0.04 \times 0.04
\]

(Equation 21)

3. Slowly increase the voltage frequency by steps of 40 mHz until the PICKUP signal appears; during each step apply the voltage signal for a time that is either at least 10% longer than \((t\text{Delay} + 100 \text{ ms})\) or a suitable time to monitor the function.
4. Note the frequency value at which the PICKUP signal appears and compare it with the set value \(\text{StartFrequency}\).
5. Decrease the frequency until its rated value is reached.
6. Check that the PICKUP signal resets.
7. Supply the IED with three-phase voltages at their rated values and frequency 20 mHz under the set value \(\text{StartFrequency}\).
8. Increase the frequency with a 40 mHz step, applying it for a time that is at least 10% longer than \((t\text{Delay} + 100 \text{ ms})\).
9. Measure the time delay of the TRIP signal, and compare it with the set value \(t\text{Delay}\). Note that the measured time consists of the set value of the time delay plus the minimum trip time of the function (80 - 90 ms).

Extended testing

[2] \(\text{floor}[x]\) is the largest integer less than or equal to \(x\)
1. Check that the IED settings are appropriate, for example the pickup value and the time delay.

2. Supply the IED with three-phase voltages at their rated values and frequency 20 mHz over the set value StartFrequency, applying it for a time that is at least 10\% longer than (tDelay+100 ms).

3. Verify that the TRIP signal is active.

4. Decrease the frequency with a 40 mHz step, applying it until the TRIP signal resets.

5. Measure the reset time of the TRIP signal, and compare it with the technical data of the function.

Verification of the low voltage magnitude blocking

1. Check that the IED settings are appropriate, especially the PUFrequency and the tDelay in SAPTOF, and the GlobalBaseSel and the MinValFreqMeas in the SMAI preprocessing function.

2. Supply the IED with three-phase voltages at rated values.

3. Slowly decrease the magnitude of the applied voltage until the BLKDMAGN signal appears.

4. Note the voltage magnitude value and compare it with the value MinValFreqMeas x UBase / 100.

Where:

- MinValFreqMeas is a set value of the SMAI.
- UBase is the value in the GBASVAL group identified by the setting GlobalBaseSel.

5. Slowly increase the frequency of the applied voltage, to a value above PUFrequency as explained in Section Verification of START value and time delay to operate.

6. Check that the PICKUP signal does not appear.

7. Wait for a time corresponding to (tDelay+100 ms), and check that the TRIP signal does not appear.

8. Slowly increase the magnitude of the applied voltages until the BLKDMAGN signal resets.

9. Verify that the signal PICKUP appears and wait for a time at least equal to (tDelay +100 ms) to verify that also the signal TRIP becomes active.

Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Frequency/SAPTOF(81,f>)/SAPTOF:X for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.
6.6.3 Rate-of-change frequency protection SAPFRC (81)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for SAPFRC (81) are available on the local HMI under Main menu/Tests/Function status/Frequency/SAPFRC(81,df/dt)/SAPFRC:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

6.6.3.1 Verifying the settings

PICKUP value and time delay to operate

1. Check that the appropriate settings are available in the IED, especially the PICKUP value and the definite time delay. Set PickupFreqgrad, to a rather small negative value.
2. Supply the IED with three-phase voltages at their rated values.
3. Slowly decrease the frequency of the applied voltage, with an increasing rate-of-change that finally exceeds the setting of PickupFreqgrad, and check that the PICKUP signal appears.
4. Note the operate value and compare it with the set value.
5. Increase the frequency to rated operating conditions, and zero rate-of-change.
6. Check that the PICKUP signal resets.
7. Instantaneously decrease the frequency of the applied voltage to a value about 20% lower than the nominal value.
8. Measure the time delay for the TRIP signal, and compare it with the set value.

Extended testing

1. The test above can be repeated to check a positive setting of PickupFreqGrad.
2. The tests above can be repeated to test the RESTORE signal, when the frequency recovers from a low value.

6.6.3.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Frequency/SAPFRC(81,df/dt)/SAPFRC:X for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.
6.7 Testing secondary system supervision functions

6.7.1 Current circuit supervision CCSRDIF (87)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for CCSRDIF (87) are available on the local HMI under Main menu/Tests/Function status/Secondary system supervision/CCSRDIF(87,INd)/CCSRDIF:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The Current circuit supervision function CCSRDIF (87) is conveniently tested with the same three-phase test set as used when testing the measuring functions in the IED.

The condition for this procedure is that the setting of *IMinOp* is lower than the setting of *Pickup_Block*.

6.7.1.1 Verifying the settings

1. Check the input circuits and the operate value of the *IMinOp* current level detector by injecting current, one phase at a time.
2. Check the phase current blocking function for all three phases by injecting current, one phase at a time. The output signals shall reset with a delay of 1 second when the current exceeds $1.5 \cdot I_{Base}$.
3. Inject a current $0.1 \cdot I_{Base}$ to the reference current input IREFSMPL.
4. Increase slowly the current in one of the phases current input and check that FAIL output is obtained when the current is about $0.9 \cdot I_{Base}$.

6.7.1.2 Completing the test

Continue to test another function or end the testing by setting the parameter *TestMode* to *Disabled* under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter *Blocked* to *No* under Main menu/Tests/Function test modes/Secondary system supervision/CCSRDIF(87,INd)/CCSRDIF:X for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter *Blocked* to *Yes*, for each individual function that has been tested.

6.7.2 Fuse failure supervision SDDRFUF

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".
Values of the logical signals for SDDRFUF are available on the local HMI under **Main menu/Tests/Function status/Secondary system supervision/SDDRFUF/SDDRFUF**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The verification is divided in two main parts. The first part is common to all fuse failure supervision options, and checks that binary inputs and outputs operate as expected according to actual configuration. In the second part the relevant set operate values are measured.

### 6.7.2.1 Checking that the binary inputs and outputs operate as expected

1. Simulate normal operating conditions with the three-phase currents in phase with their corresponding phase voltages and with all of them equal to their rated values.
2. Connect the nominal dc voltage to the 89bS binary input.
   - The signal BLKV should appear with almost no time delay.
   - No signals BLKZ and 3PH should appear on the IED.
   - Only the distance protection function can operate.
   - Undervoltage-dependent functions must not operate.
3. Disconnect the dc voltage from the 89b binary input terminal.
4. Connect the nominal dc voltage to the MCBOP binary input.
   - The BLKV and BLKZ signals should appear without any time delay.
   - All undervoltage-dependent functions must be blocked.
5. Disconnect the dc voltage from the MCBOP binary input terminal.
6. Disconnect one of the phase voltages and observe the logical output signals on the binary outputs of the IED.
   - BLKV and BLKZ signals should appear simultaneously whether the BLKV and BLKZ reset depends on the setting *SealIn* “on” or “off”. If “on” no reset, if “off” reset.
7. After more than 5 seconds disconnect the remaining two-phase voltages and all three currents.
   - There should be no change in the high status of the output signals BLKV and BLKZ.
   - The signal 3PH will appear.
8. Establish normal voltage and current operating conditions simultaneously and observe the corresponding output signals.
   - They should change to logical 0 as follows:
     - Signal 3PH after about 25ms
     - Signal BLKV after about 50ms
     - Signal BLKZ after about 200ms
6.7.2.2 Measuring the operate value for the negative sequence function

1. Simulate normal operating conditions with the three-phase currents in phase with their corresponding phase voltages and with all of them equal to their rated values.
2. Slowly decrease the measured voltage in one phase until the BLKV signal appears.
3. Record the measured voltage and calculate the corresponding negative-sequence voltage according to the equation.

Observe that the voltages in the equation are phasors.

\[ 3 \cdot V_2 = V_A + a^2 \cdot V_B + a \cdot V_C \]

(Equation 22)

Where:

\[ V_A, V_B, \text{and } V_C = \text{the measured phase voltages} \]

\[ a = 1 \cdot e^{j\frac{2\pi}{3}} = -0.5 + j\frac{\sqrt{3}}{2} \]

4. Compare the result with the set value (consider that the set value 3V2PU is in percentage of the base voltage VBase) of the negative-sequence operating voltage.
5. Repeat steps 1 and 2. Then slowly increase the measured current in one phase until the BLKV signal disappears.
6. Record the measured current and calculate the corresponding negative-sequence current according to the equation.

Observe that the currents in the equation are phasors.

\[ 3 \cdot I_2 = I_A + a^2 \cdot I_B + a \cdot I_C \]

(Equation 25)

Where:

\[ I_A, I_B, \text{and } I_C = \text{the measured phase currents} \]

\[ a = 1 \cdot e^{j\frac{2\pi}{3}} = -0.5 + j\frac{\sqrt{3}}{2} \]

7. Compare the result with the set value of the negative-sequence operating current. Consider that the set value 3I2< is in percentage of the base current IBase.

6.7.2.3 Measuring the operate value for the zero-sequence function

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1. Simulate normal operating conditions with the three-phase currents in phase with their corresponding phase voltages and with all of them equal to their rated values.

2. Slowly decrease the measured voltage in one phase until the BLKV signal appears.

3. Record the measured voltage and calculate the corresponding zero-sequence voltage according to the equation. Observe that the voltages in the equation are phasors.

\[ 3 \cdot V_0 = V_A + V_B + V_C \]  
(Equation 28)

Where:
\[ V_A, V_B \text{ and } V_C \text{ = the measured phase voltages} \]

4. Compare the result with the set value (consider that the set value \(3V0\)Pickup is in percentage of the base voltage of the zero-sequence operating voltage.

5. Repeat steps 1 and 2. Then slowly increase the measured current in one phase until the BLKV signal disappears.

6. Record the measured current and calculate the corresponding zero-sequence current according to the equation. Observe that the currents in the equation are phasors.

\[ 3 \cdot I_0 = I_A + I_B + I_C \]  
(Equation 30)

Where:
\[ I_A, I_B \text{ and } I_C \text{ = the measured phase currents} \]

7. Compare the result with the set value of the zero-sequence operating current. Consider that the set value \(3I0\) is in percentage of the base current \(I_{Base}\).

6.7.2.4 Checking the operation of the dv/dt and di/dt based function

1. Simulate normal operating conditions with the three-phase currents in phase with their corresponding phase voltages and with all of them equal to their rated values.

2. Change the voltages and currents in all three phases simultaneously. The voltage change must be greater than the set value for \(DVPU\) and the current change must be less than the set value for \(DIPU\).
• The BLKV and BLKZ signals appear without any time delay. The BLKZ signal will be activated only if the internal deadline detection is not activated at the same time.

• 3PH should appear after 5 seconds, if the remaining voltage levels are lower than the set $VDLDPU$ of the DLD function.

3. Apply normal conditions as in step 1. The BLKV, BLKZ and 3PH signals should reset, if activated, see step 1 and 2.

4. Change the voltages and currents in all three phases simultaneously. The voltage change must be greater than the set value for $DVPU$ and the current change must be more than the set value for $DIPU$. The BLKV, BLKZ and 3PH signals should not appear.

5. Repeat step 2.

6. Connect the nominal voltages in all three phases and feed a current below the operate level in all three phases.

7. Keep the current constant. Disconnect the voltage in all three phases simultaneously.

8. Change the magnitude of the voltage and current for phase 1 to a value greater than the set value for $DVPU$ and $DIPU$.

9. Check that the pickup output signals STDVA and STDIA and the general pickup signals STDV or STDI are activated.

10. Check that the pickup output signals for the current and voltage phases 2 and 3 are activated by changing the magnitude of the voltage and current for phases 2 and 3.

6.7.2.5 Completing the test

Continue to test another function or end the testing by setting the parameter $TestMode$ to $Disabled$ under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter $Blocked$ to $No$ under Main menu/Tests/Function test modes/Secondary system supervision/SDDRFUF/SDDRFUF:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter $Blocked$ to $Yes$, for each individual function that has been tested.

6.8 Testing control functions

During periods of frequent counter state/value changes, if the auxiliary power to the IED is interrupted, it is possible that this information will be lost.

6.8.1 Synchrocheck, energizing check, and synchronizing SESRSYN (25)
This section contains instructions on how to test the synchrocheck synchronization check, energizing check, and synchronizing function SESRSYN (25) for single, double and breaker-and-a-half arrangements.

This section contains instructions on how to test the synchrocheck synchronization check and energizing check for single CB with or without the synchronizing function.

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for SESRSYN (25) are available on the local HMI under Main menu/Tests/Function status/Control/SESRSYN(25,SYNC)/SESRSYN:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

At commissioning and periodical checks, the functions shall be tested with the used settings. To test a specific function, it might be necessary to change some setting parameters, for example:

- **AutoEnerg** = Disabled/DLLB/DBLL/Both
- **ManEnerg** = Disabled
- **Operation** = Disabled/Enabled
- Activation of the voltage selection function if applicable

The tests explained in the test procedures below describe the settings, which can be used as references during testing before the final settings are specified. After testing, restore the equipment to the normal or desired settings.

A secondary injection test set with the possibility to alter the phase angle and amplitude of the voltage is needed. The test set must also be able to generate different frequencies on different outputs.

The description below applies for a system with a nominal frequency of 50 Hz but can be directly applicable to 60 Hz. SESRSYN (25) can be set to use different phases, phase to ground or phase to phase. Use the set voltages instead of what is indicated below.

Figure 20 shows the general test connection principle, which can be used during testing. This description describes the test of the version intended for one bay.

Figure 21 shows the general test connection for a breaker-and-a-half diameter with one-phase voltage connected to the line side.
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Figure 20: General test connection with three-phase voltage connected to the line side
6.8.1.1 Testing the synchronizing function

This section is applicable only if the synchronizing function is included.

The voltage inputs used are:

- **V-Line**: VA, VB or VC line 1 voltage inputs on the IED
- **V-Bus**: Bus voltage input on the IED

**Testing the frequency difference**

The frequency difference is in the example set at 0.20 Hz on the local HMI, and the test should verify that operation is achieved when the $FreqDiffMax$ frequency difference is lower than 0.20 Hz. The test procedure below will depend on the settings used. Input STARTSYN must be activated during the test.

1. Apply voltages
1.1. V-Line = 100% GlblBaseSelLine and f-Line = 50.0 Hz
1.2. V-Bus = 100% GlblBaseSelBus and f-Bus = 50.2 Hz

2. Check that a closing pulse is submitted at a closing angle less than 2 degrees from phase equality. Modern test sets will evaluate this automatically.

3. Repeat with
   3.1. V-Bus = 80% GlblBaseSelBus and f-Bus = 50.25 Hz, to verify that the function does not operate when frequency difference is above limit.

4. Repeat with different frequency differences for example, 100 mHz with f-Bus nominal and line leading and for example 20 mHz (or just above FreqDiffMin) to verify that independent of frequency difference the closing pulse occurs within 2 degrees.

5. Verify that the closing command is not issued when the frequency difference is less than the set value FreqDiffMin.

6.8.1.2 Testing the synchrocheck check

During the test of SESRSYN (25) for a single bay arrangement, these voltage inputs are used:

- V-Line: VA, VB or VC line 1 voltage inputs on the IED
- V-Bus: Bus voltage input on the IED

Testing the voltage selection for single 1/2 CB arrangements

At test of the SESRSYN (25) function for a breaker-and-a-half diameter the following alternative voltage inputs can be used for the three SESRSYN (SESRSYN 1, SESRSYN 2, SESRSYN 3) functions. These three SESRSYN functions can either be in one, two or three different IEDs. Table 10 describes the scenario when SESRSYN 1, SESRSYN 2 and SESRSYN 3 all are in the same IED. If SESRSYN 3 is in another IED, Bus1 will be considered as Bus2 and Line2 as Line1. The voltage is selected by activation of different inputs in the voltage selection logic as shown in table 10 and figure 22.

<table>
<thead>
<tr>
<th>SESRSYN</th>
<th>CBConfig setting</th>
<th>Section to be synchroniz ed</th>
<th>Activated B1QCLD input on IED from</th>
<th>Activated B2QCLD input on IED from</th>
<th>Activated LN1QCLD input on IED from</th>
<th>Activated LN2QCLD input on IED from</th>
<th>Indication from SESRSYN on IED</th>
</tr>
</thead>
<tbody>
<tr>
<td>SESRSYN 1</td>
<td>breaker-and-a-half bus CB</td>
<td>Bus1 – Line1</td>
<td></td>
<td>LN1 989</td>
<td></td>
<td></td>
<td>B1SEL, LN1SEL</td>
</tr>
<tr>
<td>(Operates on CB1 52)</td>
<td></td>
<td>Bus1 – Line2</td>
<td>CB2 252</td>
<td></td>
<td>LN2 989</td>
<td></td>
<td>B1SEL, LN2SEL</td>
</tr>
<tr>
<td></td>
<td></td>
<td>Bus1 – Bus2</td>
<td>CB2 252</td>
<td>CB3 352</td>
<td></td>
<td></td>
<td>B1SEL, B2SEL</td>
</tr>
</tbody>
</table>

Table 10: Voltage selection logic

Table continues on next page
### Objects used in the voltage selection logic

<table>
<thead>
<tr>
<th>SESRSYN</th>
<th>CBConfig setting</th>
<th>Section to be synchronized</th>
<th>Activated B1QCLD input on IED from</th>
<th>Activated B2QCLD input on IED from</th>
<th>Activated LN1QCLD input on IED from</th>
<th>Activated LN2QCLD input on IED from</th>
<th>Indication from SESRSYN on IED</th>
</tr>
</thead>
<tbody>
<tr>
<td>SESRSYN 2 (Operates on CB2 252)</td>
<td>Tie CB</td>
<td>Line1 – Line2</td>
<td>CB1 52</td>
<td>LN1 989</td>
<td>LN2 989</td>
<td>B1SEL, LN2SEL</td>
<td>B1SEL, LN2SEL</td>
</tr>
<tr>
<td></td>
<td></td>
<td>Bus1 – Line2</td>
<td>CB2 252</td>
<td>LN1 989</td>
<td>LN2 989</td>
<td>B2SEL, LN1SEL</td>
<td></td>
</tr>
<tr>
<td></td>
<td></td>
<td>Bus2 – Line1</td>
<td>CB3 52</td>
<td>LN1 989</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td></td>
<td>Bus1 – Bus2</td>
<td>CB1 52</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>SESRSYN 3 (Operates on CB3 352)</td>
<td>breaker-and-a-half bus alt. CB (mirrored)</td>
<td>Bus2 – Line2</td>
<td>CB2 252</td>
<td>LN1 989</td>
<td>LN2 989</td>
<td>B2SEL, LN1SEL</td>
<td></td>
</tr>
<tr>
<td></td>
<td></td>
<td>Bus2 – Line1</td>
<td>CB3 52</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td></td>
<td>Bus2 – Bus1</td>
<td>CB2 252</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td></td>
<td></td>
<td>Bus1 – Bus2</td>
<td>CB1 52</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

**Figure 22:** Objects used in the voltage selection logic
Testing the voltage difference
Set the voltage difference to 0.15 p.u. on the local HMI, and the test should check that operation is achieved when the voltage difference $VDiffSC$ is lower than 0.15 p.u.

The settings used in the test shall be final settings. The test shall be adapted to site setting values instead of values in the example below.

Test with no voltage difference between the inputs.

Test with a voltage difference higher than the set $VDiffSC$.

1. Apply voltages V-Line (for example) = 80% $GblBaseSelLine$ and V-Bus = 80% $GblBaseSelBus$
2. Check that the AUTOSYOK and MANSYOK outputs are activated.
3. The test can be repeated with different voltage values to verify that the function operates within the set $VDiffSC$. Check with both V-Line and V-Bus respectively lower than the other.
4. Increase the V-Bus to 110% $GblBaseSelBus$, and the V-Line = 90% $GblBaseSelLine$ and also the opposite condition.
5. Check that the two outputs for manual and auto synchronism are not activated.

Testing the phase angle difference
The phase angle differences $PhaseDiffM$ and $PhaseDiffA$ respectively are set to their final settings and the test should verify that operation is achieved when the phase angle difference is lower than this value both leading and lagging.

Test with no voltage difference.

1. Apply voltages V-Line (for example) = 100% $GblBaseSelLine$ and V-Bus = 100% $GblBaseSelBus$, with a phase difference equal to 0 degrees and a frequency difference lower than $FreqDiffA$ and $FreqDiffM$.
2. Check that the AUTOSYOK and MANSYOK outputs are activated.
   The test can be repeated with other phase difference values to verify that the function operates for values lower than the set ones, $PhaseDiffM$ and $PhaseDiffA$. By changing the phase angle on the voltage connected to V-Bus, between $\pm \delta \phi$ degrees, the user can check that the two outputs are activated for a phase difference lower than the set value. It should not operate for other values. See figure 23.
3. Change the phase angle between +dφ and -dφ and verify that the two outputs are activated for phase differences between these values but not for phase differences outside, see figure 23.

Testing the frequency difference

The frequency difference test should verify that operation is achieved when the FreqDiffA and FreqDiffM frequency difference is lower than the set value for manual and auto synchronizing check, FreqDiffA and FreqDiffM respectively and that operation is blocked when the frequency difference is greater.

Test with frequency difference = 0 mHz

Test with a frequency difference outside the set limits for manual and auto synchronizing check respectively.

1. Apply voltages V-Line equal to 100% GblBaseSelLine and V-Bus equal to 100% GblBaseSelBus, with a frequency difference equal to 0 mHz and a phase difference lower than the set value.
2. Check that the AUTOSYOK and MANSYOK outputs are activated.
3. Apply voltage to the V-Line equal to 100% GblBaseSelLine with a frequency equal to 50 Hz and voltage V-Bus equal to 100% GblBaseSelBus, with a frequency outside the set limit.
4. Check that the two outputs are not activated. The test can be repeated with different frequency values to verify that the function operates for values lower than the set ones. If a modern test set is used, the frequency can be changed continuously.

Testing the reference voltage

1. Use the same basic test connection as in figure 20.
The voltage difference between the voltage connected to V-Bus and V-Line should be 0%, so that the AUTOSYOK and MANSYOK outputs are activated first.

2. Change the V-Line voltage connection to V-Line2 without changing the setting on the local HMI. Check that the two outputs are not activated.

### 6.8.1.3 Testing the energizing check

During the test of the energizing check function for a single bay arrangement, these voltage inputs are used:

<table>
<thead>
<tr>
<th>V-Line</th>
<th>VA, VB or VC line1 voltage inputs on the IED</th>
</tr>
</thead>
<tbody>
<tr>
<td>V-Bus</td>
<td>Bus voltage input on the IED</td>
</tr>
</tbody>
</table>

**General**

When testing the energizing check function for the applicable bus, arrangement shall be done for the energizing check functions. The voltage is selected by activation of different inputs in the voltage selection logic.

Live voltage level is fixed to 80% $U_{Base}$ and dead voltage level to fixed 40% $U_{Base}$.

The test shall be performed according to the settings for the station. Test the alternatives below that are applicable.

**Testing the dead line live bus (DLLB)**

The test should verify that the energizing check function operates for a low voltage on the V-Line and for a high voltage on the V-Bus. This corresponds to the energizing of a dead line to a live bus.

1. Apply a single-phase voltage 100% $GblBaseSelBus$ to the V-Bus, and a single-phase voltage 30% $GblBaseSelLine$ to the V-Line.
2. Check that the AUTOENOK and MANENOK outputs are activated after set $tAutoEnerg$ respectively $tManEnerg$.
3. Increase the V-Line to 60% $GblBaseSelLine$ and V-Bus to be equal to 100% $GblBaseSelBus$. The outputs should not be activated.
4. The test can be repeated with different values on the V-Bus and the V-Line.

**Testing the dead bus live line (DBLL)**

The test should verify that the energizing check function operates for a low voltage on the V-Bus and for a high voltage on the V-Line. This corresponds to an energizing of a dead bus to a live line.

1. Check the AUTOENOK and MANENOK outputs are activated after set $tAutoEnerg$ respectively $tManEnerg$.
2. Increase the V-Line to 60% $GblBaseSelLine$ and V-Bus to be equal to 100% $GblBaseSelBus$. The outputs should not be activated.
3. The test can be repeated with different values on the V-Bus and the V-Line.
1. Verify the settings AutoEnerg or ManEnerg to be DBLL.
2. Apply a single-phase voltage of 30% GblBaseSelBus to the V-Bus and a single-phase voltage of 100% GblBaseSelLine to the V-Line.
3. Check that the AUTOENOK and MANENOK outputs are activated after set tAutoEnerg respectively tManEnerg.
4. Decrease the V-Line to 60% GblBaseSelLine and keep the V-Bus equal to 30% GblBaseSelBus. The outputs should not be activated.
5. The test can be repeated with different values on the V-Bus and the V-Line.

Testing both directions (DLLB or DBLL)

1. Verify the local HMI settings AutoEnerg or ManEnerg to be Both.
2. Apply a single-phase voltage of 30% GblBaseSelLine to the V-Line and a single-phase voltage of 100% GblBaseSelBus to the V-Bus.
3. Check that the AUTOENOK and MANENOK outputs are activated after set tAutoEnerg respectively tManEnerg.
4. Change the connection so that the V-Line is equal to100% GblBaseSelLine and the V-Bus is equal to 30% GblBaseSelBus. The outputs should still be activated.
5. The test can be repeated with different values on the V-Bus and the V-Line.

Testing the dead bus dead line (DBDL)
The test should verify that the energizing check function operates for a low voltage on both the V-Bus and the V-Line, that is, closing of the breaker in a non-energized system. Test is valid only when this function is used.

1. Verify the local HMI setting AutoEnerg to be Disabled and ManEnerg to be DBLL.
2. Set the parameter ManEnergDBDL to Enabled.
3. Apply a single-phase voltage of 30% GblBaseSelBus to the V-Bus and a single-phase voltage of 30% GblBaseSelLine to the V-Line.
4. Check that the MANENOK output is activated after set tManEnerg.
5. Increase the V-Bus to 80% GblBaseSelBus and keep the V-Line equal to 30% GblBaseSelLine. The outputs should not be activated.
6. Repeat the test with ManEnerg set to DLLB with different values on the V-Bus and the V-Line voltage.

6.8.1.4 Testing the voltage selection

Testing the voltage selection for single CB arrangements
This test should verify that the correct voltage is selected for the measurement in the SESRSYN function used in a double-bus arrangement. Apply a single-phase voltage of
30% GblBaseSelLine to the V-Line and a single-phase voltage of 100% GblBaseSelBus to the V-Bus.

If the VB1OK or VB2OK inputs for the fuse failure are used, they must be activated, during tests below. Also verify that deactivation prevents operation and gives an alarm.

1. Connect the signals above to binary inputs and binary outputs.
2. Connect the voltage inputs to the analog inputs used for each bus or line depending of the type of busbar arrangement and verify that correct output signals are generated.

6.8.1.5 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Control/SESRSYN(25,SYNC)/SESRSYN:X for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.8.2 Autorecloser for 3-phase operation SMBRREC (79)

Verification of the Autorecloser for 3-phase operation function SMBRREC (79) for three-phase reclosing attempts can be considered to consist of two parts.

- One part to verify the internal logic and timing of the function
- One part to verify its interaction with the protection system

This section deals with verification of SMBRREC (79) itself. However, it is practical to initiate SMBRREC (79) by activating a protection function, for example, by secondary injection tests.

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for SMBRREC (79) are available on the local HMI under Main menu/Tests/Function status/Control/SMBRREC(79,0->1)/SMBRREC:X. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The purpose of verification before commissioning is to check that entered selections, setting parameters and configuration render the intended result. The function is flexible with many options and facilities. At commissioning only the selections and settings intended for use are verified. If one chooses to reduce some time settings in order to speed
up verification, be careful to set the parameters at intended operational values at the end of the verification procedure. One such parameter is the $t_{\text{Reset}}$ time that must be timed out before a new test sequence can be performed.

The verification test is performed together with protection and trip functions. Figure 24 illustrates a suggested testing arrangement, where the circuit-breaker (CB) is simulated by an external bi-stable relay (BR), for example a relay type RXMVB2 or RXMD or Breaker Simulator of ABB. The following manual switches are used:

- Switch or push-button to close (SC)
- Switch or push-button to trip (ST)
- Switch for CB ready condition (SRY)

If no bi-stable relay or breaker simulator is available, replace it with two self-reset auxiliary relays and use a self-holding connection.

Use a secondary injection IED test set to operate the protection function. The test set shall be switched off when a trip signal is given or when the BR comes to open position to simulate real conditions.

The CB simulation can be made more elaborate, including simulation of the operating gear condition, CBREADY of either the type ready for a Close-Open (CO) cycle, or the type ready for an Open-Close -Open (OCO) cycle.

The CB condition CBREADY of a type, CO, shall be high (true) until a closing operation is performed. It then goes low (false) for a recharging time of about 5 - 10s. After that it is high again.

A CB condition CBREADY of a type, OCO shall be high (true) before and during tripping (Initiate reclosing). During tripping it goes low for a recharging time, for example, 10s. It may thus be low at the instant of reclosing. After each Open or Close operation it may need a recharging period before it goes high again.

In the example of CB simulation arrangement, the CBREADY condition is simulated by a manual switch, SRY.

Information and material for the verification:

- Protection or control unit, IED, configured and with settings entered.
- Configuration diagram for the IED
- Terminal diagram for the IED, or plant circuit diagram including the IED
- Technical reference manual for the IED
- IED test set for secondary injection
- Means to indicate, measure and record operation and times, for example an event recording facility
A bi-stable relay (BR) or two auxiliary relays to simulate a CB
Two push-buttons (SC, ST) to operate the BR and a change-over switch (SRY) to simulate CBREADY
Possibly a switch simulation the synchronizing check SESRSYN (25) condition

Figure 24: Simulating the CB operation by a bi-stable relay/breaker simulator and manual switches

6.8.2.1 Preparation of the verification

1. Check the function settings on the local HMI under Main menu/Settings/IED Settings/Control/SMBRREC(79,0->1)/SMBRREC:1
   If any timer settings are reduced to speed up or facilitate the testing, they shall be set to normal after testing. A temporary label on the IED can be a reminder to restore normal settings after which a verification test should be performed.

2. Decide if a synchronizing check function SESRSYN (25) shall be included in the test.
If SESRSYN (25) as an internal function or external device is not operated by the injection, input signal SYNC must be connected as a permanent high signal or controlled by a switch.

3. Read and make notes of the reclosing operation counters on the local HMI under Main menu/Tests/Function status/Control/SMBRREC(79,0->1)/SMBRREC: 1
   Possibly reset the counters to Zero. Counters are reset in the reset menu.

4. Make arrangements for the simulation of the CB, for example as in figure 24.

5. Make arrangements for indication, recording and time measurements.
   The signals for, 52a, RI, CLOSECMD, READY and other relevant signals should preferably be arranged for event recording with time tagging. If that is not possible, other means of time measurement and recording should be arranged.

6.8.2.2 Switching the autorecloser for 3-phase operation function to Enabled and Disabled

1. Set the Operation setting to Disabled and check the state.
2. Set the Operation setting to Enabled and check the state, including SETON and READY.
   The CB should be closed and ready.
3. If external control Disabled/Enabled is connected, check that it works.
   Set Operation to ExternalCtrl and use that control to switch Enabled and Disabled, and check the state of the function.

6.8.2.3 Verifying the autorecloser for 3-phase operation function SMBRREC (79)

Select the test cases to be run according to what is applicable to the particular application. It can be, for example, three-phase single-shot reclosing or two-shot reclosing. Below, a case with three-phase single-shot reclosing is described.

1. Set Operation = Enabled.
2. If the autorecloser for 3-phase operation function SMBRREC(79) is not to be operated, ensure that the SMBRREC input is activated. If SMBRREC(79) is to be included, ensure that it is supplied with the appropriate AC quantities.
3. Simulate CB closed position by closing switch SC to make the BR relay pick-up.
4. Simulate CBREADY by closing the switch SRY, and leave it closed.
5. Inject AC quantities to give a trip to the BR and to the RI input.
   Observe and preferably record the operation. The BR relay shall trip and reclose (pick-up). After reclosing, the SRY switch can be opened for about 5s and then closed again.
   The autoreclosing open time and the sequence should be checked, for example in the event recording. Check also the operation indications (disturbance report) and the
operation counters on the local HMI under **Main menu/Tests/Function status/SMBRREC(79,0->1)/SMBRREC:1**

Should the operation not be as expected, this should be investigated. It could be caused by an inappropriate setting or missing condition such as CBREADY.

6. Repeat the sequence by simulating a permanent fault.

Shortly after the reclosing shot, a new fault is applied. If a single-shot reclosing program is selected, there shall be one reclosing operation and then blocking of SMBRREC (79) for the set Reset time.

Before a new reclosing sequence can be run, the CBREADY and 52a (CB closed) must be set manually.

### 6.8.2.4 Checking the reclosing conditions

When checking the influence of a releasing condition it is suggested to first run a sequence with the condition fulfilled. When the condition signal is removed, and a new sequence is run, it indicates that the result was due to the changed condition. In case of a blocking signal the procedure should be similar. Start without the blocking or inhibit signal, and then run a sequence with the blocking or inhibit signal added.

**Checking the influence of the INHIBIT signal**

1. Check that the autorecloser function SMBRREC (79) is operative, for example, by making a reclosing shot without the INHIBIT signal.
2. Apply a fault and thereby a RI signal. At the same time, or during the open time, apply a signal to the input INHIBIT.
3. Check that the reclosing sequence is interrupted and no reclosing takes place.

**Check closing onto a fault**

1. Check that the autorecloser function SMBRREC (79) is operative, for example by making a reclosing shot.
   - Keep the CBREADY signal high.
2. Set the breaker simulating relay BR in Open position.
3. Close the BR relay and apply immediately a fault and thereby a RI signal.
4. Check that no reclosing takes place.

**Checking the influence of CB not ready for reclosing**

1. Check that the autorecloser function SMBRREC (79) is operative, for example by making a reclosing shot.
   - Keep the CB simulator BR closed. Remove the CBREADY signal by opening SRY.
2. Apply a fault and thereby a RI signal.
3. Check that no reclosing takes place.
Checking the influence of synchronizing check (at three-pole reclosing)

1. Check that the autorecloser for 3-phase operation function SMBRREC (79) is operative, for example, by making a three-pole reclosing shot with the synchronizing check condition. Remove the SMBRREC (25) signal.
2. Apply a fault causing three-phase trip and thereby a RI signal.
3. Wait for the \( tSync \) time out limit. Check that no reclosing is made.

Restoring equipment

After the tests, restore the equipment to normal or desired state. Check the following items in particular:

1. Check the operation counters. Reset the counters to zero, if that is the user's preference. The counter reset function is found on the local HMI under Main menu/Clear/Clear counters/ SMBRREC(79,0->1)
2. Restore settings that may have been modified for the tests back to normal.
3. Disconnect the test switch, CB simulating arrangement and test circuits. Reconnect any links or connection terminals, which may have been opened for the tests.
4. Reset indications, alarms and disturbance recordings. Clearing of the disturbance report must be done via the Disturbance Handling in PCM600.

6.8.2.5 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Control/SMBRREC(79,0->1)/SMBRREC:X for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.8.3 Autorecloser for 1/3-phase operation STBRREC (79)

Verification of the automatic reclosing function STBRREC (79) for single and three-phase reclosing attempt, can be considered to consist of two parts; one part to verify the internal logic and timing of the function and one part to verify its interaction with the protection system. This section deals with verification of the auto-reclosing function itself. However, it is practical to start initiate the autoreclosing function by activating a protection function, for example, by secondary injection tests.
Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for STBRREC (79) are available on the local HMI under **Main menu/Tests/Function status/Control/STBRREC(79,0→1)/STBRREC:1**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The purpose of verification before commissioning is to check that entered selections, setting parameters and configuration render the intended result. The function is flexible with many options and facilities. At commissioning only the selections and settings intended for use are verified. If one chooses to reduce some time settings in order to speed up verification, be careful to set the parameters at intended operational values at the end of the verification procedure. One such parameter is the reclaim Reset time that must be timed out before a new test can be performed.

The verification test is performed together with protection and trip functions. Figure 25 illustrates a suggested testing arrangement, where the circuit-breaker (CB) is simulated by an external bi-stable relay (BR), for example a relay type RXMVB2 or RXMD or Breaker Simulator from ABB.
The following manual switches are used:

- Switch or push-button to close (SC)
- Switch or push-button to trip (ST)
- Switch for CB ready condition (SRY)

If no bi-stable relay or breaker simulator is available, replace it with two self-reset auxiliary relays and use a self-holding connection.
Use a secondary injection IED test set to operate the protection function. The test set shall be switched off when a trip signal is given or when the BR comes to open position to simulate real conditions.

The CB simulation can be made more elaborate, including simulation of the operating gear condition, CBREADY of either the type ready for a Close-Open (CO) cycle, or the type ready for an Open-Close -Open (OCO) cycle.

The CB condition CBREADY of a type, CO, shall be high (true) until a closing operation is performed. It then goes low (false) for a recharging time of about 5 -10 s. After that it is high again.

A CB condition CBREADY of a type, OCO shall be high (true) before and during tripping (Start Initiate reclosing). During tripping it goes low for a recharging time, for example, 10 s. It may thus be low at the instant of reclosing. After each Open or Close operation it may need a recharging period before it goes high again.

In the example of CB simulation arrangement, the CBREADY condition is simulated by a manual switch, SRY.

Information and material for the verification:

- Protection or control unit, Intelligent electronic device (IED), configured and with settings entered
- Configuration diagram for the IED
- Terminal diagram for the IED, or plant circuit diagram including the IED
- Technical reference manual for the IED
- IED test set for secondary injection
- Means to indicate, measure and record operation and times, e.g. an event recording facility
- A bi-stable relay (BR) or two auxiliary relays to simulate a CB
- Two push-buttons (SC, ST) to operate the BR and a change-over switch (SRY) to simulate CBREADY
- Possibly a switch simulation the Synchronism check SESRSYN (25) condition.

### 6.8.3.1 Preparation of the verification

1. Check the function settings. In the HMI tree they are found under Main menu/Settings/IED Settings/Control/STBRREC(79,0->1)/STBRREC:1
   If any timer settings are reduced to speed-up or facilitate the testing, they shall be set to normal after testing. A temporary label on the unit can be a reminder to restore normal settings after which a verification test should be performed.
2. Decide if a synchronization check (SYNC) shall be included in the test.
If SYNC as an internal function or external device is not operated by the injection, it may be connected as a permanent high signal or controlled by a switch.

3. Read and make notes of the reclosing operation counters. Local HMI tree **Main menu/Tests/Function status/Control/STBRREC(79,0->1)/STBRREC:1**
   Possibly reset the counters to zero. Counters are reset in the RESET menu. Make arrangements for the simulation of the CB, for example, as in figure 13.

4. Make arrangements for indication, recording and time measurements.

   The signals for Add 52A, PICKUP, CLOSECMD, READY and other relevant signals should preferably be arranged for event recording with time tagging. If that is not possible, other means of time measurement and recording should be arranged.

### 6.8.3.2 Switching the auto-reclosing function *Enabled* and *Disabled*

1. Set the **Operation** setting to *Disabled* and check the state.
2. Set the **Operation** setting to *Enabled* and check the state, including SETON and READY.
   The CB should be closed and ready.
3. If external control *Enabled/Disabled* is connected, check that it works.
4. Set **Operation** to *ExternalCtrl*, and use that control to switch *Enabled* and *Disabled*, and check the state of the function.

### 6.8.3.3 Verifying the auto-reclosing function

Select the test cases to be run according to what is applicable to the particular application. It can be, for example, three-phase single-shot reclosing or two-shot reclosing. Below a case with three-phase single-shot reclosing is described.

1. Set **Operation** = *Enabled*.
2. If SESRSYN (25) is not to be operated, ensure that the SYNC input is activated. If the SESRSYN (25) function is to be included, ensure that SESRSYN (25) is supplied with the appropriate AC quantities.
3. Simulate CB closed position by closing switch SC to make the BR relay pickup.
4. Simulate CBREADY by closing the switch SRY, and leave it closed.
5. Inject AC quantities to give a trip to the BR and to the PICKUP input. 
   Observe and preferably record the operation. The BR relay shall trip and reclose (pickup). After reclosing, the SRY switch can be opened for about 5 s and then closed again.
   The auto-reclosing open time and the sequence should be checked, for example in the event recording. Check also the operation indications (disturbance report) and the operation counters. **Main menu/Tests/Function status/STBRREC (79, 0->1)/STBRREC:1**
Should the operation not be as expected, this should be investigated. It could be caused by an inappropriate setting or missing condition such as CBREADY (or SYNC at three-phase reclosing).

6. Repeat the sequence by simulating a permanent fault.
   Shortly after the reclosing shot a new fault is applied. If a single-shot reclosing program is selected, there shall be one reclosing operation and then blocking of the auto-reclosing function for the set Reset time.
   Before a new reclosing sequence can be run, the CBREADY and 52A (CB closed) must be set manually.

6.8.3.4 Checking the reclosing conditions

When checking the influence of a releasing condition it is suggested to first run a sequence with the condition fulfilled. When the condition signal is removed, and a new sequence is run, it indicates that the result was due to the changed condition. In case of a blocking signal the procedure should be similar. Start without the blocking or inhibit signal, and then run a sequence with the blocking or inhibit signal added.

6.8.3.5 Checking the influence of the INHIBIT signal

1. Check that the auto-reclosing function is operative, for example, by making a reclosing shot without the INHIBIT signal.
2. Apply a fault and thereby a PICKUP signal. At the same time, or during the open time, apply a signal to the input INHIBIT.
3. Check that the reclosing sequence is interrupted and no reclosing takes place.

6.8.3.6 Check closing onto a fault

1. Check that the closing function is operative, for example by making a reclosing shot.
   Keep the CBREADY signal high.
2. Set the breaker simulating relay BR in Open position.
3. Close the BR relay and apply immediately a fault and thereby an INITIATE signal.
4. Check that no reclosing takes place.

6.8.3.7 Checking the influence of CB not ready for reclosing

1. Check that the auto-reclosing function is operative, for example by making a reclosing shot.
Keep the CB simulator BR closed. Remove the CBREADY signal by opening SRY.
2. Apply a fault and thereby a PICKUP signal.
3. Check that no reclosing takes place.

6.8.3.8 Checking the influence of synchronism check (at three-pole reclosing)

1. Check that the auto-reclosing function is operative, for example, by making a three-phase reclosing shot with the synchronism check condition. Remove the SYNC signal.
2. Apply a fault causing three-phase trip and thereby a PICKUP and a TR3P signal.
3. Wait for the $t_{Sync}$ time out limit.
   Check that no reclosing is made.

6.8.3.9 Restoring equipment

After the tests, restore the equipment to normal or desired state. Check the following items in particular.

1. Check the operation counters.
   Reset the counters to zero, if that is the user's preference. The counter reset function is found in the HMI under Main menu/Clear/Clear counters/STBRREC (79, 0- >1)
2. Restore settings that may have been modified for the tests back to normal.
3. Disconnect the test switch, CB simulating arrangement and test circuits. Reconnect any links or connection terminals, which may have been opened for the tests.
4. Reset indications, alarms and disturbance recordings.
   Clearing of the disturbance report must be done via PCM600 using the Disturbance Handling tool.

6.8.3.10 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Control/STBRREC(79,0->1)/STBRREC:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.8.4 Interlocking

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".
Values of the logical signals are available on the local HMI under **Main menu/Tests/Function status/Control/\(<\text{Function}\)/</Function:1>**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The interlocking function consists of a bay-level part and a station-level part. The interlocking is delivery specific and is realized by bay-to-bay communication over the station bus. For that reason, test the function in a system, that is, either in a complete delivery system as an acceptance test (FAT/SAT) or as parts of that system.

**6.8.5 Apparatus control APC**

The apparatus control function consists of four types of function blocks, which are connected in a delivery-specific way between bays and to the station level. For that reason, test the total function in a system, that is, either in a complete delivery system as an acceptance test (FAT/SAT) or as parts of that system.

If a block/unblock command is sent from remote to function, while the IED is shut down, this command will not be recognized after the start up, thus the command that was sent prior to the shut down is used. In such cases, where there is a mismatch, the user is advised to make a complete cycle of block/unblock operations to align the statuses.

**6.9 Testing scheme communication functions**

**6.9.1 Scheme communication logic with delta based blocking scheme signal transmit ZCPSCH (85)**

Prepare the IED for verification of settings as outlined in **5.1 "Preparing the IED to verify settings"**.

Values of the logical signals for ZCPSCH (85) are available on the local HMI under **Main menu/Tests/Function status/Scheme communication/ZCPSCH(85)/ZCPSCH:1**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

Check the scheme logic during the secondary injection test of the impedance or overcurrent protection functions.

Activating of the different zones verifies that the CS signal is issued from the intended zones. The CS signal from the independent tripping zone must have a $t_{SendMin}$ minimum time.
Check the tripping function by activating the CR and CR_GUARD inputs with the overreaching zone used to achieve the PLTR_CRD signal.

It is sufficient to activate the zones with only one type of fault with the secondary injection.

6.9.1.1 Testing permissive underreaching

1. Activate the receive (CR) signal in the IED.
2. Apply healthy normal load conditions to the IED for at least two seconds.
3. Apply a fault condition within the permissive zone.
4. Check that correct trip outputs, external signals, and indications are obtained for the actual type of fault generated.
5. Check that other zones operate according to their zone timers and that the send (CS) signal is obtained only for the zone configured to generate the actual signal.
6. Deactivate the receive (CR) signal in the IED.
7. Check that the trip time complies with the zone timers and that correct trip outputs, external signals, and indications are obtained for the actual type of fault generated.

6.9.1.2 Testing permissive overreaching

1. Activate the receive (CR) signal in the IED.
2. Apply healthy normal load conditions to the IED for at least two seconds.
3. Apply a fault condition within the permissive zone.
4. Check that correct trip outputs, external signals, and indication are obtained for the actual type of fault generated.
5. Check that the other zones operate according to their zone timer and that the send (CS) signal is obtained only for the zones that are configured to give the actual signal. Also the zone connected to CS underreach is giving CS in this mode.
6. Deactivate the IED receive (CR) signal.
7. Apply healthy normal load conditions to the IED for at least two seconds.
8. Apply a fault condition within the permissive zone.
9. Check that trip time complies with the zone timers and that correct trip outputs, external signals, and indications are obtained for the actual type of fault generated.

6.9.1.3 Testing blocking scheme

1. Deactivate the receive (CR) signal of the IED.
2. Apply healthy normal load conditions to the IED for at least two seconds.
3. Apply a fault condition within the forward directed zone used for scheme communication tripping.
4. Check that correct trip outputs and external signals are obtained for the type of fault generated and that the operate time complies with the $t_{Coord}$ timer (plus relay measuring time).

5. Check that the other zones operate according to their zone times and that a send (CS) signal is only obtained for the reverse zone.

6. Activate the IED receive (CR) signal.

7. Apply a fault condition in the forward directed zone used for scheme communication tripping.

8. Check that the no trip from scheme communication occurs.

9. Check that the trip time from the forward directed zone used for scheme communication tripping complies with the zone timer and that correct trip outputs, external signals, and indications are obtained for the actual type of fault generated.

6.9.1.4 Testing delta blocking scheme

1. Deactivate the receive (CR) signal of the IED.
2. Apply healthy normal load conditions to the IED for at least two seconds.
3. Apply a fault condition within the forward directed zone used for scheme communication tripping.
4. Check that correct trip outputs and external signals are obtained for the type of fault generated and that the operate time complies with the $t_{Coord}$ timer (plus relay measuring time).
5. Check that the other zones operate according to their zone times and that a send (CS) signal is only obtained for the reverse zone.
6. Check that for a forward fault, carrier send (CS) signal is first obtained from the delta based fault inception detection (as it is not directional), and immediately inhibited by the forward zone.
7. Activate the IED receive (CR) signal.
8. Apply a fault condition in the forward directed zone used for scheme communication tripping.
9. Check that the no trip from scheme communication occurs.
10. Check that the trip time from the forward directed zone used for scheme communication tripping complies with the zone timer and that correct trip outputs, external signals, and indications are obtained for the actual type of fault generated.

6.9.1.5 Checking of unblocking logic

Check the unblocking function (if the function is required) when checking the communication scheme.

Command function with continuous unblocking ($Unblock = 1$)

Procedure
1. Activate the guard input signal (CR_GUARD) of the IED.

2. Using the scheme selected, check that a signal accelerated trip (TRIP) is obtained when the guard signal is deactivated.

6.9.1.6 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Scheme communication/ZCPSCH(85)/ZCPSCH:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.9.2 Current reversal and WEI logic for distance protection 3-phase ZCRWPSCH (85)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ZCRWPSCH (85) are available on the local HMI under Main menu/Tests/Function status/Scheme communication/ZCRWPSCH(85)/ZCRWPSCH:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The current reversal logic and the weak-end infeed functions are tested during the secondary-injection test of the impedance or overcurrent protection zones together with the scheme communication logic for the distance protection function ZCPSCH (85).

6.9.2.1 Current reversal logic

It is possible to check the delay of the CS send signal with $t_{DelayRev}$ by changing from a reverse to a forward fault.

By continuously activating the CR input and changing from a reverse to a forward fault, the delay $t_{DelayRev}$ can be checked.

Checking of current reversal

The reverse zone timer must not operate before the forward zone fault is applied. The user might need to increase the reverse zone timer setting during testing of current reversal.
The forward zone timer must be set longer than the $t_{\text{DelayRev}}$ setting.

1. Activate the receive (CRL) signal.
2. Set the healthy condition to an impedance at 50% of the reach of the reverse zone connected to IRVL.
3. After the pickup condition is obtained for reverse zone, apply a fault at 50% of the reach of the forward zone connected to WEIBLK2.
4. Check that correct trip outputs and external signals are obtained for the type of fault generated.
   The operation time should be about the $t_{\text{DelayRev}}$ setting longer than the carrier accelerated trip (TRIP) previously recorded for permissive scheme communication.
5. Restore the forward and reverse zone timer to its original setting.

### 6.9.2.2 Weak-end infeed logic at permissive schemes

1. Check the blocking of the echo with the injection of a CRL signal >40ms after a reverse fault is applied.
2. Measure the duration of the echoed CS signal by applying a CRL receive signal.
3. Check the trip functions and the voltage level for trip by reducing a phase voltage and applying a CRL receive signal.

### 6.9.2.3 Testing conditions

Only one type of fault is sufficient, with the current reversal and weak-end infeed logic for distance protection function ZCRWPSCH (85). For phase A-G fault, set these parameters:

<table>
<thead>
<tr>
<th>Phase</th>
<th>I (Amps)</th>
<th>Phase-angle (Deg)</th>
<th>V (Volts)</th>
<th>Phase-angle (Deg)</th>
</tr>
</thead>
<tbody>
<tr>
<td>A</td>
<td>0</td>
<td>0</td>
<td>Set less than $UPN&lt;PU27PN$</td>
<td>0</td>
</tr>
<tr>
<td>B</td>
<td>0</td>
<td>240</td>
<td>69.3</td>
<td>240</td>
</tr>
<tr>
<td>C</td>
<td>0</td>
<td>120</td>
<td>69.3</td>
<td>120</td>
</tr>
</tbody>
</table>

If wanted, change all settings cyclically for other faults (BG and CG).

Weak-end infeed set for echo and trip
1. Apply input signals according to table 11.
2. Activate the receive (CR) signal.
3. After the IED has operated, turn off the input signals.
4. Check that trip, send signal, and indication are obtained.
   (note: a 200mS pulse)

6.9.2.4 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Scheme communication/ZCRWPSCH(85)/ZCRWPSCH:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.9.3 Current reversal and WEI logic for distance protection, phase segregated ZCWSPSCH (85)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ZCWSPSCH (85) are available on the local HMI under Main menu/Tests/Function status/Scheme communication/ZCWSPSCH(85)/ZCWSPSCH:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The current reversal logic and the weak-end infeed functions are tested during the secondary injection test of the impedance or overcurrent protection zones together with the Scheme communication logic for the distance protection function ZCP SCH (85).

6.9.3.1 Current reversal logic

It is possible to check the delay of the CS send signal with tDelayRev by changing from a reverse to a forward fault.

By continuously activating the CR input and changing from a reverse to a forward fault, the delay tDelayRev can be checked.

Checking of current reversal
The reverse zone timer must not operate before the forward zone fault is applied. The user might need to increase the reverse zone timer setting during testing of current reversal.
The forward zone timer must be set longer than the $t_{DelayRev}$ setting.

1. Activate the receive (CRL) signal.
2. Set the healthy condition to an impedance at 50% of the reach of the reverse zone connected to IRVL.
3. After the pickup condition is obtained for reverse zone, apply a fault at 50% of the reach of the forward zone connected to WEIBLK2.
4. Check that correct trip outputs and external signals are obtained for the type of fault generated.
   The operation time should be about the $t_{DelayRev}$ setting longer than the carrier accelerated trip (TRIP) previously recorded for permissive scheme communication.
5. Restore the forward and reverse zone timer to its original setting.

6.9.3.2 Weak-end infeed logic at permissive schemes

1. Check the blocking of the echo with the injection of a CRL signal $\geq 40$ ms after a reverse fault is applied.
2. Measure the duration of the echoed CS signal by applying a CRL receive signal.
3. Check the trip functions and the voltage level for trip by reducing a phase voltage and applying a CRL receive signal.

6.9.3.3 Testing conditions

Only one type of fault is sufficient, with the Current reversal and WEI logic for distance protection phase segregated ZCWSPSCH (85). Apply three faults (one in each phase). For phase $A-G$ fault, set these parameters:

<table>
<thead>
<tr>
<th>Phase</th>
<th>I (Amps)</th>
<th>Phase-angle (Deg)</th>
<th>V (Volts)</th>
<th>Phase-angle (Deg)</th>
</tr>
</thead>
<tbody>
<tr>
<td>A</td>
<td>0</td>
<td>0</td>
<td>Set less than $PU27PN$</td>
<td>0</td>
</tr>
<tr>
<td>B</td>
<td>0</td>
<td>240</td>
<td>69.3</td>
<td>240</td>
</tr>
<tr>
<td>C</td>
<td>0</td>
<td>120</td>
<td>69.3</td>
<td>120</td>
</tr>
</tbody>
</table>

Change all settings cyclically for other faults ($BG$ and $CG$).

Weak-end infeed set for echo and trip.
1. Apply input signals according to table 12.
2. Activate the receive (CR) signal of the terminal.
3. After the relay has operated, turn off the input signals.
4. Check that trip, send signal, and indication are obtained (note: a 200ms pulse).
5. Apply input signals according to table 12.
6. Activate the receive (CR) signal of the terminal.
7. After the relay has operated turn off the input signals.
8. Check that the send signal is obtained.

6.9.3.4 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Scheme communication/ZCWSPSCH(85)/ZCWSPSCH:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.9.4 Local acceleration logic ZCLCPLAL

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ZCLCPLAL are available on the local HMI under Main menu/Tests/Function status/Scheme communication/ZCLCPLAL/ZCLCPLAL:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The logic is checked during the secondary injection test of the impedance measuring zones.

6.9.4.1 Verifying the settings

1. Provide the IED with conditions equivalent to normal load for at least two seconds.
2. Deactivate the conditions for accelerated function.
3. Apply a phase-to-ground fault at 100% of line impedance.
4. Check that the fault is tripped with the second zone time delay.
5. Provide the IED with conditions equivalent to normal load for at least two seconds.
6. Activate the condition for accelerated function either by the autorecloser or by the loss-of-load.
7. Apply a phase-to-ground fault at 100% of line impedance.
8. Check that the fault is tripped instantaneously.
6.9.4.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Scheme communication/ZCLCPLAL/ZCLCPLAL:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.9.5 Scheme communication logic for residual overcurrent protection ECPSCH (85)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ECPSCH (85) are available on the local HMI under Main menu/Tests/Function status/Scheme communication/ECPSCH(85)/ECPSCH:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

Before testing the communication logic for residual overcurrent protection function ECPSCH (85), the four step residual overcurrent protection function EF4PTOC (51N/67N) has to be tested according to the corresponding instruction. Once this is done, continue with the instructions below.

If the current reversal and weak-end infeed logic for ground-fault protection is included, proceed with the testing according to the corresponding instruction after the testing the communication logic for residual overcurrent protection. The current reversal and weak-end-infeed functions shall be tested together with the permissive scheme.

6.9.5.1 Testing the directional comparison logic function

Blocking scheme

1. Inject the polarizing voltage 3V0 at 5% of VBase where the current is lagging the voltage by 65°.
2. Inject current (65° lagging the voltage) in one phase at about 110% of the set operating current, and switch the current off with the switch.
3. Switch the fault current on and measure the operating time of the communication logic.
   Use the TRIP signal from the configured binary output to stop the timer.
4. Compare the measured time with the set value tCoord.
5. Activate the CR binary input.
6. Check that the CRL output is activated when the CR input is activated.
7. Switch the fault current on (110% of the set operating current) and wait longer than the set value $t_{Coord}$.

No TRIP signal should appear.

8. Switch the fault current off.
9. Reset the CR binary input.
10. Activate the BLOCK digital input.
11. Switch the fault current on (110% of the set operating current) and wait for a period longer than the set value $t_{Coord}$.

No TRIP signal should appear.

12. Switch the fault current and the polarizing voltage off.
13. Reset the BLOCK digital input.

**Permissive scheme**

1. Inject the polarizing voltage 3V0, which is 5% of $V_{Base}$ where the current is lagging the voltage by 65°.
2. Inject current (65° lagging the voltage) into one phase at about 110% of the set operating current, and switch the current off with the switch.
3. Switch the fault current on, (110% of the set operating current) and wait longer than the set value $t_{Coord}$.

No TRIP signal should appear, and the CS binary output should be activated.

4. Switch the fault current off.
5. Activate the CR binary input.
6. Switch the fault current on (110% of the set operating current) and measure the operating time of the ECPSCH (85) logic. Use the TRIP signal from the configured binary output to stop the timer.
7. Compare the measured time with the setting for $t_{Coord}$.
8. Activate the BLOCK digital input.
9. Switch the fault current on (110% of the set operating current) and wait for a period longer than the set value $t_{Coord}$. 
No TRIP signal should appear.

10. Switch the fault current and the polarizing voltage off.
11. Reset the CR binary input and the BLOCK digital input.

6.9.5.2 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Scheme communication/ECPSCH(85)/ECPSCH:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.9.6 Current reversal and weak-end infeed logic for residual overcurrent protection ECRWPSCH (85)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for ECRWPSCH (85) are available on the local HMI under Main menu/Tests/Function status/Scheme communication/ECRWPSCH(85)/ECRWPSCH:1. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

First, test the four step residual overcurrent protection function EF4PTOC (51N/67N) and then the current reversal and weak-end infeed logic according to the corresponding instructions. Then continue with the instructions below.

6.9.6.1 Testing the current reversal logic

1. Inject the polarizing voltage 3V0 to 5% of VBase and the phase angle between voltage and current to 155°, the current leading the voltage.
2. Inject current (180° — AngleRCA) in one phase to about 110% of the set operating current of the four step residual overcurrent protection (INDir).
3. Check that the IRVL output is activated in the disturbance recorder after the set time (tPickUpRev).
4. Abruptly reverse the current to $\text{AngleRCA}$ setting lagging the voltage, to operate the forward directional element.

5. Check that the IRVL output still is activated after the reversal with a time delay that complies with the setting ($t_{\text{DelayRev}}$).

6. Switch off the polarizing voltage and the current.

### 6.9.6.2 Testing the weak-end infeed logic

**If setting $WEI = \text{Echo}$**

1. Inject the polarizing voltage 3V0 to ($180^\circ - \text{AngleRCA}$) of $V_{\text{Base}}$ and the phase angle between voltage and current to $155^\circ$, the current leading the voltage.

2. Inject current ($180^\circ - \text{AngleRCA}$) in one phase to about 110% of the setting operating current ($\text{INDir}$).

3. Activate the CRL binary input.

   No ECHO and CS should appear.

4. Abruptly reverse the current to the setting of $\text{AngleRCA}$ setup lagging the voltage, to operate the forward directional element.

   No ECHO and CS should appear.

5. Switch off the current and check that the ECHO and CS appear on the corresponding binary output during 200ms after resetting the directional element.

6. Switch off the CRL binary input.

7. Activate the BLOCK binary input.

8. Activate the CRL binary input.

   No ECHO and CS should appear.

9. Switch off the polarizing voltage and reset the BLOCK and CRL binary input.

**If setting $WEI = \text{Echo} \; \& \; \text{Trip}$**

1. Inject the polarizing voltage 3V0 to about 90% of the setting ($3V0_{PU}$) operating voltage.

2. Activate the CRL binary input.
No ECHO, CS and TRWEI outputs should appear.

3. Increase the injected voltage to about 110% of the setting (3V0PU) operating voltage.
4. Activate the CRL binary input.
5. Check that the ECHO, CS and TRWEI appear on the corresponding binary output or on the local HMI.
6. Reset the CRL binary input.
7. Activate the BLOCK binary input.
8. Activate the CRL binary input.

No ECHO, CS and TRWEI outputs should appear.

9. Reset the CRL and BLOCK binary input.
10. Inject the polarizing voltage 3V0 to about 110% of the setting (3V0PU) and adjust the phase angle between the voltage and current to (180° — AngRCA) setting the current leading the voltage.
11. Inject current in one phase to about 110% of the setting operating current (INDir).
12. Activate the CRL binary input.

No ECHO and TRWEI should appear.

13. Abruptly reverse the current to 65° lagging the voltage, to operate the forward directional element.

No ECHO and TRWEI should appear.

14. Switch the current off and check that the ECHO, CS and TRWEI appear on the corresponding binary output during 200ms after resetting the directional element. If EF4PTOC operates in forward direction also CS should be obtained.
15. Switch the polarizing voltage off and reset the CRL binary input.

6.9.6.3 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Scheme communication/ECRWPSCH(85)/ECRWPSCH:1 for the function,
or for each individual function in a chain, to be tested next. Remember to set the parameter *Blocked* to *Yes*, for each individual function that has been tested.

### 6.10 Testing logic functions

#### 6.10.1 Tripping logic, common 3-phase output SMPPTRC (94)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for SMPPTRC (94) are available on the local HMI under **Main menu/Tests/Function status/Logic/SMPPTRC(94,1->0)/SMPPTRC:X**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

This function is functionality tested together with other protection functions (ground-fault overcurrent protection, and so on) within the IED. It is recommended that the function is tested together with the autorecloser function, regardless of whether the autorecloser function is integrated or external.

##### 6.10.1.1 Three-phase operating mode

1. Check that *AutoLock* and *TripLockout* are both set to *Disabled*.
2. Initiate a three-phase fault.
   An adequate time interval between the faults should be considered, to overcome a reset time caused by the possible activation of the Autorecloser function, SMBRREC (79). The function must issue a three-pole trip in all cases, when a trip is initiated by any protection function, either integrated or external. The functional TRIP output signal must always appear.

##### 6.10.1.2 Circuit breaker lockout

The following tests should be carried out when the built-in lockout function is used in addition to possible other tests, which depends on the complete configuration of an IED.

1. Check that *AutoLock* and *TripLockout* are both set to *Disabled*.
2. Initiate a three-phase fault.
   The functional output TRIP should be active at each fault. The output CLLKOUT must not be activated.
3. Activate the automatic lockout function, set *AutoLock = Enabled* and repeat.
   Besides the TRIP outputs, CLLKOUT should be set.
4. Reset the lockout signal by activating the reset lockout (RSTLKOUT) signal.
5. Activate the TRIP signal lockout function, set $TripLockout = Enable$ and repeat. The output TRIP must be active and stay active after each fault. CLLKOUT must be activated.

6. Reset the lockout.
   All functional outputs should reset.

7. Deactivate the TRIP signal lockout function, set $TripLockout = Disabled$ and the automatic lockout function, set $AutoLock = Disabled$ if not used.

### 6.10.1.3 Completing the test

Continue to test another function or end the testing by setting the parameter $TestMode$ to $Disabled$ under **Main menu/Tests/IED test mode**/TESTMODE:1. If another function is tested, then set the parameter $Blocked$ to $No$ under **Main menu/Tests/Function test modes/Logic/SMPPTRC(94,1->0)/SMPPTRC:X** for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter $Blocked$ to $Yes$, for each individual function that has been tested.

### 6.10.2 Tripping logic phase segregated output SPTPPTRC (94)

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for SPTPPTRC (94) are available on the local HMI under **Main menu/Tests/Function status/Logic/SPTPPTRC(94,1->0)/SPTPPTRC:X**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

This function is functionality tested together with other protection functions (ground-fault overcurrent protection, and so on) within the IED. It is recommended that the function is tested together with the autorecloser function, or when a separate external unit is used for reclosing purposes. The testing is preferable done in conjunction with the protection system and autorecloser function.

### 6.10.2.1 1p/3p operating mode

In addition to various other tests, the following tests should be performed. They depend on the complete configuration of an IED.

1. Make sure that $TripLockout$ and $AutoLock$ are both set to $Disabled$.
2. Initiate different single-phase-to-ground faults one at a time.
   Single-phase tripping will only be allowed when an auto-reclose attempt will follow. Autorecloser STBRREC (79) has functionality such as the long trip time, CB ready and so on, which can prevent a proper single-phase tripping and auto reclose. To bypass this problem the fault initiation should be with a test set and with the auto reclose in full service with a test set connected to the distance protection function.
Consider using an adequate time interval between faults, to overcome a reclaim time of which is activated by the autorecloser function. Only a single-phase trip should occur for each separate fault and only one of the trip outputs (TR_A, TR_B, TR_C) should be activated at a time. Functional outputs TRIP and TR1P should be active during each fault. No other outputs should be active.

3. Initiate different phase-to-phase and three-phase faults.
Consider using an adequate time interval between faults, to overcome a reclaim time which is activated by the STBRREC (79) function. A three-phase trip should occur for each separate fault and all of the trips. Functional outputs TRIP, all TR_A, TR_B, TR_C and TR3P should be active at each fault. No other outputs should be active.

4. Initiate a single-phase-to-ground fault and switch it off immediately when the trip signal is issued for the corresponding phase.

5. Initiate the same fault once again within the reclaim time of the used autorecloser function.
A single-phase fault shall be given at the first fault. A three-phase trip must be initiated for the second fault. Check that the corresponding trip signals appear after both faults. Functional outputs TRIP, TR_A, TR_B, TR_C and TR1P should be active during first fault. No other outputs should be active. Functional outputs TRIP, all TR_A, TR_B, TR_C and TR3P should be active during second fault.

6. Initiate a single-phase-to-ground fault and switch it off immediately when the trip signal is issued for the corresponding phase.

7. Initiate the second single-phase-to-ground fault in one of the remaining phases. This shall be within the time interval, shorter than $t_{EvolvingFault}$ (default setting 2.0 s) and shorter than the dead-time of the autoreclose function, when included in the protection scheme. Check that the second trip is a three-phase trip and that a three-phase autoreclosing attempt is given after the three-phase dead time. Functional outputs TRIP, TR_A, TR_B, TR_C and TR1P should be active during first fault. No other outputs should be active. Functional outputs TRIP, all TR_A, TR_B, TR_C and TR3P should be active during second fault.

6.10.2.2 Circuit breaker lockout

The following tests should be carried out when the built-in lockout function is used in addition to possible other tests, which depends on the complete configuration of an IED.

1. Check that AutoLock and TripLockout are both set to Disabled.
2. Initiate a three-phase fault
The functional output TRIP should be active at each fault. The output CLLKOUT must not be set.
3. Activate the automatic lockout function, set AutoLock = Enabled and repeat.
4. Reset the lockout signal by shortly thereafter activating the reset lockout (RSTLKOUT) signal.
5. Activate the TRIP signal lockout function, set TripLockout = Enabled and repeat. The output TRIP must be active and stay active after each fault, CLLKOUT must be set.
6. Reset the lockout. All functional outputs should reset.
7. Deactivate the TRIP signal lockout function, set TripLockout = Disabled and the automatic lockout function, set AutoLock = Disabled if not used.

6.10.2.3 Completing the test

Continue to test another function or end the testing by setting the parameter TestMode to Disabled under Main menu/Tests/IED test mode/TESTMODE:1. If another function is tested, then set the parameter Blocked to No under Main menu/Tests/Function test modes/Logic/SPTPTRC(94,1->0)/SPTPTRC:1 for the function, or for each individual function in a chain, to be tested next. Remember to set the parameter Blocked to Yes, for each individual function that has been tested.

6.11 Testing monitoring functions

6.11.1 Event counter CNTGGIO

The event counter function CNTGGIO can be tested by connecting a binary input to the counter under test and applying pulses to the counter. The speed of pulses must not exceed 10 per second. Normally the counter will be tested in connection with tests on the function that the counter is connected to, such as trip logic. When configured, test it together with the function that operates it. Trig the function and check that the counter result corresponds with the number of operations.

6.11.2 Limit counter L4UFCNT

The Limit counter function L4UFCNT can be tested by connecting a binary input to the counter and applying pulses to the counter. The speed of the pulses must not exceed the cycle time of the function. Normally the counter will be tested when testing the function that the counter is connected to, such as the trip function. When the function is configured, test it together with the function that operates it. Trig the function and check that the counter result corresponds to the number of operations.

6.11.2.1 Completing the test

Continue to test another function or end the test by changing the Test mode setting to Off. Restore connections and settings to their original values, if they were changed for testing purposes.
6.11.3 Fault locator LMBRFLO

Prepare the IED for verification of settings as outlined in 5.1 "Preparing the IED to verify settings".

Values of the logical signals for LMBRFLO are available on the local HMI under **Main menu/Tests/Function status/Monitoring/LMBRFLO/LMBRFLO:1**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The Fault locator function LMBRFLO depends on other functions to work properly, that is, phase selection information from distance protection function and analog information supplied by the trip value recorder function. Check that proper binary initiate (pickup or tripping) and phase selection signals are connected and voltage and current signals are configured (parameter settings).

The fault locator LMBRFLO function, supports kilometer and mile for the line length unit. The fault distance will be presented with the same unit as the line length and is mapped to IEC61850 -8-1 communication protocol, where the fault distance is supposed to be in kilometer (km). Select the line length unit to kilometer for compliance with IEC61850.

The result is displayed on the local HMI or via PCM600. Distances to faults for the last 100 recorded disturbances can be found on the local HMI under **Main menu/Tests/Function status/Monitoring/LMBRFLO/LMBRFLO:1/Outputs**.

If PCM600 is used, the result is displayed on the recording list after upload, including loop selection information.

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Test settings</th>
</tr>
</thead>
<tbody>
<tr>
<td>I</td>
<td>Healthy conditions V = 69.3 V, I = 0 A &amp; ZF = 0°</td>
</tr>
<tr>
<td>Impedance</td>
<td>Test point Note:</td>
</tr>
<tr>
<td>[Z]</td>
<td>Z ≤ (X0 + 2·X1)/3 For single-phase faults</td>
</tr>
<tr>
<td></td>
<td>Z ≤ X1 For three and two phase faults</td>
</tr>
<tr>
<td></td>
<td>Z ≤ (X0 + 2·X1 XM)/3 For single-phase fault with mutual zero-sequence current</td>
</tr>
<tr>
<td>Impedance angle [ZΦ]</td>
<td>Test angle</td>
</tr>
<tr>
<td></td>
<td>ZΦ arctan[(X0 + 2·X1) / (R0 + 2R1)] For single-phase faults</td>
</tr>
<tr>
<td></td>
<td>ZΦ arctan(X1/R1) For two-phase faults</td>
</tr>
</tbody>
</table>
6.11.3.1 Measuring the operate limit

1. Set the test point (|Z| fault impedance and ZΦ impedance phase angle) for a condition that meets the requirements in table 13.
2. Subject the IED to healthy normal load conditions for at least two seconds.
3. Apply a fault condition.
   Check that the distance-to-fault value displayed on the HMI complies with equations 32, 33 and 34

\[
p = \frac{Z_x}{X1} \cdot 100
\]  
\text{(Equation 32)}

in % for two- and three-pole faults

\[
p = \frac{3 \cdot Z_x}{X0 + 2 \cdot X1} \cdot 100
\]  
\text{(Equation 33)}

in % for single-phase-to-ground faults

\[
p = \frac{3 \cdot Z_x}{X0 + 2 \cdot X1 \pm XM} \cdot 100
\]  
\text{(Equation 34)}

in % for single-phase-to-ground faults with mutual zero sequence current.

Where:

\( p \) = the expected value of a distance to fault in percent
\( Z_x \) = set test point on the test set
\( X0 \) = set zero-sequence reactance of a line
\( X1 \) = set positive-sequence reactance of a line
\( XM \) = set mutual zero-sequence impedance of a line

6.11.3.2 Completing the test
6.12 Testing metering functions

6.12.1 Pulse counter PCGGIO

The test of the Pulse counter function PCGGIO requires the Parameter Setting tool in PCM600 or an appropriate connection to the local HMI with the necessary functionality. A known number of pulses with different frequencies are connected to the pulse counter input. The test should be performed with settings Operation = Enable or Operation = Disable and the function blocked or unblocked. The pulse counter value is then checked in PCM600 or on the local HMI.

6.13 Testing station communication

6.13.1 Establishing connection and verifying the IEC 61850 communication

About this chapter

This chapter contains instructions on how to establish connection and verify that the IEC 61850 communication operates as intended, when the IED is connected to an Ethernet network via the optical ports of the COM module.

6.13.1.1 Overview

The COM03 ports are used for substation bus (IEC 61850-8-1) communication as well as redundant communication.

The COM05 ports are also used for communication but not redundant communication.

For IEC 61850-8-1 redundant communication according to IEC62439–3 Edition 2, port LAN_1A and LAN_1B is utilized.

Redundant communication according to IEC62439–3 Edition 1 and IEC 61850–9–2LE process bus communication are not supported in the 650 Ver 1.3 series IEDs.
6.13.1.2 Setting the station communication

To enable the IEC 61850 communication, the corresponding COM03 ports must be activated. Port LAN1 A and LAN1 B are used for redundancy.

If COM03 is used; the following below apply. If COM05 is used; there is no redundancy and the port is named LAN1 or (FRONT)

To enable IEC 61850 station communication:

- The IEC 61850-8-1 station communication functionality must be configured in the local HMI. Navigate to Main Menu/Configuration/Communication/TCP-IP configuration/ETHLAN1_AB and set the OperationMode parameter to NonRedundant(A) or, for redundant communication, to PRP(A+B).
- To enable GOOSE communication, the Operation parameter for the corresponding GOOSE function blocks (GOOSEBINRCV and GOOSEINTLKRCV) must be set to Enabled in the application configuration.
- To enable GOOSE communication via the front port the parameter GOOSE in Main menu/Configuration/Communication/Station communication/IEC61850-8-1/PortSelGOOSE must be set to Front. To enable GOOSE communication via rear port the parameter PortSelGOOSE must be set to LAN1.

To enable IEC 61850 station communication:

1. Enable IEC 61850-8-1 (substation bus) communication for port A and B.
   1.1. Set values for ETHLAN1_AB.
       Navigate to Main Menu/Configuration/TCP-IP configuration/ETHLAN1_AB.
       Set values for OperationMode, IPAddress and IPMask. OperationMode must be set to NonRedundantA.
       Check that the correct IP address is assigned to the port.
   1.2. Enable IEC 61850-8-1 communication.
       Navigate to Main menu/Settings/General settings/Communication/Station communication/IEC 61850-8-1.
       Set Operation to Enabled and PortSelGOOSE to the port used.

2. Enable redundant IEC 61850-8-1 communication for port A and B.
   2.1. Enable redundant communication.
       Navigate to Main Menu/Configuration/TCP-IP configuration/ETHLAN1_AB.
       Set values for OperationMode, IPAddress and IPMask. OperationMode must be set to .
Make sure that the optical fibres are connected correctly.

6.13.1.3 Verifying the station communication

Connect a PC to the substation network and ping the connected IED and the Substation Master PC to verify that the communication is working up to the transport layer.

The best way to verify the communication up to the application layer is to use a protocol analyzer connected to the substation or process bus and monitor the communication.

Verifying redundant IEC 61850-8-1 communication

Ensure that the IED receives IEC 61850-8-1 data on both ports A and B. In the local HMI navigate to Main menu/Tests/Function status/Communication/PRP Status/LAN1–A / LAN1–B and check that both signals LAN1-A and LAN1-B are shown as Ok. Remove the optical connection to one of the ports A or B. Verify that either signal LAN1-A or LAN1-B (depending on which connection that was removed) are shown as Error and that the other signal is shown as Ok. Be sure to re-connect the removed connection after completed verification.

6.14 Exit test mode

The following procedure is used to return to normal operation.

1. Navigate to the test mode folder.
2. Change the Enable setting to Disable. Press the 'E' key and the left arrow key.
3. Answer YES, press the 'E' key and exit the menus.
Section 7 Commissioning and maintenance of the fault clearing system

7.1 Commissioning and maintenance of the fault clearing system

About this chapter
This chapter discusses maintenance tests and other periodic maintenance measures.

7.1.1 Commissioning tests
During commissioning all protection functions shall be verified with the setting values used at each plant. The commissioning tests must include verification of all circuits by highlighting the circuit diagrams and the configuration diagrams for the used functions.

Further, the settings for protection functions are tested and recorded carefully as outlined for the future periodic maintenance tests.

The final testing includes primary verification of all directional functions where load currents is checked on the local HMI and in PCM600. The magnitudes and angles of all currents and voltages should be checked and the symmetry verified.

Directional functions have information about the measured direction and, for example, measured impedance. These values must be checked and verified as correct with the export or import of power available.

Finally, final trip tests must be performed. This involves activation of protection functions or tripping outputs with the circuit breaker closed and the tripping of the breaker verified. When several breakers are involved, each breaker must be checked individually and it must be verified that the other involved breakers are not tripped at the same time.

7.1.2 Periodic maintenance tests
The periodicity of all tests depends on several factors, for example the importance of the installation, environmental conditions, simple or complex equipment, static or electromechanical IEDs, and so on.
The normal maintenance practices of the user should be followed. However, ABB's recommendation is as follows:

Every second to third year

- Visual inspection of all equipment.
- Removal of dust on ventilation louvres and IEDs if necessary.
- Periodic maintenance test for protection IEDs of object where no redundant protections are provided.

Every four to six years

- Periodic maintenance test for protection IEDs of objects with redundant protection system.

First maintenance test should always be carried out after the first half year of service.

When protection IEDs are combined with built-in control, the test interval can be increased drastically, up to for instance 15 years, because the IED continuously reads service values, operates the breakers, and so on.

7.1.2.1 Visual inspection

Prior to testing, the protection IEDs should be inspected to detect any visible damage that may have occurred (for example, dirt or moisture deposits, overheating). Should burned contacts be observed when inspecting the IEDs, a diamond file or an extremely fine file can be used to polish the contacts. Emery cloth or similar products must not be used as insulating grains of abrasive may be deposited on the contact surfaces and cause failure.

Make sure that all IEDs are equipped with covers.

7.1.2.2 Maintenance tests

To be made after the first half year of service, then with the cycle as proposed above and after any suspected maloperation or change of the IED setting.

Testing of protection IEDs shall preferably be made with the primary circuit de-energized. The IED cannot protect the circuit during testing. Trained personnel may test one IED at a time on live circuits where redundant protection is installed and de-energization of the primary circuit is not allowed.
ABB protection IEDs are preferably tested by aid of components from the COMBITEST testing system or FT test systems described in information B03-9510 E. Main components are RTXP 8/18/24 test switch located to the left in each protection IED and RTXH 8/18/24 test handle, which is inserted in test switch at secondary testing. All necessary operations such as opening of trip circuits, short-circuiting of current circuits and opening of voltage circuits are automatically performed in the right order to allow for simple and safe secondary testing even with the object in service.

Important components of FT test system are FT1, FTx, FT19, FT19RS, FR19RX switches and assemblies as well as FT-1 test plug.

**Preparation**
Before starting maintenance testing, the test engineers should scrutinize applicable circuit diagrams and have the following documentation available:

- Test instructions for protection IEDs to be tested
- Test records from previous commissioning and maintenance tests
- List of valid settings
- Blank test records to fill in measured values

**Recording**
It is of utmost importance to carefully record the test results. Special test sheets covering the frequency of test, date of test and achieved test values should be used. IED setting list and protocols from previous tests should be available and all results should be compared for differences. At component failures, spare equipment is used and set to the requested value. A note of the exchange is made and the new measured values are recorded. Test records for several years of testing should be stored in a common file for a station, or a part of a station, to give a simple overview of the period of testing and achieved test values. These test records are valuable when analysis of service disturbances shall be done.

**Secondary injection**
The periodic maintenance test is done by secondary injection from a portable test set. Each protection shall be tested according to the secondary injection test information for the specific protection IED. Only the setting values adopted shall be checked for each protection function. If the discrepancy between obtained value and requested set value is too big the setting should be adjusted, the new value recorded and a note should be made in the test record.

**Alarm test**
When inserting the test handle of RTXP or using FT plugs, the alarm and event signalling is normally blocked. This is done in the IED by setting the event reporting to *Disabled* during the test. This can be done when the test handle is inserted or the IED is set to test mode from the local HMI. At the end of the secondary injection test it should be checked that the event and alarm signalling is correct by activating the events and performing some selected tests.
Self supervision check
Once secondary testing has been completed, it should be checked that no self-supervision signals are activated continuously or sporadically. Especially check the time synchronization system, GPS or other, and communication signals, both station communication and remote communication.

Trip circuit check
When the protection IED undergoes an operational check, a tripping pulse is normally obtained on one or more of the output contacts and preferably on the test switch. The healthy circuit is of utmost importance for the protection operation. If the circuit is not provided with a continuous trip-circuit supervision, it is possible to check that circuit is really closed when the test-plug handle has been removed by using a high-ohmic voltmeter and measuring between the plus and the trip output on the panel. The measurement is then done through the tripping magnet of the circuit breaker and therefore the complete tripping circuit is checked.

Note that the breaker must be closed.

Please observe that the test system does not provide built-in security during this test. If the instrument should be set on Amp instead of Volts, the circuit breaker naturally is tripped, therefore, great care is necessary.

Trip circuit from trip IEDs to circuit breaker is often supervised by trip-circuit supervision. It can then be checked that a circuit is healthy by opening tripping output terminals in the cubicle. When the terminal is opened, an alarm shall be achieved on the signal system after a delay of some seconds.

Remember to close the circuit directly after the test and tighten the terminal carefully.

Measurement of service currents
After a maintenance test it is recommended to measure the service currents and service voltages recorded by the protection IED. The service values are checked on the local HMI or in PCM600. Ensure that the correct values and angles between voltages and currents are recorded. Also check the direction of directional functions such as Distance and directional overcurrent functions.

For transformer differential protection, the achieved differential current value is dependent on the tap changer position and can vary between less than 1% up to perhaps
10% of rated current. For line differential functions, the capacitive charging currents can normally be recorded as a differential current.

The zero-sequence current to ground-fault protection IEDs should be measured. The current amounts normally very small but normally it is possible to see if the current circuit is "alive".

The neutral-point voltage to a ground-fault protection IED is checked. The voltage is normally 0.1 to 1V secondary. However, voltage can be considerably higher due to harmonics. Normally a CVT secondary can have around 2.5 - 3% third-harmonic voltage.

**Restoring**

Maintenance is very important to improve the availability of the protection system by detecting failures before the protection is required to operate. There is however little point in testing healthy equipment and then putting it back into service with an open terminal, with a removed fuse or open miniature circuit breaker with an open connection, wrong setting, and so on.

Thus a list should be prepared of all items disturbed during test so that all can be put back into service quickly and without overlooking something. It should be put back into service item by item and signed by the responsible engineer.
Section 8 Troubleshooting

8.1 Fault tracing

8.1.1 Identifying hardware errors

1. Check the module with an error.
   - Check the general IED status in Main menu/Diagnostics/IED status/General for a faulty hardware module.
   - Check the history of changes in internal event list in Main menu/Diagnostics/Internal Events.
2. Inspect the IED visually.
   - Inspect the IED visually to find any physical error causes.
   - If you can find some obvious physical damage, contact ABB for repair or replacement actions.
3. Check whether the error is external or internal.
   - Check that the error is not caused by external origins.
   - Remove the wiring from the IED and test the input and output operation with an external test device.
   - If the problem remains, contact ABB for repair or replacement actions.

8.1.2 Identifying runtime errors

1. Check the error origin from IED's internal event list Main menu/Diagnostics/IED status/General.
2. Reboot the IED and recheck the supervision events to see if the fault has cleared.
3. In case of persistent faults, contact ABB for corrective actions.

8.1.3 Identifying communication errors

Communication errors are normally communication interruptions or synchronization message errors due to communication link breakdown.
• Check the IEC61850 and DNP3 communication status in internal event list in **Main menu/Diagnostics/IED Status/General**.
• In case of persistent faults originating from IED’s internal faults such as component breakdown, contact ABB for repair or replacement actions.

### 8.1.3.1 Checking the communication link operation

There are several different communication links on the product. First check that all communication ports that are used for communication are turned on.

1. Check the front communication port RJ-45.
   1.1. Check that the uplink LED is lit with a steady green light. The uplink LED is located on the LHMI above the RJ-45 communication port on the left. The port is used for direct electrical communication to a PC connected via a crossed-over Ethernet cable.
   1.2. Check the communication status of the front port via the LHMI in **Main menu/Test/Function status/Communication/DOSFRNT:1/Outputs**. Check that the **LINKUP** value is 1, that is, the communication is working. When the value is 0, there is no communication link.

2. Check the communication status of the rear port X1 via the LHMI in **Main menu/Tests/Function status/Communication/DOSLAN1:1/Outputs**. The X1 communication port on the rear side of the IED is for optical Ethernet via LC connector.
   • Check that the **LINKUP** value is 1, that is, the communication is working. When the value is 0, there is no communication link.

### 8.1.3.2 Checking the time synchronization

• Select **Main menu/Diagnostics/IED status/General** and check the status of the time synchronization on **Time Synch**. The **Time synch** value is **Normal** when the synchronization is in order.

![Note]

Note that the time synchronization source has to be activated. Otherwise the value is always **Normal**.

### 8.1.4 Running the display test

To run the display test, either use the push buttons or start the test via the menu.
• Select **Main menu/Tests/LED test**.
• Press simultaneously `Esc` and `Menu`.

All the LEDs are tested by turning them on simultaneously. The display shows a set of patterns so that all the pixels are activated. After the test, the display returns to normal state.

### 8.2 Indication messages

#### 8.2.1 Internal faults

When the Ready LED indicates an internal fault by flashing, the message associated with the fault is found in the internal event list in the LHMI menu **Main menu/Diagnostics/Internal events**. The message includes the date, time, description and signal state for the fault. The internal event list is not updated dynamically. The list is updated by leaving the **Internal events** menu and then selecting it again. The current status of the internal fault signals can also be checked via the LHMI in **Main menu/Diagnostics/IED status**.

Different actions are taken depending on the severity of the fault. If the fault is found to be permanent, the IED stays in internal fault mode. The IED continues to perform internal tests during the fault situation.

When a fault appears, the fault indication message is to be recorded and stated when requesting support or service.

**Table 14: Internal fault indications**

<table>
<thead>
<tr>
<th>Fault indication</th>
<th>Additional information</th>
</tr>
</thead>
<tbody>
<tr>
<td>Internal Fault</td>
<td></td>
</tr>
<tr>
<td>Real Time Clock Error</td>
<td>Hardware error with the real time clock.</td>
</tr>
<tr>
<td>Internal Fault</td>
<td></td>
</tr>
<tr>
<td>Runtime Exec. Error</td>
<td>One or more of the application threads are not working properly.</td>
</tr>
<tr>
<td>Internal Fault</td>
<td></td>
</tr>
<tr>
<td>SW Watchdog Error</td>
<td>This signal will be activated when the terminal has been under too heavy load for at least 5 minutes.</td>
</tr>
<tr>
<td>Internal Fault</td>
<td></td>
</tr>
<tr>
<td>Runtime App Error</td>
<td>One or more of the application threads are not in an expected state.</td>
</tr>
<tr>
<td>Internal Fault</td>
<td></td>
</tr>
<tr>
<td>File System Error</td>
<td>A file system error has occurred.</td>
</tr>
</tbody>
</table>

Table continues on next page
### 8.2.2 Warnings

The warning message associated with the fault is found in the internal event list in the LHMI menu **Main menu/Diagnostics/Internal events**. The message includes the date, time, description and signal state for the fault. The current status of the internal fault signals can also be checked via the LHMI in **Main menu/Diagnostics/IED status/General**.

When a fault appears, record the fault indication message and state it when ordering service.

**Table 15: Warning indications**

<table>
<thead>
<tr>
<th>Warning indication</th>
<th>Additional information</th>
</tr>
</thead>
<tbody>
<tr>
<td>Warning IEC 61850 Error</td>
<td>IEC 61850 has not succeeded in some actions such as reading the configuration file, startup etc.</td>
</tr>
<tr>
<td>Warning DNP3 Error</td>
<td>Error in DNP3 communication.</td>
</tr>
</tbody>
</table>

### 8.2.3 Additional indications

The additional indication messages do not activate internal fault or warning.

The messages are listed in the LHMI menu under the event list. The signal status data is found under the IED status and in the internal event list.

**Table 16: Additional indications**

<table>
<thead>
<tr>
<th>Warning indication</th>
<th>Additional information</th>
</tr>
</thead>
<tbody>
<tr>
<td>Time Synch Error</td>
<td>Source of the time synchronization is lost or time system has made a time reset.</td>
</tr>
<tr>
<td>Settings Changed</td>
<td>Settings have been changed.</td>
</tr>
<tr>
<td>Setting Groups Changed</td>
<td>Setting group has been changed.</td>
</tr>
</tbody>
</table>
8.3 Correction procedures

8.3.1 Changing and setting the password

The password can only be set with PCM600.

For more information, see PCM600 documentation.

8.3.2 Identifying IED application problems

Navigate to the appropriate menu in the LHMI to identify possible problems.

- Check that the function is on.
- Check that the correct setting group (1 to 4) is activated.
- Check the blocking.
- Check the mode.
- Check the measurement value.
- Check the connection to trip and DFR functions.
- Check the channel settings.

8.3.2.1 Inspecting the wiring

The physical inspection of wiring connections often reveals the wrong connection for phase currents or voltages. However, even though the phase current or voltage connections to IED terminals might be correct, wrong polarity of one or more measurement transformers can cause problems.

- Check the current or voltage measurements and their phase information from Main menu/Measurements/Analog primary values or Analog secondary values.
- Check that the phase information and phase shift between phases is correct.
- Correct the wiring if needed.
  - Change the parameter Negation in Configuration/Analog modules/3PhaseAnalogGroup/SMAI_20_n:1 (n= the number of the SMAI used).

Changing the Negation parameter is not recommended without special skills.

- In PCM600, change the parameter CTStarPointn (n= the number on the current input) under the parameter settings for each current input.
• Check the actual state of the connected binary inputs.
  • In LHMI, select **Main menu/Tests/I/O modules**. Then navigate to the board with the actual binary input to be checked.
  • With PCM600, right-click the product and select **Signal Monitoring**. Then navigate to the actual I/O board and to the binary input in question. The activated input signal is indicated with a yellow-lit diode.

• Measure output contacts using the voltage drop method of applying at least the minimum contact load given for the output relays in the technical data, for example 100 mA at 24 V AC/DC.

  Output relays, especially power output relays, are designed for breaking high currents. Due to this, layers of high resistance may appear on the surface of the contacts. Do not determine proper functionality of connectivity or contact resistance by measuring with a regular hand-held ohm meter.

---

*Figure 26: Testing output contacts using the voltage drop method*

- 1 Contact current
- 2 Contact voltage drop
- 3 Load
- 4 Supply voltage
To check the status of the output circuits driving the output relay via the LHMI, select **Main menu/Tests/I/O modules** and then navigate to the board with the actual binary output to be checked.

- Test and change the relay state manually.
1. To set the IED to test mode, select **Main menu/Tests/IED test mode/TESTMODE:1** and set the parameter to **enable**.

2. To operate or force the output relay to operate, select and then navigate to the board with the actual binary output relay to be operated/forced.

3. Select the BOn_PO to be operated/forced and use [ and ] or [ and ] to operate the actual output relay.

   In PCM600, only the result of these operations can be checked by right-clicking the product and selecting Signal Monitoring tool and then navigating to the actual I/O-board and the binary input in question. The activated output signal is indicated with a yellow-lit diode. Each BOn_PO is represented by two signals. The first signal in LHMI is the actual value 1 or 0 of the output, and in PCM600 a lit or dimmed diode. The second signal is the status Normal or Forced. Forced status is only achieved when the BO is set to **Forced** or operated on the LHMI.

   Set the parameter **TestMode** to **disable** after completing these tests. The Pickup LED stops flashing when the relay is no longer in test mode.

An initially high contact resistance does not cause problems as it is reduced quickly by the electrical cleaning effect of fritting and thermal destruction of layers, bringing the contact resistance back to the mOhm range. As a result, practically the full voltage is available at the load.
<table>
<thead>
<tr>
<th>Abbreviation</th>
<th>Definition</th>
</tr>
</thead>
<tbody>
<tr>
<td>AC</td>
<td>Alternating current</td>
</tr>
<tr>
<td>ACC</td>
<td>Actual channel</td>
</tr>
<tr>
<td>ACT</td>
<td>Application configuration tool within PCM600</td>
</tr>
<tr>
<td>A/D converter</td>
<td>Analog-to-digital converter</td>
</tr>
<tr>
<td>ADBS</td>
<td>Amplitude deadband supervision</td>
</tr>
<tr>
<td>AI</td>
<td>Analog input</td>
</tr>
<tr>
<td>ANSI</td>
<td>American National Standards Institute</td>
</tr>
<tr>
<td>AR</td>
<td>Autoreclosing</td>
</tr>
<tr>
<td>ASCT</td>
<td>Auxiliary summation current transformer</td>
</tr>
<tr>
<td>ASD</td>
<td>Adaptive signal detection</td>
</tr>
<tr>
<td>ASDU</td>
<td>Application service data unit</td>
</tr>
<tr>
<td>AWG</td>
<td>American Wire Gauge standard</td>
</tr>
<tr>
<td>BBP</td>
<td>Busbar protection</td>
</tr>
<tr>
<td>BFOC/2,5</td>
<td>Bayonet fibre optic connector</td>
</tr>
<tr>
<td>BFP</td>
<td>Breaker failure protection</td>
</tr>
<tr>
<td>BI</td>
<td>Binary input</td>
</tr>
<tr>
<td>BOS</td>
<td>Binary outputs status</td>
</tr>
<tr>
<td>BR</td>
<td>External bistable relay</td>
</tr>
<tr>
<td>BS</td>
<td>British Standards</td>
</tr>
<tr>
<td>CB</td>
<td>Circuit breaker</td>
</tr>
<tr>
<td>CCVT</td>
<td>Capacitive Coupled Voltage Transformer</td>
</tr>
<tr>
<td>Class C</td>
<td>Protection Current Transformer class as per IEEE/ ANSI</td>
</tr>
<tr>
<td>CMPPS</td>
<td>Combined megapulses per second</td>
</tr>
<tr>
<td>CMT</td>
<td>Communication Management tool in PCM600</td>
</tr>
<tr>
<td>CO cycle</td>
<td>Close-open cycle</td>
</tr>
<tr>
<td>Abbreviation</td>
<td>Full Form</td>
</tr>
<tr>
<td>--------------</td>
<td>-----------</td>
</tr>
<tr>
<td>COMTRADE</td>
<td>Standard Common Format for Transient Data Exchange format for Disturbance recorder according to IEEE/ANSI C37.111, 1999 / IEC60255-24</td>
</tr>
<tr>
<td>COT</td>
<td>Cause of transmission</td>
</tr>
<tr>
<td>CPU</td>
<td>Central processing unit</td>
</tr>
<tr>
<td>CR</td>
<td>Carrier receive</td>
</tr>
<tr>
<td>CRC</td>
<td>Cyclic redundancy check</td>
</tr>
<tr>
<td>CROB</td>
<td>Control relay output block</td>
</tr>
<tr>
<td>CS</td>
<td>Carrier send</td>
</tr>
<tr>
<td>CT</td>
<td>Current transformer</td>
</tr>
<tr>
<td>CU</td>
<td>Communication unit</td>
</tr>
<tr>
<td>CVT or CCVT</td>
<td>Capacitive voltage transformer</td>
</tr>
<tr>
<td>DAR</td>
<td>Delayed autoreclosing</td>
</tr>
<tr>
<td>DARPA</td>
<td>Defense Advanced Research Projects Agency (The US developer of the TCP/IP protocol etc.)</td>
</tr>
<tr>
<td>DBDL</td>
<td>Dead bus dead line</td>
</tr>
<tr>
<td>DBLL</td>
<td>Dead bus live line</td>
</tr>
<tr>
<td>DC</td>
<td>Direct current</td>
</tr>
<tr>
<td>DFC</td>
<td>Data flow control</td>
</tr>
<tr>
<td>DFT</td>
<td>Discrete Fourier transform</td>
</tr>
<tr>
<td>DHCP</td>
<td>Dynamic Host Configuration Protocol</td>
</tr>
<tr>
<td>DI</td>
<td>Digital input</td>
</tr>
<tr>
<td>DLLB</td>
<td>Dead line live bus</td>
</tr>
<tr>
<td>DNP</td>
<td>Distributed Network Protocol as per IEEE Std 1815-2012</td>
</tr>
<tr>
<td>DR</td>
<td>Disturbance recorder</td>
</tr>
<tr>
<td>DRAM</td>
<td>Dynamic random access memory</td>
</tr>
<tr>
<td>DRH</td>
<td>Disturbance report handler</td>
</tr>
<tr>
<td>DTT</td>
<td>Direct transfer trip scheme</td>
</tr>
<tr>
<td>EHV network</td>
<td>Extra high voltage network</td>
</tr>
<tr>
<td>EIA</td>
<td>Electronic Industries Association</td>
</tr>
<tr>
<td>EMC</td>
<td>Electromagnetic compatibility</td>
</tr>
<tr>
<td>EMF</td>
<td>Electromotive force</td>
</tr>
<tr>
<td>Abbreviation</td>
<td>Description</td>
</tr>
<tr>
<td>--------------</td>
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</tr>
<tr>
<td>EMI</td>
<td>Electromagnetic interference</td>
</tr>
<tr>
<td>EnFP</td>
<td>End fault protection</td>
</tr>
<tr>
<td>EPA</td>
<td>Enhanced performance architecture</td>
</tr>
<tr>
<td>ESD</td>
<td>Electrostatic discharge</td>
</tr>
<tr>
<td>F-SMA</td>
<td>Type of optical fibre connector</td>
</tr>
<tr>
<td>FAN</td>
<td>Fault number</td>
</tr>
<tr>
<td>FCB</td>
<td>Flow control bit; Frame count bit</td>
</tr>
<tr>
<td>FOX 20</td>
<td>Modular 20 channel telecommunication system for speech, data and protection signals</td>
</tr>
<tr>
<td>FOX 512/515</td>
<td>Access multiplexer</td>
</tr>
<tr>
<td>FOX 6Plus</td>
<td>Compact time-division multiplexer for the transmission of up to seven duplex channels of digital data over optical fibers</td>
</tr>
<tr>
<td>FTP</td>
<td>File Transfer Protocol</td>
</tr>
<tr>
<td>FUN</td>
<td>Function type</td>
</tr>
<tr>
<td>GCM</td>
<td>Communication interface module with carrier of GPS receiver module</td>
</tr>
<tr>
<td>GDE</td>
<td>Graphical display editor within PCM600</td>
</tr>
<tr>
<td>GI</td>
<td>General interrogation command</td>
</tr>
<tr>
<td>GIS</td>
<td>Gas-insulated switchgear</td>
</tr>
<tr>
<td>GOOSE</td>
<td>Generic object-oriented substation event</td>
</tr>
<tr>
<td>GPS</td>
<td>Global positioning system</td>
</tr>
<tr>
<td>GSAL</td>
<td>Generic security application</td>
</tr>
<tr>
<td>GSE</td>
<td>Generic substation event</td>
</tr>
<tr>
<td>HDLC protocol</td>
<td>High-level data link control, protocol based on the HDLC standard</td>
</tr>
<tr>
<td>HFBR connector type</td>
<td>Plastic fiber connector</td>
</tr>
<tr>
<td>HMI</td>
<td>Human-machine interface</td>
</tr>
<tr>
<td>HSAR</td>
<td>High speed autoreclosing</td>
</tr>
<tr>
<td>HV</td>
<td>High-voltage</td>
</tr>
<tr>
<td>HVDC</td>
<td>High-voltage direct current</td>
</tr>
<tr>
<td>IDBS</td>
<td>Integrating deadband supervision</td>
</tr>
<tr>
<td>IEC</td>
<td>International Electrical Committee</td>
</tr>
<tr>
<td>IEC 61869-2</td>
<td>IEC Standard, Instrument transformers</td>
</tr>
</tbody>
</table>
IEC 60870-5-103  Communication standard for protective equipment. A serial master/slave protocol for point-to-point communication

IEC 61850  Substation automation communication standard

IEC 61850–8–1  Communication protocol standard

IEEE  Institute of Electrical and Electronics Engineers

IEEE 802.12  A network technology standard that provides 100 Mbits/s on twisted-pair or optical fiber cable

IEEE P1386.1  PCI Mezzanine Card (PMC) standard for local bus modules. References the CMC (IEEE P1386, also known as Common Mezzanine Card) standard for the mechanics and the PCI specifications from the PCI SIG (Special Interest Group) for the electrical EMF (Electromotive force).

IEEE 1686  Standard for Substation Intelligent Electronic Devices (IEDs) Cyber Security Capabilities

IED  Intelligent electronic device

I-GIS  Intelligent gas-insulated switchgear

Instance  When several occurrences of the same function are available in the IED, they are referred to as instances of that function. One instance of a function is identical to another of the same kind but has a different number in the IED user interfaces. The word "instance" is sometimes defined as an item of information that is representative of a type. In the same way an instance of a function in the IED is representative of a type of function.

IP 1. Internet protocol. The network layer for the TCP/IP protocol suite widely used on Ethernet networks. IP is a connectionless, best-effort packet-switching protocol. It provides packet routing, fragmentation and reassembly through the data link layer.

2. Ingression protection, according to IEC standard

IP 20  Ingression protection, according to IEC standard, level IP20- Protected against solid foreign objects of 12.5mm diameter and greater.

IP 40  Ingression protection, according to IEC standard, level IP40- Protected against solid foreign objects of 1mm diameter and greater.

IP 54  Ingression protection, according to IEC standard, level IP54- Dust-protected, protected against splashing water.

IRF  Internal failure signal
<table>
<thead>
<tr>
<th>Abbreviation</th>
<th>Definition</th>
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<tr>
<td>IRIG-B</td>
<td>InterRange Instrumentation Group Time code format B, standard 200</td>
</tr>
<tr>
<td>ITU</td>
<td>International Telecommunications Union</td>
</tr>
<tr>
<td>LAN</td>
<td>Local area network</td>
</tr>
<tr>
<td>LCD</td>
<td>Liquid crystal display</td>
</tr>
<tr>
<td>LDD</td>
<td>Local detection device</td>
</tr>
<tr>
<td>LED</td>
<td>Light-emitting diode</td>
</tr>
<tr>
<td>LNT</td>
<td>LON network tool</td>
</tr>
<tr>
<td>MCB</td>
<td>Miniature circuit breaker</td>
</tr>
<tr>
<td>MVAL</td>
<td>Value of measurement</td>
</tr>
<tr>
<td>NCC</td>
<td>National Control Centre</td>
</tr>
<tr>
<td>NOF</td>
<td>Number of grid faults</td>
</tr>
<tr>
<td>NUM</td>
<td>Numerical module</td>
</tr>
<tr>
<td>OCO cycle</td>
<td>Open-close-open cycle</td>
</tr>
<tr>
<td>OCP</td>
<td>Overcurrent protection</td>
</tr>
<tr>
<td>OLTC</td>
<td>On-load tap changer</td>
</tr>
<tr>
<td>OTEV</td>
<td>Disturbance data recording initiated by other event than start/pick-up</td>
</tr>
<tr>
<td>OV</td>
<td>Over-voltage</td>
</tr>
<tr>
<td>Overreach</td>
<td>A term used to describe how the relay behaves during a fault condition. For example, a distance relay is overreaching when the impedance presented to it is smaller than the apparent impedance to the fault applied to the balance point, that is, the set reach. The relay “sees” the fault but perhaps it should not have seen it.</td>
</tr>
<tr>
<td>PCI</td>
<td>Peripheral component interconnect, a local data bus</td>
</tr>
<tr>
<td>PCM600</td>
<td>Protection and control IED manager</td>
</tr>
<tr>
<td>PC-MIP</td>
<td>Mezzanine card standard</td>
</tr>
<tr>
<td>POR</td>
<td>Permissive overreach</td>
</tr>
<tr>
<td>POTT</td>
<td>Permissive overreach transfer trip</td>
</tr>
<tr>
<td>Process bus</td>
<td>Bus or LAN used at the process level, that is, in near proximity to the measured and/or controlled components</td>
</tr>
<tr>
<td>PSM</td>
<td>Power supply module</td>
</tr>
<tr>
<td>PST</td>
<td>Parameter setting tool within PCM600</td>
</tr>
<tr>
<td>Term</td>
<td>Definition</td>
</tr>
<tr>
<td>--------------</td>
<td>-----------------------------------------------------------------------------</td>
</tr>
<tr>
<td>PT ratio</td>
<td>Potential transformer or voltage transformer ratio</td>
</tr>
<tr>
<td>PUTT</td>
<td>Permissive underreach transfer trip</td>
</tr>
<tr>
<td>RCA</td>
<td>Relay characteristic angle</td>
</tr>
<tr>
<td>RISC</td>
<td>Reduced instruction set computer</td>
</tr>
<tr>
<td>RMS value</td>
<td>Root mean square value</td>
</tr>
<tr>
<td>RS422</td>
<td>A balanced serial interface for the transmission of digital data in point-to-point connections</td>
</tr>
<tr>
<td>RS485</td>
<td>Serial link according to EIA standard RS485</td>
</tr>
<tr>
<td>RTC</td>
<td>Real-time clock</td>
</tr>
<tr>
<td>RTU</td>
<td>Remote terminal unit</td>
</tr>
<tr>
<td>SA</td>
<td>Substation Automation</td>
</tr>
<tr>
<td>SBO</td>
<td>Select-before-operate</td>
</tr>
<tr>
<td>SC</td>
<td>Switch or push button to close</td>
</tr>
<tr>
<td>SCL</td>
<td>Short circuit location</td>
</tr>
<tr>
<td>SCS</td>
<td>Station control system</td>
</tr>
<tr>
<td>SCADA</td>
<td>Supervision, control and data acquisition</td>
</tr>
<tr>
<td>SCT</td>
<td>System configuration tool according to standard IEC 61850</td>
</tr>
<tr>
<td>SDU</td>
<td>Service data unit</td>
</tr>
<tr>
<td>SMA connector</td>
<td>Subminiature version A, A threaded connector with constant impedance.</td>
</tr>
<tr>
<td>SMT</td>
<td>Signal matrix tool within PCM600</td>
</tr>
<tr>
<td>SMS</td>
<td>Station monitoring system</td>
</tr>
<tr>
<td>SNTP</td>
<td>Simple network time protocol – is used to synchronize computer clocks on local area networks. This reduces the requirement to have accurate hardware clocks in every embedded system in a network. Each embedded node can instead synchronize with a remote clock, providing the required accuracy.</td>
</tr>
<tr>
<td>SOF</td>
<td>Status of fault</td>
</tr>
<tr>
<td>SPA</td>
<td>Strömberg protection acquisition, a serial master/slave protocol for point-to-point communication</td>
</tr>
<tr>
<td>SRY</td>
<td>Switch for CB ready condition</td>
</tr>
<tr>
<td>ST</td>
<td>Switch or push button to trip</td>
</tr>
<tr>
<td>Starpoint</td>
<td>Neutral/Wye point of transformer or generator</td>
</tr>
<tr>
<td>SVC</td>
<td>Static VAr compensation</td>
</tr>
<tr>
<td>TC</td>
<td>Trip coil</td>
</tr>
<tr>
<td>------</td>
<td>-----------------------------------------------</td>
</tr>
<tr>
<td>TCS</td>
<td>Trip circuit supervision</td>
</tr>
<tr>
<td>TCP</td>
<td>Transmission control protocol. The most common transport layer protocol used on Ethernet and the Internet.</td>
</tr>
<tr>
<td>TCP/IP</td>
<td>Transmission control protocol over Internet Protocol. The de facto standard Ethernet protocols incorporated into 4.2BSD Unix. TCP/IP was developed by DARPA for Internet working and encompasses both network layer and transport layer protocols. While TCP and IP specify two protocols at specific protocol layers, TCP/IP is often used to refer to the entire US Department of Defense protocol suite based upon these, including Telnet, FTP, UDP and RDP.</td>
</tr>
<tr>
<td>TEF</td>
<td>Time delayed ground-fault protection function</td>
</tr>
<tr>
<td>TLS</td>
<td>Transport Layer Security</td>
</tr>
<tr>
<td>TM</td>
<td>Transmit (disturbance data)</td>
</tr>
<tr>
<td>TNC connector</td>
<td>Threaded Neill-Concelman, a threaded constant impedance version of a BNC connector</td>
</tr>
<tr>
<td>TP</td>
<td>Trip (recorded fault)</td>
</tr>
<tr>
<td>TPZ, TPY, TPX, TPS</td>
<td>Current transformer class according to IEC</td>
</tr>
<tr>
<td>TRM</td>
<td>Transformer Module. This module transforms currents and voltages taken from the process into levels suitable for further signal processing.</td>
</tr>
<tr>
<td>TYP</td>
<td>Type identification</td>
</tr>
<tr>
<td>UMT</td>
<td>User management tool</td>
</tr>
<tr>
<td><strong>Underreach</strong></td>
<td>A term used to describe how the relay behaves during a fault condition. For example, a distance relay is underreaching when the impedance presented to it is greater than the apparent impedance to the fault applied to the balance point, that is, the set reach. The relay does not “see” the fault but perhaps it should have seen it. See also Overreach.</td>
</tr>
<tr>
<td>UTC</td>
<td>Coordinated Universal Time. A coordinated time scale, maintained by the Bureau International des Poids et Mesures (BIPM), which forms the basis of a coordinated dissemination of standard frequencies and time signals. UTC is derived from International Atomic Time (TAI) by the addition of a whole number of &quot;leap seconds&quot; to synchronize it with Universal Time 1 (UT1), thus allowing for the eccentricity of the Earth's orbit, the rotational axis tilt (23.5 degrees), but still showing the Earth's irregular rotation, on which UT1 is based.</td>
</tr>
</tbody>
</table>
Coordinated Universal Time is expressed using a 24-hour clock, and uses the Gregorian calendar. It is used for aeroplane and ship navigation, where it is also sometimes known by the military name, "Zulu time." "Zulu" in the phonetic alphabet stands for "Z", which stands for longitude zero.

<table>
<thead>
<tr>
<th>Abbreviation</th>
<th>Description</th>
</tr>
</thead>
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<tr>
<td>UV</td>
<td>Undervoltage</td>
</tr>
<tr>
<td>WEI</td>
<td>Weak end infeed logic</td>
</tr>
<tr>
<td>VT</td>
<td>Voltage transformer</td>
</tr>
<tr>
<td>$3I_o$</td>
<td>Three times zero-sequence current. Often referred to as the residual or the ground-fault current</td>
</tr>
<tr>
<td>$3V_o$</td>
<td>Three times the zero sequence voltage. Often referred to as the residual voltage or the neutral point voltage</td>
</tr>
</tbody>
</table>